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A FINITE DIFFERENCE METHOD FOR STUDYING THERMAL
DEFORMATION IN TWO-DIMENSIONAL MICRO
SCALE METAL THIN FILMS EXPOSED TO
ULTRASHORT PULSED LASERS

By

Haojie Wang, M.S.

A Dissertation Presented in Partial Fulfillment
Of the Requirement for the Degree
Doctor of Philosophy

COLLEGE OF ENGINEERING AND SCIENCE
LOUISIANA TECH UNIVERSITY

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IN TWO-DIMENSIONAL MICROSCALE METAL THIN FILMS EXPOSED TO ULTRASHORT
PULSED LASERS

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ABSTRACT

Ultrashort-pulsed lasers have been attracting worldwide interest in science and engineering because the lasers with pulse durations on the order of sub-picoseconds to femtoseconds possess capabilities in limiting the undesirable spread of the thermal process zone in a heated sample during material processing at the microscale. Prevention of thermal damage is an important factor for success of ultrashort-pulsed lasers in real applications. The thermal damage induced by ultrashort pulses is intrinsically different from that induced by long-pulse or continuous lasers. It occurs after the heating pulse is over and involves the shattering of thin metal layers (without a clear signature of thermal damage by excessive temperature) rather than the melt damage caused by high temperatures. In this dissertation, by replacing the displacement components in the dynamic equations of motion using the velocity components, and employing a staggered grid, we develop a finite difference method for studying thermal deformation in two-dimensional films exposed to ultrashort-pulsed lasers, where the thin films are a single-layered thin film and a double-layered thin film with perfectly interfacial thermal contact and imperfectly interfacial thermal contact, respectively. The method is obtained based on the parabolic two-step heat transport equations. It accounts for the coupling effect between lattice temperature and strain rate, as well as for the hot electron blast effect in momentum transfer. The developed methodology allows us to avoid non-physical oscillations in the solution.

Such oscillations have been an intrinsic feature of most numerical method proposed so far in the context of problem of interest. The development of physical-based, numerical-oscillation-free methods for thermal analysis of thin metal films subjected to heating of ultrashort-pulsed lasers represents challenging tools at the forefront of this practically important area of research.

This method is tested for its applicability by investigating the temperature rise and deformation in (1) a single-layered gold thin film, (2) a double-layered gold and chromium thin film with perfect thermal contact at the interface, and (3) a double-layered gold and chromium thin film with imperfect thermal contact at the interface. Results show that there are no non-physical oscillations in the solutions, and the method is promising.

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NOMENCLATURE

C_{e0}	electron heat capacity, $J/(m^3 K)$
C_p	volumetric heat capacity
C_l	lattice heat capacity, $J/(m^3 K)$
E	modulus of elasticity, Pa
G	electron-lattice coupling factor, $W/(m^3 K)$
J	laser fluence, J/m^2
K	bulk modulus, Pa
k_e	thermal conductivity, $W/(mK)$
L_x	length in x direction, m
L_y	length in y direction, m
m_e	electron mass, kg
n_a	atomic number density per unit volume, m^{-3}
n_e	number density per unit volume, m^{-3}
N	number of grid points
Q	volumetric heat source, W/m^2
\bar{q}	heat flux, W/m^2
R	surface reflectivity

T	absolute temperature, K
T_e	electron temperature, K
T_l	lattice temperature, K
t	time, s
t_p	laser pulse duration, s
u	displacement in x direction, m
v	displacement in y direction, m
v_1	velocity components in x direction, m/s
v_2	velocity components in y direction, m/s
v_s	speed of sound, m/s
x	Cartesian coordinates
x_s	optical penetration depth, m
y	Cartesian coordinates
y_s	spatial profile parameter, m

Greek Symbols

Δt	time increment, s
Δx	spatial size, m
Δy	spatial size, m
Δ_{-t}	finite difference operator
δ_x	finite difference operator
δ_y	finite difference operator

ϵ_x	normal strain in x direction
ϵ_y	normal strain in y direction
γ_{xy}	shear strain
Λ	electron-blast coefficient, $J/(m^3 K^2)$
λ	Lame constant, Pa
μ	shear modulus, Pa
ρ	density, kg/m^3
σ	Stefan-Boltzman's constant
σ_x	normal stresses in x direction, Pa
σ_y	normal stresses in y direction, Pa
σ_{xy}	shear stress, Pa

Subscripts and Superscripts

0	initial value at $t = 0$
D	Debye temperature, K
e	electron
i	index in x direction
j	index in y direction
l	lattice
m	index for multilayer system
n	index in time direction
x	in x direction
y	in y direction

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CHAPTER ONE

INTRODUCTION

1.1 Overview

Ultrafast lasers with pulse durations on the order of sub-picoseconds to femtoseconds possess exclusive capabilities in limiting the undesirable spread of the thermal process zone in a heated sample [Tzou 2002]. The application of ultrashort-pulsed lasers includes structural monitoring of metal thin films [Mandelis 1992, Opsal 1991], structural tailoring of microfilms [Grigoropoulos 1994], and laser synthesis and processing in thin film deposition [Narayan 1991]. Recent applications of ultrashort-pulsed lasers have been demonstrated in different disciplines such as physics, chemistry, biology, medicine, and optical technology [Liu 2000, Shirk 1998]. The non-contact nature of femtosecond lasers has made them an ideal candidate for precise thermal processing of functional nanophase materials [Tzou 2002].

Success of high-energy femtosecond lasers in real applications relies on three factors [Tzou 2002]: (1) well characterized pulsed width, intensity and experimental techniques; (2) reliable microscale heat transfer models; and (3) prevention of thermal damage which is also the most important task in real applications. It should be pointed out here that ultrafast damage induced by sub-picosecond pulses is intrinsically different from that induced by long-pulse or continuous lasers. For the latter, laser damage is

caused by the elevated temperatures resulting from the continuous pumping of photon energy into the processed sample. Therefore, the “damage threshold” in heating by long-pulse lasers is often referred to as the laser intensity that drives the heated spot to the melting temperature. Thermal damage induced by ultrashort pulsed lasers in the picosecond domain, on the other hand, occurs after the heating pulse is over. Field induced multi-photon ionization produces free electrons that are rapidly accelerated by the laser pulse. Absorbing energy from the impinging photons in the femtosecond domain, these free electrons mobilize and ionize neighboring atoms through high-frequency collisions, which generates more electrons. Thermal energy is transmitted to phonons through phonon-electron coupling by the hot electrons, resulting in a new thermal property, called the electron-phonon coupling factor, for microscale heat transfer in metals. This process doesn't stop until a critical density of hot electrons is reached. In fact, under a sufficiently high intensity of heating, it has been shown that the ultrafast damage involves shattering of a thin material layer (from the heated surface) without a clear signature of thermal damage by excessive temperature [Tzou 2002]. Obviously, a new driving force, rather than the melting temperature, brings about such ultrafast damage probably in only a few picoseconds after heating is applied [Tzou 2002]. Hence, it is important to study the thermal deformation induced by ultrashort-pulsed lasers in order to prevent thermal damage.

1.2 Objective of the Research

The objective of this research is to develop finite difference schemes for solving ultrafast deformation in microscale thin films induced by ultrashort-pulsed lasers, based

on the dynamic equations of motion coupled with two-step parabolic heat transport equations. To achieve this objective, the following procedure is pursued:

- (1) Introduce two velocity components into the model and re-write the dynamic equations of motion in order to prevent the solution from oscillations.
- (2) Construct a staggered grid in order to prevent the solution from oscillations.
- (3) Develop second-order, in both space and time, finite difference schemes to obtain the temperature, displacement, and stress distributions in a microscale thin film induced by ultrashort-pulsed lasers.
- (4) Apply the numerical schemes to investigate the temperature, displacement, and stress distributions in a single-layered gold thin film, and a double-layered gold and chromium thin film with perfect interfacial thermal contact and imperfect interfacial thermal contact, respectively, exposed to ultrashort-pulsed lasers.

Results of the research will provide a no non-physical oscillation numerically efficient method for thermal analysis of metal thin films subjected to heating of ultrashort-pulsed lasers and give us a better understanding of the ultrafast deformation in microscale thin films. The result will also have an impact on the design and calibration of short-pulse lasers for applications in the structural monitoring of thin metal films, laser micro-machining and patterning, structural tailoring of micro-films, and laser synthesis and processing in thin film deposition, as well as in other disciplines where high-energy short-pulse lasers are important.

1.3 Overview of the Dissertation

Chapter two introduces the process of micro-heat transfer by phonon-electron interaction model, the dual-phase-lagging behavior, the comparison of classical

thermomechanics and ultrafast thermomechanics, and a review of some previous works.

Chapter three describes a single-layered thin film problem and a double-layered thin film problem, where the interface is either perfectly thermal contact or imperfectly thermal contact, defines the geometry and sets up the governing equations including the initial and boundary conditions.

Chapter four develops a staggered finite difference method for solving the governing equation system and numerical algorithms for obtaining the temperature, displacement, and stress distributions in a single-layered thin film and a double-layered thin film where the interface is either perfectly thermal contact or imperfectly thermal contact induced by ultrashort-pulsed lasers.

Chapter five shows the numerical results obtained based on the developed numerical method for thermal deformation in a single-layered gold thin film, and a gold layer padding on a chromium layer with perfectly thermal interfacial contact and imperfectly thermal interfacial contact, respectively. Various meshes are chosen to test the convergence of the scheme. The electron temperature and the lattice temperature distributions, the displacement, the stress, and the strain are calculated and discussed.

Finally, the conclusions and future work are discussed in Chapter six.

CHAPTER TWO

LITERATURE REVIEW

2.1 Macroscopic Heat Transfer

In thermodynamics, heat is defined as energy transfer due to temperature gradients or differences. Consistent with this view point, only two modes of heat transfer are recognized: conduction and radiation. For example, heat transfer across a steel pipe is by conduction, whereas heat transfer from the sun to earth is by radiation. These modes of transfer occur on a molecular or subatomic scale.

In the atmosphere at normal pressure, conduction is by molecules that travel a very short distance before colliding with another molecule and exchanging energy. On the other hand, radiation is by photons, which travel almost unimpeded through the air from one surface to another. Thus, an important distinction between conduction and radiation is that the energy carriers for conduction have a shorter mean free path, whereas for radiation, the carriers have a long mean free path. Additionally, a fluid, by virtue of its mass and velocity, can transport momentum, and by virtue of its temperature, it can transport energy. Therefore, convection is defined as the transport of energy by bulk motion of a medium. We will focus our discussion on the conduction mode of heat transfer.

In the classical theory of heat transfer, the main phenomenological law that governs heat conduction is Fourier's Law. It is a constitutive equation that depicts the way in which cause varies with effect. It is necessary along with the conservation of energy law to derive the heat transport equations. Regardless of the assumptions formulated in the constitutive equation, it must be admissible under the framework of the second law of thermodynamics.

Fourier's Law of heat conduction,

$$\vec{q} = -k\nabla T, \quad (2.1)$$

where k is the thermal conductivity of the material dictates that the heat flux vector (\vec{q}) and the temperature gradient (∇T) across a material volume occur at the same instant of time. The energy equation derived from the first law of thermodynamics is

$$-\nabla \cdot \vec{q} = C_p \frac{\partial T}{\partial t} - Q, \quad (2.2)$$

where C_p is the volumetric heat capacity and Q is the heat source. Taking the divergence of Eq. (2.1) and substituting it into Eq. (2.2), we obtain the traditional heat diffusion equation:

$$C_p \frac{\partial T}{\partial t} = \nabla \cdot (k\nabla T) + Q. \quad (2.3)$$

The immediate response dictated by Fourier's Law results in an infinite speed of heat propagation, implying that a disturbance applied at a certain location in a solid medium is immediately sensed anywhere else in the medium. Because the heat flux vector and the temperature gradient are simultaneous, there is no difference between the cause and the effect of heat flow [Kaba 2004, Kaba 2005].

2.2 Microscale Heat Transfer

2.2.1 Differences with Macroscale Heat Transfer

While the conventional, (macroscale) model is widely used to understand the transfer of heat energy, it is often not physically realistic. Eq. (2.3) is a parabolic equation and as a result, any temperature disturbance will propagate at an infinite speed. This model is physically unrealizable [Herwig 2000].

Because Fourier's law does not predict finite wave speeds, the law does not accurately approximate the heat transfer in certain cases. The assumption of instantaneous energy transmission fails during a short duration of initial transient, or when the thermal propagation speed is not high, such as in low temperatures [Barron 1985]. In other words, Fourier's law breaks down at temperatures near absolute zero or when the observation time is extremely small during a transient. For these cases, the wave nature of thermal transport becomes dominant, rendering Fourier's Law incomplete as an approximation for these cases [Glass 1985]. Specific to this work, Fourier's law does not accurately predict the transient temperature during microscale ($< 10^{-12} \text{ s}$) laser heating of thin metal films ($< 10^{-16} \text{ m}$) [Qiu 1993c, Barron 2005, Barron 2006].

2.2.2 Wave Nature of Microscale Heat Transfer

In solids that are not good electrical conductors, the principal mode of conduction heat transfer is that of vibrational energy transfer from one atom to its neighbors. Atoms in solids are constantly at very high frequencies with relatively small amplitudes. The atomic vibrations of adjacent atoms are coupled through atomic bonding. These vibrations are coordinated in such a way that traveling lattice waves are produced, which

propagates through the lattice at the speed of sound. A single quantum of vibrational energy is called a phonon.

However, in metals, the free electron mechanism of heat transport is much more efficient than the phonon mechanism, because phonons are more easily scattered than free electrons and because electrons have higher velocities. The mean free path of an electron in a bulk material is typically on the order of 10 to 30 nm, where the electron lattice is dominant. However, when the film thickness is on the order of the mean free path, boundary scattering becomes important [Tzou 1996]. Thin films are manufactured using a number of methods and a wide variety of conditions. The manufacturing method and environmental conditions during manufacture can have serious influence on the microstructure of the film, which in turn influences defect and grain boundary scattering. Also, when heated by ultrashort pulses, the electron system becomes so hot that electron-electron scattering can become significant. Thus, microscale heat transfer requires consideration of the microscopic energy carriers and the full range of possible scattering mechanisms.

2.2.3 Dual Phase Lagging Behavior of Microscale Heat Transfer

Qiu and others [Qiu 1993c] have proposed a phase lag model to explain the wave-like propagation of heat on a mircoscale. This model expresses two primary phases for heat conduction. The first involves the deposition of energy on electrons while the second involves the transfer of this energy from electrons to the lattice of the material. As early as 1957, Kaganov et al proposed that free electrons can be heated to a temperature much higher than the lattice temperature in certain situations [Kaganov 1957]. This high heating results in a double phase heating of the material. Accoding to Qiu's research,

there exist two characteristic times for the transfer of heat: thermalization time and relaxation time [Qiu 1993c]. Thermalization time represents the time for electrons and the lattice to reach thermal equilibrium. It represents the time necessary to convert heat energy to the internal lattice. Relaxation time represents the time for electrons to change their states.

During a relatively slow heating process, the thermalization time can be thought of as instantaneous. This process is modeled well by a Fourier's Law model. However, for very short laser-pulse heating, these assumptions are subject to question [Qiu 1993c]. In fact, because the physical dimension in microscale heat transfer is of the same order of magnitude as the electron free path, the response time is of this same magnitude. This fact indicates that the temperature gradient is not descriptive for a thin film of the same thickness as the mean free path [Tzou 1996].

2.2.4 Mathematical Model of Microscale Heat Transfer

The model in Eq. (2.3) can be described as a parabolic one-step equation because of the assumptions it makes that heat energy is converted to lattice energy instantaneously and that heat energy is assumed to be a diffusive process [Qiu 1993c]. Other non-Fourier models have been proposed to deal with the failings of the Fourier model on a microscale. One model is based on the modified flux law [Tzou 1993]

$$\bar{q} + \tau \frac{\partial \bar{q}}{\partial t} = -k\nabla T, \quad (2.4)$$

where τ is the relaxation time and \bar{q} is the heat flux. The heat flux vector in this case maintains a memory of the time-history of the temperature gradient. Relaxation time is the effective mean free path l , divided by the phonon speed v_s . Mathematically, $\tau = l/v_s$.

In the absence of relaxation time (or $\tau = 0$), which implies a mathematical idealization from either a zero mean free path ($l = 0$) or an infinite phonon speed ($v \rightarrow \infty$) for phonon collisions, then Eq. (2.4) reduces to the classical Fourier rate equation. Therefore, an infinite speed of heat propagation is an assumption made in the classical theory of diffusion utilizing Fourier's Law [Tzou 1993].

When Eq. (2.4) is combined with Eq. (2.3), we obtain the hyperbolic heat equation,

$$C \frac{\partial T}{\partial t} = -\nabla \bar{q} + Q, \quad (2.5a)$$

$$\tau \frac{\partial \bar{q}}{\partial t} + k \nabla T + \bar{q} = 0. \quad (2.5b)$$

This equation is known as a hyperbolic equation because of the additional term that modifies the parabolic Fourier heat Eq. (2.3) [Tang 1996]. This modification predicts a finite speed of heat propagation because of the relaxation time τ , associated with heat transfer. Typical wave speeds in metals are on the order of 10^5 m/s [Ozisik 1994].

While the hyperbolic model answers some issues arising from a microscale examination of heat transfer, it still leaves some questions. It is not based on the details of energy transport in the material, such as the interaction of electrons and phonons [Qiu 1993a]. Also, material properties may not be able to be regarded as constant. The relaxation time and thermal conductivity are generally temperature-dependent [Tzou 1993]. In addition, the value of thermal conductivity depends on processing parameters such as laser pulse duration and intensity, during short-pulse laser heating [Qiu 1993b].

These considerations have led to the dual-phase lagging equation. This equation is derived from the lagging equation which holds a lag in heat flux behind the temperature

gradient. Compared to the hyperbolic heat equation, this model has an additional mixed derivative term. Now, as with the hyperbolic model, the time lag associated with heat flux causes wavelike behavior. However, the additional time lag creates a mixed derivative term that renders the equation in the form of a parabolic equation. Thus this parabolic dual phase equation is modeled as follows:

$$C_e(T_e) \frac{\partial T_e}{\partial t} = \nabla \cdot (k \nabla T_e) - G(T_e - T_l) + S, \quad (2.6a)$$

$$C_l(T_l) \frac{\partial T_l}{\partial t} = G(T_e - T_l). \quad (2.6b)$$

Here, $C_e(T_e)$ and $C_l(T_l)$ are the volumetric electron heat capacity and the volumetric lattice heat capacity, respectively, and G is the electron-lattice coupling factor. The coupling factor will be described in detail later. Qiu and Tien [Qiu 1993a] derived a model described as the hyperbolic two step model from the Boltzmann transport for electrons. Each of these models has functionality. Each is, however, contingent upon the interrelatedness of thermalization time and relaxation time.

The complexity of solutions for Eq. (2.6) lies in the temperature-dependent heat capacity of the electron gas. Tzou argues that for an electron gas temperature lower than the Fermi temperature, (of the order of 10^4 K), the electron heat capacity (C_e) is proportional to the electron temperature [Tzou 1996]. This argument makes the equation non-linear. In metals, the specific heat can be given by [Barron 1985]:

$$C_e = \gamma_e T_e, \quad (2.7)$$

where γ_e is known as the electron specific heat coefficient and is experimentally obtainable.

In the parabolic dual-phase model, the energy exchange between phonons and electrons is characterized by the phonon-electron coupling factor G [Kaganov 1957]:

$$G = \frac{\pi^2}{6} \frac{m_e n_e v_s^2}{\tau_e T_e} \text{ for } T_e \gg T_l, \quad (2.8)$$

where m_e represents the electron mass, n_e the number density (concentration) of electrons per unit volume, and v_s the speed of sound,

$$v_s = \frac{\sigma}{2\pi h} (6\pi^2 n_a)^{-\frac{1}{3}} T_D, \quad (2.9)$$

with the quantity h being Planck's constant, k being Boltzmann constant, n_a being the atomic number density per unit volume, and T_D representing the Debye temperature. The electron temperature (T_e) is much higher than the lattice temperature (T_l) in the early time response. The condition $T_e \gg T_l$ in Eq. (2.8) for the applicability of G is thus valid in the fast-transient process of electron-phonon dynamics. Within the limits of Wiedemann-Frenz's law, which states that for metals at moderate temperatures ($T_l > 0.48T_D$), the ratio of the thermal conductivity to the electrical conductivity is proportional to the temperature and the constant of proportionality is independent of particular metal, the electron thermal conductivity can be expressed as [Kaganov 1957]

$$k_e = \frac{\pi^2 n_e k^2 \tau_e T_e}{3m_e}, \quad (2.10)$$

Or simply

$$m_e = \frac{\pi^2 n_e k^2 \tau_e T_e}{3k_e}, \quad (2.11)$$

Substituting Eq. (2.10) into Eq. (2.8) for the electron mass yields

$$G = \frac{\pi^4 (n_e v k_s)^2}{18\sigma} \quad (2.12)$$

This coupling factor is dependent upon the thermal conductivity (k) and the number density of the electron gas. The coupling factor does not show a strong dependence on temperature and is not affected by relaxation time [Tzou 1996]

In order to estimate the value of G , the number density of the electron gas is a key quantity. Qiu and Tien assumed one free electron per atom for noble metals and employed the s-band approximation for the valence electrons in transition metals [Qiu 1993c]. Thus the value for number density of the electron gas is chosen as a fraction of the valence electrons. The phonon-electron coupling factor is calculated, and experimentally measured values are listed in Table 2.1 for comparison.

Table 2.1 Phonon-electron coupling factor (G), for some noble and transition metals [Tzou 1997].

Metal	Calculated, $\times 10^{16}$ W/m ³ K	Measured, $\times 10^{16}$ W/m ³ K
Cu	14	4.8 ± 0.7 (Brorson et al. 1990) 10 (Elsayed-Ali et al. 1987)
Ag	3.1	2.8 (Groeneveld et al. 1990)
Au	2.6	2.8 ± 0.5 (Brorson et al. 1990)
Cr	45 ($n_e/n_a = 0.5$)	42 ± 5 (Brorson et al. 1990)
W	27 ($n_e/n_a = 1.0$)	26 ± 3 (Brorson et al. 1990)
V	648 ($n_e/n_a = 2.0$)	523 ± 37 (Brorson et al. 1990)
Nb	138 ($n_e/n_a = 2.0$)	387 ± 36 (Brorson et al. 1990)
Ti	202 ($n_e/n_a = 1.0$)	185 ± 16 (Brorson et al. 1990)

Eq. (2.6a) is governed by diffusion in the electron gas and heat is transferred to the lattice in a lumped capacity sense through the coupling factor, G . In other words, the rate of energy increase in the metal lattice is proportional to the temperature difference between the metal lattice and the electrons. By eliminating the electron gas temperature, T_e , from Eq. (2.6) for constant thermal properties, one can show that:

$$\frac{1}{\alpha_T} \frac{\partial T_l}{\partial t} + \frac{1}{C_T^2} \frac{\partial^2 T_l}{\partial t^2} = \nabla^2 T_l + \frac{\alpha_e}{C_T^2} \frac{\partial}{\partial t} (\nabla^2 T_l), \quad (2.13)$$

where α_e is the thermal diffusivity of the electron gas and α_T is the equivalent thermal diffusivity represented by:

$$\alpha_T = \frac{k}{C_e + C_l}, \quad (2.14)$$

C_T is the thermal wave speed and is represented by:

$$C_T = \sqrt{\frac{kG}{C_e C_l}}. \quad (2.15)$$

However, for simplicity of discussion and ease of numerical analysis, this single equation form is seldom utilized. In this work, Eq. (2.6) is used.

Researchers determined the parabolic two-step model to be a good estimate [Qiu 1992]. To compare experimental results with a numerical model, the normalized temperature change in the electron gas is identical to the normalized reflectivity change on the film surface.

$$\frac{\Delta R}{(\Delta R)_{\max}} = \frac{\Delta T_e}{(\Delta T_e)_{\max}}, \quad (2.16)$$

where R denotes the reflectivity. The left side of Eq. (2.16) can be measured by the front-surface-pump and back-surface-probe technique [Tzou 1996]. The right hand side of Eq. (2.16) represents the solution to the numerical model for estimating heat propagation.

Figure 2.1 shows the resulting applicability of the parabolic two step model. The predicted temperature change at the surface of a thin gold film is compared with the experimental data collected [Tzou 1997].

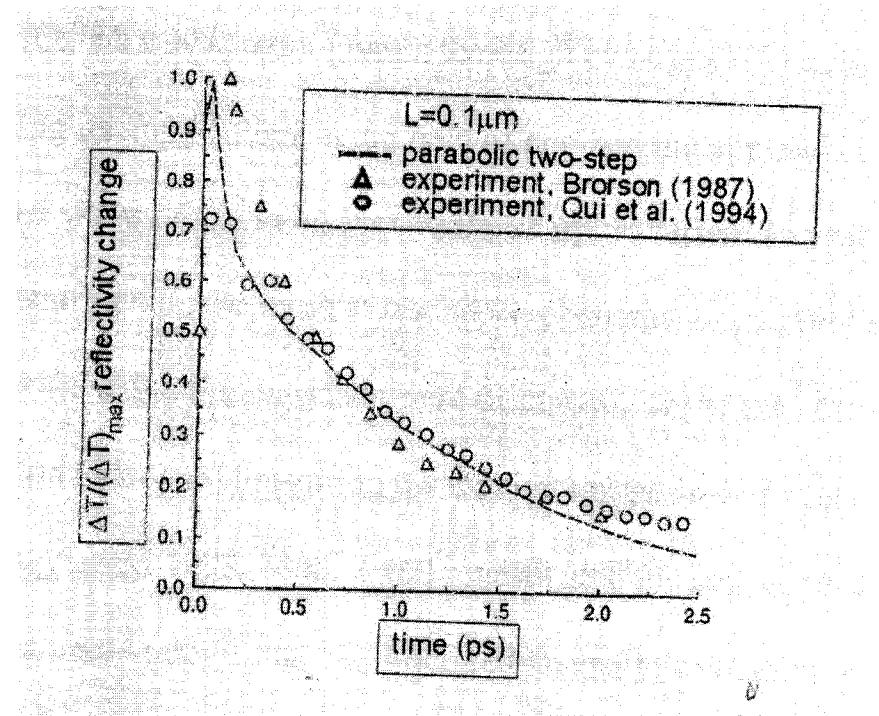


Fig. 2.1 Normalized temperature change (reflectivity change) in gold film predicted by dual-phase-lag model [Tzou 1997].

2.3 Classical Thermomechanics

Consider a homogeneous, isotropic, thermoelastic metal material. In the absence of a body force, the dynamic equations of motion and the energy equation in classical linear thermoelasticity are given as [Chen 2002a]

$$\rho \frac{\partial^2 u_i}{\partial t^2} = \sigma_{ii}, \quad (2.17)$$

$$C \frac{\partial T}{\partial t} = \nabla \cdot (k \nabla T) + Q - (3\lambda + 2\mu) \alpha_r \frac{\partial \varepsilon_{ii}}{\partial t}, \quad (2.18)$$

with the constitutive laws for stresses, σ_{ij} ,

$$\sigma_{ij} = 2\mu \varepsilon_{ij} + \lambda \varepsilon_{kk} \delta_{ij} - (3\lambda + 2\mu) \alpha_r (T - T_0) \delta_{ij}, \quad (2.19)$$

as well as the strain-displacement relations,

$$\varepsilon_{ij} = \frac{1}{2} (u_{i,j} + u_{j,i}). \quad (2.20)$$

Here ρ denotes the mass density of the material, u_i the displacements, C heat capacity, T temperature, λ Lame constant, μ shear modulus, α_r thermal expansion coefficient, T_0 initial temperature, ε_{ij} strains, Q volumetric heat source, δ_{ij} the Kronecker delta function, and k is thermal conductivity. The subscripts i , j and k ($= 1, 2, 3$ for each) refer to the spatial coordinates in three-dimensional space. The repeated index represents summation. The comma ' , ' denotes derivatives with respect to the spatial coordinates and time, respectively.

2.4 Ultrafast Thermomechanics

For ultrafast laser heating on metals, the phenomena of thermal and momentum transfer are different from those described by the above classical thermomechanics. In fact, ultrafast thermal transport is a two-step process. In the first step, the laser energy that penetrates into the material excites the free electrons that are confined within optical penetration depth during the laser irradiation. In the second step, a major part of the hot-electron thermal energy transfers to the neighboring lattice and the other part of the

electron thermal energy diffuses, through electron, into deeper regions of the material. In the early time of the heating process, the electron temperature is much greater than the lattice temperature due to the fact that the heat capacity of electron is much smaller than that of the metal lattice. As a result of the nonequilibrium between electrons and the lattice, a hot-electron blast force is induced from the hot-electron gas and acts on the lattice [Chen 2002a].

The major shortcomings from using the one-temperature thermomechanics theories to simulate the ultrashort laser heating are (a) they overestimate the lattice temperature before the thermal equilibrium state is established and (b) the hot-electron blast effect is ignored in the momentum transfer. To properly describe the thermomechanical response of metal materials irradiated by an ultrashort laser pulse, a model should consider (a) the two-step heating process in thermal transport, the volumetric absorption of laser beam energy, and the coupling between thermal and mechanical energy, and (b) the hot-electron blast effect in momentum transfer.

Thus, the dynamic equations of motion and the energy equation in ultrafast thermoelasticity can be written as [Chen 2002a]

$$\rho \frac{\partial^2 u_i}{\partial t^2} = \sigma_{ji,j} + 2\Lambda T_e T_{e,i}. \quad (2.21)$$

$$C_e \frac{\partial T_e}{\partial t} = \nabla \cdot (k_e \nabla T_e) - G(T_e - T_l) + Q, \quad (2.22)$$

$$C_l \frac{\partial T_l}{\partial t} = G(T_e - T_l) - (3\lambda + 2\mu)\alpha_T \frac{\partial \varepsilon_{ii}}{\partial t}. \quad (2.23)$$

where σ_{ij} is the same as those in classical linear thermoelasticity model. In the above equations, Λ is the coefficient for the hot-electron blast force, G represents the electron-

lattice coupling factor. The quantities with subscripts e and l are associated with electrons

and the lattice, respectively. Electron heat capacity C_e is $C_e(T_e) = C_{e0} \left(\frac{T_e}{T_0} \right)$ and electron

thermal conductivity k_e is $k_e(T_e, T_l) = k_0 \left(\frac{T_e}{T_l} \right)$.

As a two-step heating, the volumetric laser energy source Q first increases the temperature of the electron gas as represented by Eq. (2.22). Through the phonon-electron interaction, the hot-electron gas then heats up the metal lattice as represented by Eq. (2.23). It is noted that the unique hot-electron blast force $2\Delta T_e T_{e,i}$ is introduced in the momentum Eq. (2.21).

2.5 Previous work

Up-to-date, there are many researchers studying heat transfer models related to ultrashort-pulsed lasers [Tzou 1994, 1995a, 1995b, 1995c, 1995d, 1997, 1999, 2000a, 2000b, 2001, 2002] [Ozisik 1994] [Chiffell 1994] [Wang 2000, 2001a, 2001b, 2002] [Antaki 1998, 2000, 2002] [Dai 1999, 2000a, 2000b, 2000c, 2001a, 2001b, 2004a, 2004b] [Qiu 1992, 1993, 1994a, 1994b] [Joshi 1993] [Chen 1999a, 1999b, 2000a, 2000b, 2001, 2003] [Al-Nimr 1997a, 1997b, 1999, 2000a, 2000b, 2000c, 2001, 2003] [Ho 1995, 2003] [Tsai 2003]. Among these Tzou and Ozisik [Tzou 1994] considered the heat equation in only one dimension. They studied the lagging behavior by solving over a semi-infinite interval. Their solutions were obtained using the Laplace transform method and the Riemann-sum approximation for the inversion.

Ozisik's [Ozisik 1994] work gives a thorough overview of the thermal wave theory emphasizing its applications in the field of engineering applications. Special

features in thermal wave propagation such as the sharp wavefront and rate effects, the thermal shock phenomenon, the thermal resonance phenomenon, and reflections of thermal waves across a material interface were discussed. Joshi and Majumdar [Joshi 1993] obtained numerical solutions using the explicit upstream difference method. Antaki and others [Antaki 1998, 2000, 2002] investigated the heat conduction in a semi-infinite slab. Tang and Araki [Tang 1999] derived an analytic solution in finite rigid slabs by using Green's formula and a finite integral transform technique. Ho and colleagues [Ho 1995, 2003] studied heat transfer in a multilayered structure using the lattice Boltzmann method. Tsai and Hung [Tsai 2003] studied thermal wave propagation in a bi-layered composite sphere using the dual-phase-lagging heat transport equation. Recently, Dai and Nassar [Dai 2004b] have developed a finite difference scheme for solving the parabolic two-step heat transport equations in a 3D double-layered rectangular thin film. Tzou and Chiu studied thermal lagging in ultra-fast laser heating [Tzou 2001]. This study was implemented to describe the experimental data of femtosecond (*fs*) laser heating of gold films. Wang and associates [Wang 2001b] showed that the dual-phase heat conduction equations. Later, Wang [Wang 2002] showed the dual-phase heat conduction equation offers a unique solution under these same boundary conditions. Al-Nimr and Arpacı [Al-Nimr 1997a, 1997b, 1999, 2000a, 2000b, 2001, 2003] proposed an approach based on the physical decoupling of the hyperbolic two-step model, to describe the thermal behavior of a thin metal film exposed to picosecond thermal pulse. This approach was based upon the assumption that the metal film thermal behavior occurs in two distinct stages. In the first phase, the electron gas transmits its energy to the lattice through electron-phonon coupling. In the second phase, the electron gas and lattice are at thermal equilibrium. In

this phase diffusion dominates the transfer of energy within the system. This method, which eliminates the coupling of energy equations to simplify the system, applies to metal films with the parameter $\frac{GL^2}{k_e}$ much less than one. Chen and Beraun [Chen 1999a, 1999b, 2000a, 2000b, 2001, 2003] used a corrective smoothed particle method to find a numerical solution to the interaction of short laser bursts and thin metallic films. Dai and Nassar [Dai 1999, 2001, 2002, 2004] have developed many finite difference models for examining a numerical solution for a dual thin film system irradiated by an ultrashort laser burst.

Thus there is considerable research covering the dual-phase model for heat conduction. Research has supported the fact that the dual-phase model is applicable in this case. The model is well-posed, it produces a unique solution, and the numerical results accurately describe experimental results. However, only a few mathematical models for studying thermal deformation induced by ultrashort-pulsed lasers have been developed [Tzou 2002, Chen 2002a, Chen 2002c, Chen 2003]. Tzou and his colleagues [Tzou 2002] presented a one-dimensional model in a double-layered thin film. The model was solved using a differential-difference approach. Chen and his colleagues [Chen 2002a] considered a two-dimensional axisymmetric cylindrical thin film and proposed an explicit finite difference method by adding an artificial viscosity term to eliminate numerical oscillations, and in [Chen 2002c] they applied the method developed in [2002a] to investigate the deformation of metals subjected to ultrahosrt-pulsed laser heating, and in [Chen 2003] they developed a combined finite difference/finite element method to solve the coupled thermomechanical equations. In this dissertation, we consider a two-dimensional plain strain thin film model including a single-layered thin film and a

double-layered thin film with perfect interfacial thermal contact and imperfect interfacial thermal contact, respectively. We will focus on developing a no non-physical oscillations method by employing a staggered grid for studying thermal deformation in two-dimensional films exposed to ultrashort-pulsed lasers.

CHAPTER THREE

MATHEMATICAL MODEL

3.1 Problem Description

In this chapter, we will investigate the mathematical model of heat transport phenomenon in a microscale metal thin film and a double-layered thin film with perfectly interfacial thermal contact and imperfectly interfacial thermal contact, respectively. As described in Chapter Two, the hot-electron blast is found significant under intensified heating, and thus ultrafast deformation needs to be addressed in non-equilibrium heating of electrons and phonons. Because the magnitude of deformation may easily reach a fraction of the thin metal film's thickness on the microscopic level, it is of vital importance to investigate the thermal deformation and stress in the microscale metal thin films. Since the hot electron blast is strongly dependent on the temperature gradient in the electron gas, particular emphasis should be placed on the interfacial area where the temperature gradient experiences an abrupt change in transition from one metal film to another.

3.2 Model for a Thin Film

3.1.1 Governing Equations

Consider a two-dimensional microscale thin metal film in rectangular coordinates, which is exposed to ultrashort-pulsed lasers as shown in Fig. 3.1.

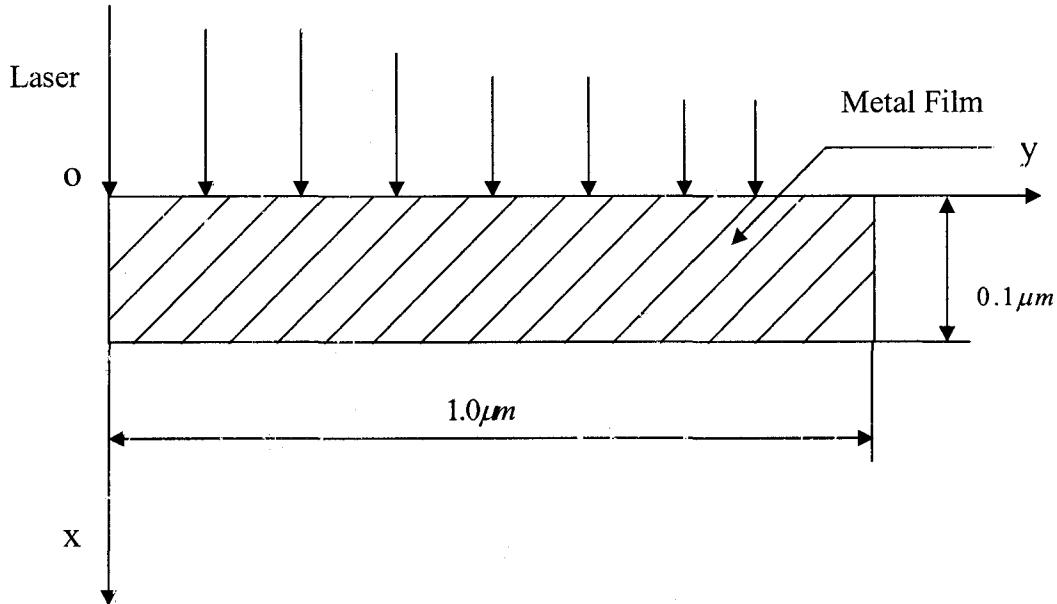


Fig. 3.1 Configuration of a metal thin film exposed to ultrashort-pulsed lasers.

The governing equations for studying thermal deformation in the thin film can be expressed as follows:

(1) Dynamic equations of motion [Tzou 2002, Chen 2002a, Brorson 1987, Wang 2006a]

$$\rho \frac{\partial^2 u}{\partial t^2} = \frac{\partial \sigma_x}{\partial x} + \frac{\partial \sigma_{xy}}{\partial y} + 2\Lambda T_e \frac{\partial T_e}{\partial x}, \quad (3.1)$$

$$\rho \frac{\partial^2 v}{\partial t^2} = \frac{\partial \sigma_{xy}}{\partial x} + \frac{\partial \sigma_y}{\partial y} + 2\Lambda T_e \frac{\partial T_e}{\partial y}, \quad (3.2)$$

where

$$\sigma_x = \lambda(\varepsilon_x + \varepsilon_y) + 2\mu\varepsilon_x - (3\lambda + 2\mu)\alpha_T(T_l - T_0), \quad (3.3)$$

$$\sigma_y = \lambda(\varepsilon_x + \varepsilon_y) + 2\mu\varepsilon_y - (3\lambda + 2\mu)\alpha_T(T_l - T_0), \quad (3.4)$$

$$\sigma_{xy} = \mu\gamma_{xy} \quad (3.5)$$

$$\varepsilon_x = \frac{\partial u}{\partial x}, \quad \varepsilon_y = \frac{\partial v}{\partial y}, \quad \gamma_{xy} = \frac{\partial u}{\partial y} + \frac{\partial v}{\partial x}. \quad (3.6)$$

Here, u is the displacement in the thickness direction (x -direction) and v is the displacement in the length direction (y -direction); ε_x and ε_y are the normal strains in the x and y direction, respectively; γ_{xy} is the shear strain; σ_x and σ_y are the normal stresses in the x and y directions, respectively; σ_{xy} is the shear stress; T_e and T_l are electron and lattice temperatures; T_0 is an initial temperature; ρ is density; Λ is electron-blast coefficient; $\lambda = K - \frac{2}{3}\mu$ [Reismann 1980] where λ is Lame constant, K is bulk modulus, and μ is shear modulus; α_T is the thermal expansion coefficient.

(2) Energy equations [Tzou 2002, Chen 2002a, Brorson 1987, Qiu 1992, Wang 2006a]

$$C_e(T_e) \frac{\partial T_e}{\partial t} = \frac{\partial}{\partial x} \left[k_e(T_e, T_l) \frac{\partial T_e}{\partial x} \right] + \frac{\partial}{\partial y} \left[k_e(T_e, T_l) \frac{\partial T_e}{\partial y} \right] - G(T_e - T_l) + Q, \quad (3.7)$$

$$C_l \frac{\partial T_l}{\partial t} = G(T_e - T_l) - (3\lambda + 2\mu)\alpha_T \frac{\partial}{\partial t} (\varepsilon_x + \varepsilon_y), \quad (3.8)$$

where the heat source is given by

$$Q = 0.94J \frac{1-R}{t_p x_s} \exp \left[-\frac{x}{x_s} - \left(\frac{y}{y_s} \right)^2 - 2.77 \left(\frac{t - 2t_p}{t_p} \right)^2 \right]. \quad (3.9)$$

Here, $C_e(T_e) = C_{e0} \left(\frac{T_e}{T_0} \right)$ is the electron heat capacity, $k_e(T_e, T_l) = k_0 \left(\frac{T_e}{T_l} \right)$ is the thermal conductivity, G is the electron-lattice coupling factor, C_l is the lattice heat capacity,

respectively; Q is energy absorption rate; J is laser fluence; R is surface reflectivity; t_p is laser pulse duration; x_s is optical penetration depth; y_s is spatial profile parameter.

3.1.2 Initial and Boundary Conditions

The boundary condition are assumed to be

$$\sigma_x = 0, \quad \sigma_{xy} = 0, \quad \text{at } x = 0, L_x, \quad (3.10)$$

$$\sigma_y = 0, \quad \sigma_{xy} = 0, \quad \text{at } y = 0, L_y, \quad (3.11)$$

$$\frac{\partial T_e}{\partial \vec{n}} = 0, \quad \frac{\partial T_l}{\partial \vec{n}} = 0, \quad (3.12)$$

where \vec{n} is the unit outward normal vector on the boundary. It should be pointed out that insulated boundaries are imposed due to the assumption that there are no heat losses from the film surfaces in the short time response.

The initial conditions are assumed to be

$$T_e = T_l = T_0, \quad u = v = 0, \quad u_i = v_i = 0, \quad \text{at } t = 0. \quad (3.13)$$

3.2 Model for a Double-layered Thin Film

3.2.1 Governing Equations

We generalize our previous model to a two-dimensional plain strain double-layered microscale thin film in rectangular coordinates, which is exposed to ultrashort-pulsed lasers as shown in Fig. 3.2.

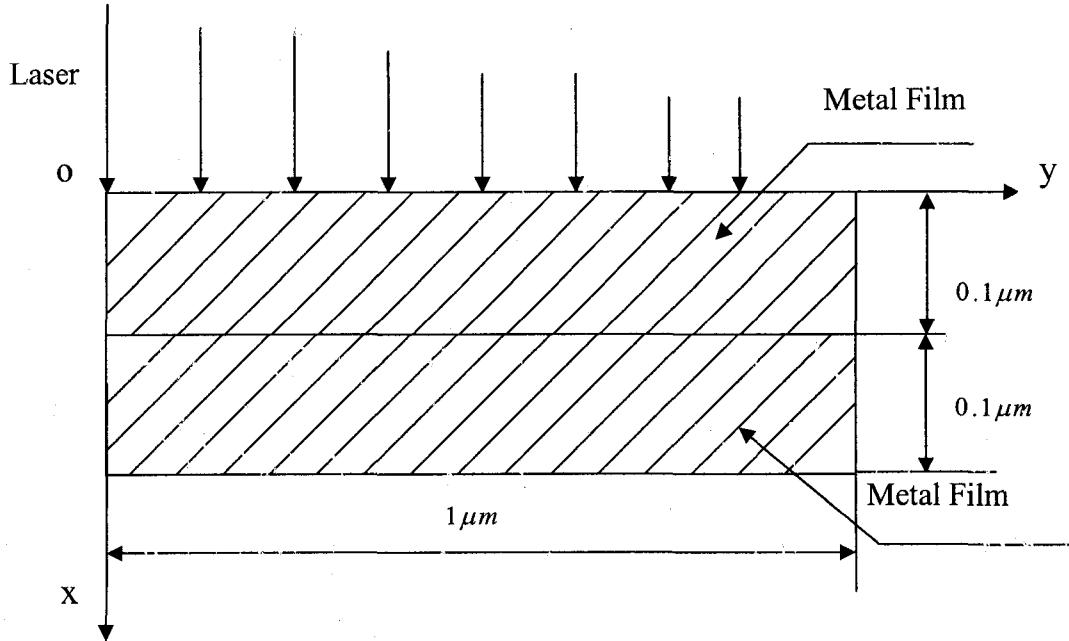


Fig. 3.2 Configuration of a double-layered thin metal film exposed to ultrashort-pulsed lasers.

The governing equations for studying thermal deformation in a thin film can be expressed as follows:

(1) Dynamic equations of motion [Tzou 2002, Chen 2002a, Brorson 1987, Qiu 1992, Wang 2006b]

$$\rho^{(m)} \frac{\partial^2 u^{(m)}}{\partial t^2} = \frac{\partial \sigma_x^{(m)}}{\partial x} + \frac{\partial \sigma_{xy}^{(m)}}{\partial y} + 2\Lambda^{(m)} T_e^{(m)} \frac{\partial T_e^{(m)}}{\partial x}, \quad (3.14)$$

$$\rho^{(m)} \frac{\partial^2 v^{(m)}}{\partial t^2} = \frac{\partial \sigma_{xy}^{(m)}}{\partial x} + \frac{\partial \sigma_y^{(m)}}{\partial y} + 2\Lambda^{(m)} T_e^{(m)} \frac{\partial T_e^{(m)}}{\partial y}, \quad (3.15)$$

where

$$\sigma_x^{(m)} = \lambda^{(m)} (\varepsilon_x^{(m)} + \varepsilon_y^{(m)}) + 2\mu^{(m)} \varepsilon_x^{(m)} - (3\lambda^{(m)} + 2\mu^{(m)}) \alpha_T^{(m)} (T_l^{(m)} - T_0), \quad (3.16)$$

$$\sigma_y^{(m)} = \lambda^{(m)} (\varepsilon_x^{(m)} + \varepsilon_y^{(m)}) + 2\mu^{(m)} \varepsilon_y^{(m)} - (3\lambda^{(m)} + 2\mu^{(m)}) \alpha_T^{(m)} (T_l^{(m)} - T_0), \quad (3.17)$$

$$\sigma_{xy}^{(m)} = \mu^{(m)} \gamma_{xy}^{(m)}, \quad (3.18)$$

$$\begin{aligned}\varepsilon_x^{(m)} &= \frac{\partial u^{(m)}}{\partial x}, & \varepsilon_y^{(m)} &= \frac{\partial v^{(m)}}{\partial y}, \\ \gamma_{xy}^{(m)} &= \frac{\partial u^{(m)}}{\partial y} + \frac{\partial v^{(m)}}{\partial x}.\end{aligned}\quad (3.19)$$

Here, $m = 1, 2$, denotes layer 1 and layer 2, respectively; $u^{(m)}$ is the displacement in the thickness direction (x -direction) and $v^{(m)}$ is the displacement in the length direction (y -direction); $\varepsilon_x^{(m)}$ and $\varepsilon_y^{(m)}$ are the normal strains in x and y directions, respectively; $\gamma_{xy}^{(m)}$ is the shear strain; $\sigma_x^{(m)}$ and $\sigma_y^{(m)}$ are the normal stresses in x and y directions, respectively; $\sigma_{xy}^{(m)}$ is the shear stress; $T_e^{(m)}$ and $T_l^{(m)}$ are electron and lattice temperatures, respectively; T_0 is initial temperature; $\lambda^{(m)} = K^{(m)} - \frac{2}{3}\mu^{(m)}$ [Reismann 1980] where $\lambda^{(m)}$ is Lame constant, $K^{(m)}$ is bulk modulus, and $\mu^{(m)}$ is shear modulus; $\alpha_T^{(m)}$ is thermal expansion coefficient.

(2) Energy equations [Tzou 2002, Chen 2002a, Brorson 1987, Qiu 1992, Wang 2006b]

$$\begin{aligned}(C_e(T_e))^{(m)} \frac{\partial T_e^{(m)}}{\partial t} &= \frac{\partial}{\partial x} \left[(k_e(T_e, T_l))^{(m)} \frac{\partial T_e^{(m)}}{\partial x} \right] \\ &+ \frac{\partial}{\partial y} \left[(k_e(T_e, T_l))^{(m)} \frac{\partial T_e^{(m)}}{\partial y} \right] - G^{(m)}(T_e^{(m)} - T_l^{(m)}) + Q,\end{aligned}\quad (3.20)$$

$$C_l^{(m)} \frac{\partial T_l^{(m)}}{\partial t} = G^{(m)}(T_e^{(m)} - T_l^{(m)}) - (3\lambda^{(m)} + 2\mu^{(m)})\alpha_T^{(m)} \frac{\partial}{\partial t}(\varepsilon_x + \varepsilon_y),\quad (3.21)$$

where the heat source is given by

$$Q = 0.94J \frac{1-R}{t_p x_s} \exp \left[-\frac{x}{x_s} - \left(\frac{y}{y_s} \right)^2 - 2.77 \left(\frac{t - 2t_p}{t_p} \right)^2 \right].\quad (3.22)$$

Here, $(C_e(T_e))^{(m)} = C_{e0}^{(m)} \cdot \frac{T_e^{(m)}}{T_0}$ is the electron heat capacity; $(k_e(T_e, T_l))^{(m)}$ is the electron thermal conductivity; $G^{(m)}$ is the electron-lattice coupling factor; $C_l^{(m)}$ is the lattice heat capacities; Q is the energy absorption rate; J is the laser fluence; R is the surface reflectivity; t_p is the laser pulse duration; x_s is the optical penetration depth, and y_s is the spatial profile parameter.

3.2.2 Initial and Boundary Conditions

The boundary conditions are assumed to be

$$\begin{aligned}\sigma_x^{(1)} &= 0, & \sigma_{xy}^{(1)} &= 0, & \text{at } x = 0, \text{ and} \\ \sigma_x^{(2)} &= 0, & \sigma_{xy}^{(2)} &= 0, & \text{at } x = L_x,\end{aligned}\quad (3.23)$$

$$\begin{aligned}\sigma_y^{(1)} &= 0, & \sigma_{xy}^{(1)} &= 0, & \text{at } y = 0, \text{ and} \\ \sigma_y^{(2)} &= 0, & \sigma_{xy}^{(2)} &= 0, & \text{at } y = L_y,\end{aligned}\quad (3.24)$$

$$\frac{\partial T_e^{(m)}}{\partial \vec{n}} = 0, \quad \frac{\partial T_l^{(m)}}{\partial \vec{n}} = 0, \quad (3.25)$$

where \vec{n} is the unit outward normal vector on the boundary. It should be pointed out that insulated boundaries are imposed due to the assumption that there are no heat losses from the film surfaces in the short time response.

The initial conditions are assumed to be

$$T_e^{(m)} = T_l^{(m)} = T_0, \quad (3.26)$$

$$u^{(m)} = v^{(m)} = 0, \quad (3.27)$$

$$u_t^{(m)} = v_t^{(m)} = 0, \quad (3.28)$$

at $t = 0$, where $m = 1, 2$.

3.2.3 Interfacial Conditions

There are two cases at the interface of the double-layered thin film. One is perfect thermal contact at interface, which is a simple one. The other is imperfect thermal contact at interface. Nonlinear interfacial condition for temperature is considered. The interfacial conditions for stress, strain, and displacement are derived.

Case 1: Perfectly thermal contact at interface

The perfect contact interfacial conditions are assumed to be, at $x = L_x / 2$,

$$u^{(1)} = u^{(2)}, \quad v^{(1)} = v^{(2)}, \quad (3.29)$$

$$\sigma_x^{(1)} = \sigma_x^{(2)}, \quad \sigma_{xy}^{(1)} = \sigma_{xy}^{(2)}, \quad (3.30)$$

$$T_e^{(1)} = T_e^{(2)}, \quad k_e^{(1)} \frac{\partial T_e^{(1)}}{\partial x} = k_e^{(2)} \frac{\partial T_e^{(2)}}{\partial x}. \quad (3.31)$$

Case 2: Imperfectly thermal contact at interface [Wang]

The nonlinear interfacial condition for T_e can be written as follows [Dai 2001, Joshi 1993]:

$$-k_e^{(1)} \frac{\partial T_e^{(1)}}{\partial x} = -k_e^{(2)} \frac{\partial T_e^{(2)}}{\partial x} = \sigma \left[\left(T_e^{(1)} \right)^4 - \left(T_e^{(2)} \right)^4 \right] \quad T_e^{(1)} \neq T_e^{(2)}, \quad (3.32)$$

where $\sigma = 5.669 \times 10^{-8} W / m^2 K^4$ is Stefan-Boltzmann constant. Once T_e is obtained, T_l at interface can be obtained based on Eq. (3.21).

To obtain the interfacial conditions for stress and displacement, we first assume that shear stresses are equal at interface,

$$\sigma_{xy}^{(1)} = \sigma_{xy}^{(2)}. \quad (3.33)$$

From Eqs. (3.18) and (3.19), we obtain that $\mu^{(1)}\gamma_{xy}^{(1)} = \mu^{(2)}\gamma_{xy}^{(2)}$ and hence

$$\mu^{(1)}\left(\frac{\partial u^{(1)}}{\partial y} + \frac{\partial v^{(1)}}{\partial x}\right) = \mu^{(2)}\left(\frac{\partial u^{(2)}}{\partial y} + \frac{\partial v^{(2)}}{\partial x}\right). \text{ It is noted that if } \mu^{(1)}\frac{\partial u^{(1)}}{\partial y} = \mu^{(2)}\frac{\partial u^{(2)}}{\partial y} \text{ and}$$

$$\mu^{(1)}\frac{\partial v^{(1)}}{\partial x} = \mu^{(2)}\frac{\partial v^{(2)}}{\partial x}, \text{ then } \mu^{(1)}\left(\frac{\partial u^{(1)}}{\partial y} + \frac{\partial v^{(1)}}{\partial x}\right) = \mu^{(2)}\left(\frac{\partial u^{(2)}}{\partial y} + \frac{\partial v^{(2)}}{\partial x}\right) \text{ is satisfied. For the}$$

$$\text{purpose of simple computation later on, we assume that } \mu^{(1)}\frac{\partial u^{(1)}}{\partial y} = \mu^{(2)}\frac{\partial u^{(2)}}{\partial y} \text{ and}$$

$$\mu^{(1)}\frac{\partial v^{(1)}}{\partial x} = \mu^{(2)}\frac{\partial v^{(2)}}{\partial x}. \text{ This leads us to assume the interfacial condition for displacements}$$

to be, for simplicity,

$$\mu^{(1)}u^{(1)} = \mu^{(2)}u^{(2)} \quad \text{and} \quad \mu^{(1)}v^{(1)} = \mu^{(2)}v^{(2)}. \quad (3.34)$$

$$\text{Based on this assumption, we obtain that } \mu^{(1)}\frac{\partial u^{(1)}}{\partial x} = \mu^{(2)}\frac{\partial u^{(2)}}{\partial x} \text{ and hence}$$

$$\mu^{(1)}\varepsilon_x^{(1)} = \mu^{(2)}\varepsilon_x^{(2)} \text{ from Eq. (3.19).}$$

$$\text{Since, } \varepsilon_x^{(m)} = \frac{1}{E^{(m)}}[(1-\gamma^2)\sigma_x^{(m)} - \gamma(1+\gamma)\sigma_y^{(m)}] + \alpha_T^{(m)}(T_l^{(m)} - T_0) \text{ [Timoshenko 1970,}$$

Bruno 1997], where E is Young's modulus and γ is Poisson ratio, we substitute it into

$$\mu^{(1)}\frac{\partial u^{(1)}}{\partial x} = \mu^{(2)}\frac{\partial u^{(2)}}{\partial x} \text{ and obtain}$$

$$\begin{aligned} & \frac{\mu^{(1)}}{E^{(1)}}[(1-\gamma^2)\sigma_x^{(1)} - \gamma(1+\gamma)\sigma_y^{(1)}] + \mu^{(1)}\alpha_T^{(1)}(T_l^{(1)} - T_0) \\ &= \frac{\mu^{(2)}}{E^{(2)}}[(1-\gamma^2)\sigma_x^{(2)} - \gamma(1+\gamma)\sigma_y^{(2)}] + \mu^{(2)}\alpha_T^{(2)}(T_l^{(2)} - T_0) \end{aligned} \quad (3.35)$$

Again, for simplicity, we assume that $\mu^{(1)}\left(\frac{(1-\gamma^2)\sigma_x^{(1)}}{E^{(1)}}\right) = \mu^{(2)}\left(\frac{(1-\gamma^2)\sigma_x^{(2)}}{E^{(2)}}\right)$ and $\frac{\mu^{(1)}}{E^{(1)}}(-\gamma(1+\gamma)\sigma_y^{(1)}) + \mu^{(1)}\alpha_T^{(1)}(T_l^{(1)} - T_0) = \frac{\mu^{(2)}}{E^{(2)}}(-\gamma(1+\gamma)\sigma_y^{(2)}) + \mu^{(2)}\alpha_T^{(2)}(T_i^{(2)} - T_0)$. Since we are only interested in $\mu^{(1)}\left(\frac{(1-\gamma^2)\sigma_x^{(1)}}{E^{(1)}}\right) = \mu^{(2)}\left(\frac{(1-\gamma^2)\sigma_x^{(2)}}{E^{(2)}}\right)$, hence we have interfacial condition to be

$$\mu^{(1)}\left(\frac{\sigma_x^{(1)}}{E^{(1)}}\right) = \mu^{(2)}\left(\frac{\sigma_x^{(2)}}{E^{(2)}}\right). \quad (3.36)$$

3.3 Conclusion

In this chapter, we have set up governing equations for a single-layered thin film, and a double-layered thin film with perfect thermal contact at the interface and imperfect thermal contact at the interface. However, the mathematical complexity of the coupled, nonlinear, transient governing Eqs. (3.1)-(3.9) for a thin metal film and Eqs. (3.14)-(3.22) for a double-layered thin film, primarily due to the temperature-dependent thermophysical properties such as $C_e(T_e)$, $C_l(T_l)$, and $k_e(T_e, T_l)$ and due to the nonlinear hot-electron blast force, makes it impossible to derive closed-form solutions to the present plain strain thermoelasticity model. Hence, numerical method is needed in order to solve the mathematical models.

CHAPTER FOUR

NUMERICAL METHOD

In this chapter, we will develop a finite difference method for solving governing equations set up in the last chapter. For thin film, the ratio of length to thickness is very large. In view of the fact that the numerical difficulty caused by a grid mesh having a high aspect ratio is less for finite difference methods than for finite element methods, the hyperbolic-parabolic partial differential equation system combined with the initial and boundary conditions is solved with a finite difference method.

4.1 Notations

We denote u_{ij}^n as numerical approximation of $u(i\Delta x, j\Delta y, n\Delta t)$, where Δt , Δx and Δy are time increment and spatial step sizes, respectively, and $1 \leq i \leq N_x + 1$ and $1 \leq j \leq N_y + 1$ so that $N_x \Delta x = L_x$, $N_y \Delta y = L_y$ where i and j are indices in x and y direction, respectively. Then we introduce the finite difference operators Δ_{-t} , δ_x , and δ_y as follows:

$$\Delta_{-t} u_{ij}^n = u_{ij}^n - u_{ij}^{n-1}, \quad (4.1)$$

$$\delta_x u_{ij}^n = u_{i+1/2,j}^n - u_{i-1/2,j}^n, \quad (4.2)$$

$$\delta_y u_{ij}^n = u_{i,j+1/2}^n - u_{i,j-1/2}^n. \quad (4.3)$$

4.2 Finite Difference Scheme and Algorithm for Single-Layered Thin Film Model

4.2.1 Conversion of the Governing Equations

In order to prevent the solution from oscillations, we introduce two velocity components v_1 and v_2 into the model and rewrite the dynamic equations of motion, Eqs. (3.1) – (3.6), as follows:

$$v_1 = \frac{\partial u}{\partial t}, \quad v_2 = \frac{\partial v}{\partial t}, \quad (4.4)$$

$$\rho \frac{\partial v_1}{\partial t} = \frac{\partial \sigma_x}{\partial x} + \frac{\partial \sigma_{xy}}{\partial y} + \Lambda \frac{\partial T_e^2}{\partial x}, \quad (4.5)$$

$$\rho \frac{\partial v_2}{\partial t} = \frac{\partial \sigma_{xy}}{\partial x} + \frac{\partial \sigma_y}{\partial y} + \Lambda \frac{\partial T_e^2}{\partial y}, \quad (4.6)$$

$$\frac{\partial \varepsilon_x}{\partial t} = \frac{\partial v_1}{\partial x}, \quad \frac{\partial \varepsilon_y}{\partial t} = \frac{\partial v_2}{\partial y}, \quad \frac{\partial \gamma_{xy}}{\partial t} = \frac{\partial v_2}{\partial x} + \frac{\partial v_1}{\partial y}. \quad (4.7)$$

4.2.2 Staggered Grid

To develop a finite difference scheme, we first construct a staggered grid as shown in Fig. 4.1, where v_1 is placed at $(x_{i+1/2}, y_j)$, v_2 is placed at $(x_i, y_{j+1/2})$, γ_{xy} and σ_{xy} are placed at $(x_{i+1/2}, y_{j+1/2})$, while ε_x , ε_y , σ_x , σ_y , T_e and T_l are at (x_i, y_j) . We denote $v_1^n(i+1/2, j)$ and $v_2^n(i, j+1/2)$ as numerical approximations of $v_1((i+1/2)\Delta x, j\Delta y, n\Delta t)$ and $v_2(i\Delta x, (j+1/2)\Delta y, n\Delta t)$, respectively. Similar notations are used for other variables.

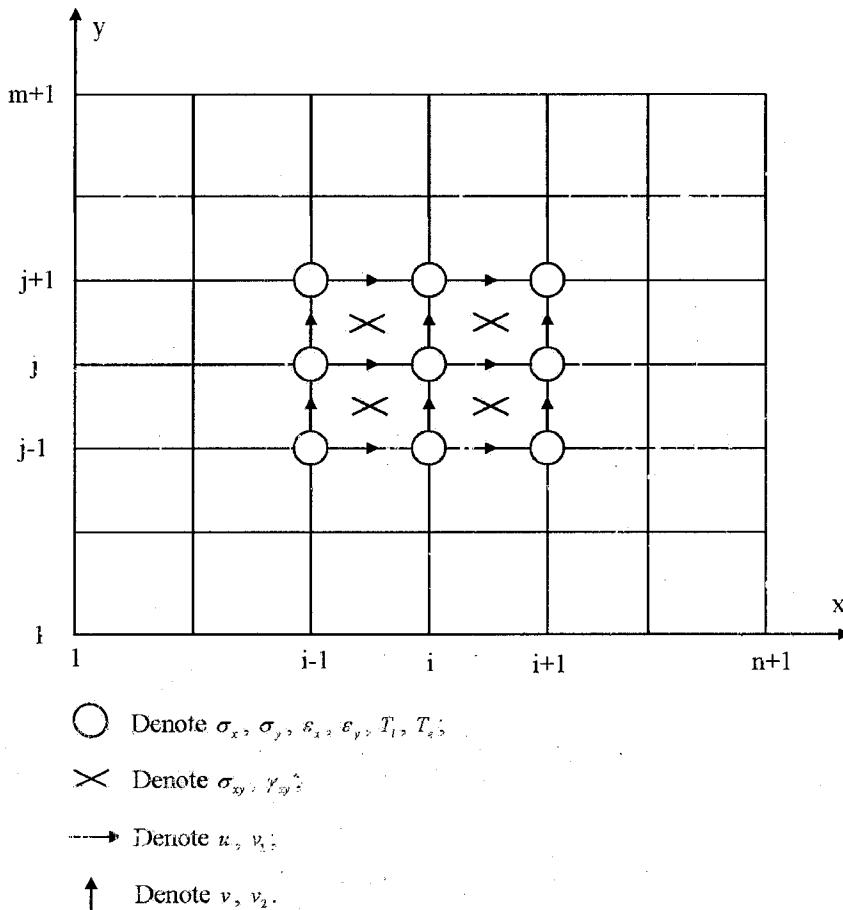


Fig. 4.1 A staggered a mesh for single-layered thin film.

It should be pointed out that the staggered grid method is often employed in computational fluid dynamics to prevent the solution from oscillation [Patankar 1980]. For example, if v_1 and ϵ_x are placed at a same location, employing a central finite difference scheme may produce a velocity component v_1 , a wave solution, implying oscillation.

4.2.3 Finite Difference Scheme and Algorithm

We now develop a finite difference method for solving the above governing equations. To this end, we first discretize Eqs. (4.5) and (4.6) using a backward finite difference scheme as follows:

$$\begin{aligned}
& \rho \frac{1}{\Delta t} \Delta_{-t} v_1^{n+1}(i+1/2, j) \\
&= \frac{1}{\Delta x} \delta_x \sigma_x^{n+1}(i+1/2, j) + \frac{1}{\Delta y} \delta_y \sigma_y^{n+1}(i+1/2, j) \\
&+ \Lambda \frac{1}{\Delta x} \delta_x (T_e^2)^{n+1}(i+1/2, j),
\end{aligned} \tag{4.8}$$

$$\begin{aligned}
& \rho \frac{1}{\Delta t} \Delta_{-t} v_2^{n+1}(i, j+1/2) \\
&= \frac{1}{\Delta x} \delta_x \sigma_{xy}^{n+1}(i, j+1/2) + \frac{1}{\Delta y} \delta_y \sigma_y^{n+1}(i, j+1/2) \\
&+ \Lambda \frac{1}{\Delta y} \delta_y (T_e^2)^{n+1}(i, j+1/2),
\end{aligned} \tag{4.9}$$

where Eq. (4.7) is discretized by using backward finite difference scheme as follows:

$$\frac{1}{\Delta t} \Delta_{-t} \varepsilon_x^{n+1}(i, j) = \frac{1}{\Delta x} \delta_x v_1^{n+1}(i, j), \tag{4.10}$$

$$\frac{1}{\Delta t} \Delta_{-t} \varepsilon_y^{n+1}(i, j) = \frac{1}{\Delta y} \delta_y v_2^{n+1}(i, j), \tag{4.11}$$

$$\begin{aligned}
& \frac{1}{\Delta t} \Delta_{-t} \gamma_{xy}^{n+1}(i+1/2, j+1/2) \\
&= \frac{1}{\Delta x} \delta_x v_2^{n+1}(i+1/2, j+1/2) + \frac{1}{\Delta y} \delta_y v_1^{n+1}(i+1/2, j+1/2),
\end{aligned} \tag{4.12}$$

and Eqs. (3.3)-(3.5) are discretized as

$$\begin{aligned}
\sigma_x^{n+1}(i, j) &= \lambda [\varepsilon_x^{n+1}(i, j) + \varepsilon_y^{n+1}(i, j)] + 2\mu \varepsilon_x^{n+1}(i, j) \\
&- (3\lambda + 2\mu) \alpha_T [T_l^{n+1}(i, j) - T_0]
\end{aligned} \tag{4.13}$$

$$\begin{aligned}
\sigma_y^{n+1}(i, j) &= \lambda [\varepsilon_x^{n+1}(i, j) + \varepsilon_y^{n+1}(i, j)] + 2\mu \varepsilon_y^{n+1}(i, j) \\
&- (3\lambda + 2\mu) \alpha_T [T_l^{n+1}(i, j) - T_0]
\end{aligned} \tag{4.14}$$

$$\sigma_{xy}^{n+1}(i+1/2, j+1/2) = \mu \gamma_{xy}^{n+1}(i+1/2, j+1/2). \tag{4.15}$$

We then discretize Eqs. (3.7) and (3.8) using the Crank-Nicholson method as follows:

$$\begin{aligned}
& C_{e0} \left[\frac{T_e^{n+1}(i, j) + T_e^n(i, j)}{2} \right] \frac{1}{\Delta t} \Delta_{-t} T_e^{n+1}(i, j) \\
&= \frac{1}{2\Delta x^2} \left[k_e^{n+1}(i+1/2, j) \delta_x T_e^{n+1}(i+1/2, j) \right. \\
&\quad \left. - k_e^{n+1}(i-1/2, j) \delta_x T_e^{n+1}(i-1/2, j) \right] \\
&\quad + \frac{1}{2\Delta x^2} \left[k_e^n(i+1/2, j) \delta_x T_e^n(i+1/2, j) \right. \\
&\quad \left. - k_e^n(i-1/2, j) \delta_x T_e^n(i-1/2, j) \right] \\
&\quad + \frac{1}{2\Delta y^2} \left[k_e^{n+1}(i, j+1/2) \delta_y T_e^{n+1}(i, j+1/2) \right. \\
&\quad \left. - k_e^{n+1}(i, j-1/2) \delta_y T_e^{n+1}(i, j-1/2) \right] \\
&\quad + \frac{1}{2\Delta y^2} \left[k_e^n(i, j+1/2) \delta_y T_e^n(i, j+1/2) \right. \\
&\quad \left. - k_e^n(i, j-1/2) \delta_y T_e^n(i, j-1/2) \right] \\
&\quad - G \left[\frac{T_e^{n+1}(i, j) + T_e^n(i, j)}{2} - \frac{T_l^{n+1}(i, j) + T_l^n(i, j)}{2} \right] \\
&\quad + Q^{n+1/2}(i, j),
\end{aligned} \tag{4.16}$$

$$\begin{aligned}
& C_l \frac{1}{\Delta t} \Delta_{-t} T_l^{n+1}(i, j) \\
&= G \left[\frac{T_e^{n+1}(i, j) + T_e^n(i, j)}{2} - \frac{T_l^{n+1}(i, j) + T_l^n(i, j)}{2} \right] \\
&\quad - (3\lambda + 2\mu) \alpha_T \left[\frac{\Delta_{-t} \varepsilon_x^{n+1}(i, j)}{\Delta t} + \frac{\Delta_{-t} \varepsilon_x^n(i, j)}{\Delta t} \right].
\end{aligned} \tag{4.17}$$

Finally, the displacements, u and v , are obtained using the Euler backward scheme for Eq. (4.4) as follows:

$$\frac{1}{\Delta t} \Delta_{-t} u^{n+1}(i+1/2, j) = v_1^{n+1}(i+1/2, j), \tag{4.18}$$

$$\frac{1}{\Delta t} \Delta_{-t} v^{n+1}(i, j+1/2) = v_2^{n+1}(i, j+1/2), \tag{4.19}$$

The boundary conditions, Eqs. (3.10)-(3.12), are discretized as follows:

$$\sigma_x^n(1, j) = 0, \quad \sigma_x^n(N_x + 1, j) = 0, \quad 1 \leq j \leq N_y + 1, \tag{4.20a}$$

$$\sigma_{xy}^n(1+1/2, j+1/2) = 0, \quad \sigma_{xy}^n(N_x + 1/2, j+1/2) = 0,$$

$$1 \leq j \leq N_y + 1, \quad (4.21b)$$

$$\sigma_y^n(i,1) = 0, \quad \sigma_y^n(N_y + 1, j) = 0, \quad 1 \leq i \leq N_x + 1, \quad (4.22a)$$

$$\sigma_{xy}^n(i + 1/2, 1 + 1/2) = 0, \quad \sigma_{xy}^n(i + 1/2, N_y + 1/2) = 0,$$

$$1 \leq i \leq N_x + 1, \quad (4.22b)$$

$$T_e^n(1, j) = T_e^n(2, j), \quad T_e^n(N_x + 1, j) = T_e^n(N_x, j),$$

$$1 \leq j \leq N_y + 1, \quad (4.23a)$$

$$T_e^n(i, 1) = T_e^n(i, 2), \quad T_e^n(i, N_y + 1) = T_e^n(i, N_y),$$

$$1 \leq i \leq N_x + 1, \quad (4.23b)$$

$$T_l^n(1, j) = T_l^n(2, j), \quad T_l^n(N_x + 1, j) = T_l^n(N_x, j),$$

$$1 \leq j \leq N_y + 1, \quad (4.24a)$$

$$T_l^n(i, 1) = T_l^n(i, 2), \quad T_l^n(i, N_y + 1) = T_l^n(i, N_y),$$

$$1 \leq i \leq N_x + 1, \quad (4.24b)$$

for any time level n . The initial conditions, Eq. (3.13), are approximated as follows:

$$u^0(i + 1/2, j) = 0, \quad v^0(i, j + 1/2) = 0, \quad (4.25a)$$

$$v_1^0(i + 1/2, j) = 0, \quad v_2^0(i, j + 1/2) = 0,$$

$$1 \leq i \leq N_x, \quad 1 \leq j \leq N_y, \quad (4.25b)$$

$$T_e^0(i, j) = T_l^0(i, j) = T_0,$$

$$1 \leq i \leq N_x + 1, \quad 1 \leq j \leq N_y + 1, \quad (4.25c)$$

$$\varepsilon_x^0(i, j) = \varepsilon_y^0(i, j) = 0, \quad (4.25d)$$

$$\sigma_x^0(i, j) = \sigma_y^0(i, j) = 0,$$

$$1 \leq i \leq N_x + 1, \quad 1 \leq j \leq N_y + 1, \quad (4.25e)$$

$$\sigma_{xy}^0(i+1/2, j+1/2) = \gamma_{xy}^0(i+1/2, j+1/2) = 0,$$

$$1 \leq i \leq N_x, \quad 1 \leq j \leq N_y. \quad (4.25f)$$

It can be seen that the truncation error of Eqs. (4.8) and (4.9) is $O(\Delta t + \Delta x^2 + \Delta y^2)$ and the truncation error of Eqs. (4.16) and (4.17) is $O(\Delta t^2 + \Delta x^2 + \Delta y^2)$. It should be pointed out that Eqs. (4.8) and (4.9) are nonlinear since the terms $\delta_x(T_e^2)^{n+1}(i+1/2, j)$ and $\delta_y(T_e^2)^{n+1}(i, j+1/2)$ are nonlinear. It can be seen that Eqs. (4.16) and (4.17) are nonlinear. Therefore, the above scheme must be solved iteratively. An algorithm for solving the above scheme at time level $n+1$ is developed as follows:

Step 1. Guess ε_x^{n+1} , ε_y^{n+1} and γ_{xy}^{n+1} by using the values of ε_x^n , ε_y^n and γ_{xy}^n . Solve Eqs. (4.16) and (4.17) iteratively for T_e^{n+1} and T_t^{n+1} .

Step 2. Solve for σ_x^{n+1} , σ_y^{n+1} and σ_{xy}^{n+1} using Eqs. (4.13)-(4.15).

Step 3. Solve for v_1^{n+1} and v_2^{n+1} using equation (4.8) and (4.9).

Step 4. Update ε_x^{n+1} , ε_y^{n+1} and γ_{xy}^{n+1} using equations (4.10)-(4.12).

Repeat the above steps until a convergent solution is obtained.

Note that the present method does not introduce an artificial viscosity term into the dynamic equations of motion. Recall that Chen et al.'s method [Chen 2002a] introduces an artificial viscosity term,

$$\Pi = \omega_L \rho V_s \Delta \bar{x} (trD) - \rho (\omega_Q \Delta \bar{x})^2 |trD| (trD), \quad (4.26)$$

into the dynamical equations of motion

$$\rho \frac{\partial^2 u}{\partial t^2} = \frac{\partial \sigma_x}{\partial x} + \frac{\partial \sigma_{xy}}{\partial y} + 2\Lambda T_e \frac{\partial T_e}{\partial x} + \frac{\partial \Pi}{\partial x}, \quad (4.27)$$

$$\rho \frac{\partial^2 v}{\partial t^2} = \frac{\partial \sigma_{xy}}{\partial x} + \frac{\partial \sigma_y}{\partial y} + 2\Lambda T_e \frac{\partial T_e}{\partial y} + \frac{\partial \Pi}{\partial y}, \quad (4.28)$$

in order to suppress oscillations in the thermal stress wave. Here, $\Delta\bar{x}$ is a characteristic dimension, v_s is the speed of sound, ω_i and ω_ρ are constants, and the velocity gradients term trD is defined as

$$trD = \frac{\partial^2 u}{\partial x \partial t} + \frac{\partial^2 v}{\partial y \partial t}. \quad (4.29)$$

In the next chapter, we will provide comparison between the results obtained with Chen et al.'s procedure and the methodology proposed here.

4.3 Finite Difference Scheme and Algorithm for Double-Layered Thin Film Model

4.3.1 Conversion of the Governing Equations

Using a similar argument in the previous system, we first introduce two velocity components $v_1^{(m)}$ and $v_2^{(m)}$ into the model and re-write the dynamic equations of motion, Eqs. (3.14) – (3.19), as follows:

$$v_1^{(m)} = \frac{\partial u^{(m)}}{\partial t}, \quad v_2^{(m)} = \frac{\partial v^{(m)}}{\partial t}, \quad (4.30)$$

$$\begin{aligned} \frac{\partial \epsilon_x^{(m)}}{\partial t} &= \frac{\partial v_1^{(m)}}{\partial x}, & \frac{\partial \epsilon_y^{(m)}}{\partial t} &= \frac{\partial v_2^{(m)}}{\partial y}, \\ \frac{\partial \gamma_{xy}^{(m)}}{\partial t} &= \frac{\partial v_2^{(m)}}{\partial x} + \frac{\partial v_1^{(m)}}{\partial y}, \end{aligned} \quad (4.31)$$

$$\rho^{(m)} \frac{\partial v_1^{(m)}}{\partial t} = \frac{\partial \sigma_x^{(m)}}{\partial x} + \frac{\partial \sigma_{xy}^{(m)}}{\partial y} + \Lambda^{(m)} \frac{\partial (T_e^2)^{(m)}}{\partial x}, \quad (4.32)$$

$$\rho^{(m)} \frac{\partial v_2^{(m)}}{\partial t} = \frac{\partial \sigma_{xy}^{(m)}}{\partial x} + \frac{\partial \sigma_y^{(m)}}{\partial y} + \Lambda^{(m)} \frac{\partial (T_e^2)^{(m)}}{\partial y}. \quad (4.33)$$

4.3.2 Staggered Grid

To develop a finite difference scheme, we first construct a staggered grid as shown in Fig. 4.2, where $v_1^{(m)}$ is placed at $(x_{i+1/2}, y_j)$, $v_2^{(m)}$ is placed at $(x_i, y_{j+1/2})$, $\gamma_{xy}^{(m)}$ and $\sigma_{xy}^{(m)}$ are placed at $(x_{i+1/2}, y_{j+1/2})$, while $\varepsilon_x^{(m)}$, $\varepsilon_y^{(m)}$, $\sigma_x^{(m)}$, $\sigma_y^{(m)}$, $T_e^{(m)}$ and $T_l^{(m)}$ are at (x_i, y_j) . Here, i and j are indices with $1 \leq i \leq 2N+1$ and $1 \leq j \leq M+1$. We denote $(v_1^n(i+1/2, j))^{(m)}$ and $(v_2^n(i, j+1/2))^{(m)}$ as numerical approximations of $v_1^{(m)}((i+1/2)\Delta x, j\Delta y, n\Delta t)$ and $v_2^{(m)}(i\Delta x, (j+1/2)\Delta y, n\Delta t)$, respectively. Similar notations are used for other variables.

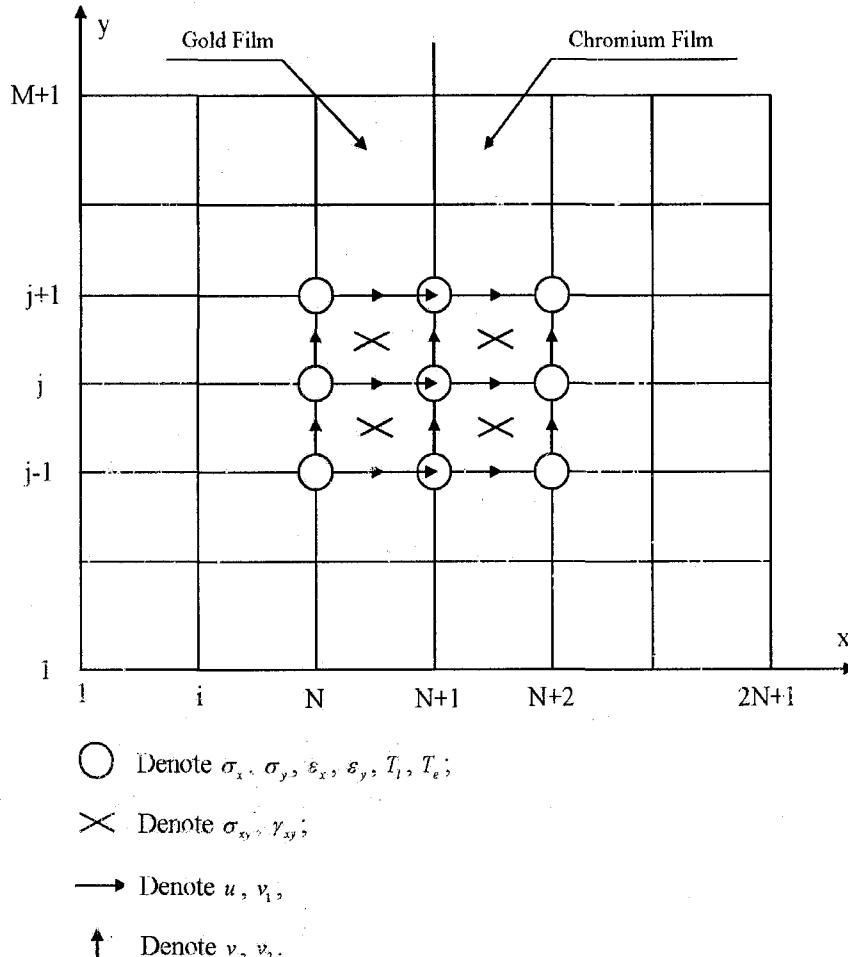


Fig. 4.2 A staggered mesh for double-layered thin film.

4.3.3 Finite Difference Scheme and Algorithm

We now develop a finite difference method for solving the above governing equations. To this end, we first discretize Eqs. (4.32) and (4.33) by using an implicit finite difference scheme as follows:

$$\begin{aligned}
 & \rho^{(m)} \frac{1}{\Delta t} \Delta_{-t} (v_1^{n+1})^{(m)}(i+1/2, j) \\
 &= \frac{1}{\Delta x} \delta_x (\sigma_x^{n+1})^{(m)}(i+1/2, j) + \frac{1}{\Delta y} \delta_y (\sigma_y^{n+1})^{(m)}(i+1/2, j) \\
 &+ \Lambda^{(m)} \frac{1}{\Delta x} \delta_x [(T_e^2)^{n+1}]^{(m)}(i+1/2, j),
 \end{aligned} \tag{4.34}$$

$$\begin{aligned}
& \rho^{(m)} \frac{1}{\Delta t} \Delta_{-t} (v_2^{n+1})^{(m)}(i, j + 1/2) \\
&= \frac{1}{\Delta x} \delta_x (\sigma_{xy}^{n+1})^{(m)}(i, j + 1/2) + \frac{1}{\Delta y} \delta_y (\sigma_y^{n+1})^{(m)}(i, j + 1/2) \\
&\quad + \Lambda^{(m)} \frac{1}{\Delta y} \delta_y [(T_e^2)^{n+1}]^{(m)}(i, j + 1/2),
\end{aligned} \tag{4.35}$$

where Eq. (4.31) is discretized as follows:

$$\frac{1}{\Delta t} \Delta_{-t} (\varepsilon_x^{n+1})^{(m)}(i, j) = \frac{1}{\Delta x} \delta_x (v_1^{n+1})^{(m)}(i, j), \tag{4.36}$$

$$\frac{1}{\Delta t} \Delta_{-t} (\varepsilon_y^{n+1})^{(m)}(i, j) = \frac{1}{\Delta y} \delta_y (v_2^{n+1})^{(m)}(i, j), \tag{4.37}$$

$$\begin{aligned}
& \frac{1}{\Delta t} \Delta_{-t} (\gamma_{xy}^{n+1})^{(m)}(i + 1/2, j + 1/2) \\
&= \frac{1}{\Delta x} \delta_x (v_2^{n+1})^{(m)}(i + 1/2, j + 1/2) + \frac{1}{\Delta y} \delta_y (v_1^{n+1})^{(m)}(i + 1/2, j + 1/2),
\end{aligned} \tag{4.38}$$

and Eqs. (3.16)-(3.18) are discretized as

$$\begin{aligned}
(\sigma_x^{n+1})^{(m)}(i, j) &= \lambda^{(m)} [(\varepsilon_x^{n+1})^{(m)}(i, j) + (\varepsilon_y^{n+1})^{(m)}(i, j)] \\
&\quad + 2\mu^{(m)} (\varepsilon_x^{n+1})^{(m)}(i, j) \\
&\quad - (3\lambda^{(m)} + 2\mu^{(m)}) \alpha_T^{(m)} [(T_l^{n+1})^{(m)}(i, j) - T_0]
\end{aligned} \tag{4.39}$$

$$\begin{aligned}
(\sigma_y^{n+1})^{(m)}(i, j) &= \lambda^{(m)} [(\varepsilon_x^{n+1})^{(m)}(i, j) + (\varepsilon_y^{n+1})^{(m)}(i, j)] \\
&\quad + 2\mu^{(m)} (\varepsilon_y^{n+1})^{(m)}(i, j) \\
&\quad - (3\lambda^{(m)} + 2\mu^{(m)}) \alpha_T^{(m)} [(T_l^{n+1})^{(m)}(i, j) - T_0]
\end{aligned} \tag{4.40}$$

$$(\sigma_{xy}^{n+1})^{(m)}(i + 1/2, j + 1/2) = \mu^{(m)} (\gamma_{xy}^{n+1})^{(m)}(i + 1/2, j + 1/2). \tag{4.41}$$

We then discretize Eqs (3.20) and (3.21) by using the Crank-Nicholson method as follows:

$$\begin{aligned}
& C_{e0}^{(m)} \left[\frac{(T_e^{n+1})^{(m)}(i, j) + (T_e^n)^{(m)}(i, j)}{2} \right] \frac{1}{\Delta t} \Delta_{-t} (T_e^{n+1})^{(m)}(i, j) \\
& = \frac{1}{2\Delta x^2} \left[\begin{aligned} & (k_e^{n+1})^{(m)}(i+1/2, j) \delta_x (T_e^{n+1})^{(m)}(i+1/2, j) \\ & - (k_e^{n+1})^{(m)}(i-1/2, j) \delta_x (T_e^{n+1})^{(m)}(i-1/2, j) \end{aligned} \right] \\
& + \frac{1}{2\Delta x^2} \left[\begin{aligned} & (k_e^n)^{(m)}(i+1/2, j) \delta_x (T_e^n)^{(m)}(i+1/2, j) \\ & - (k_e^n)^{(m)}(i-1/2, j) \delta_x (T_e^n)^{(m)}(i-1/2, j) \end{aligned} \right] \\
& + \frac{1}{2\Delta y^2} \left[\begin{aligned} & (k_e^{n+1})^{(m)}(i, j+1/2) \delta_y (T_e^{n+1})^{(m)}(i, j+1/2) \\ & - (k_e^{n+1})^{(m)}(i, j-1/2) \delta_y (T_e^{n+1})^{(m)}(i, j-1/2) \end{aligned} \right] \\
& + \frac{1}{2\Delta y^2} \left[\begin{aligned} & (k_e^n)^{(m)}(i, j+1/2) \delta_y (T_e^n)^{(m)}(i, j+1/2) \\ & - (k_e^n)^{(m)}(i, j-1/2) \delta_y (T_e^n)^{(m)}(i, j-1/2) \end{aligned} \right] \\
& - G^{(m)} \left[\begin{aligned} & \frac{(T_e^{n+1})^{(m)}(i, j) + (T_e^n)^{(m)}(i, j)}{2} \\ & - \frac{(T_l^{n+1})^{(m)}(i, j) + (T_l^n)^{(m)}(i, j)}{2} \end{aligned} \right] \\
& + Q^{n+1/2}(i, j),
\end{aligned} \tag{4.42}$$

$$\begin{aligned}
& C_l^{(m)} \frac{1}{\Delta t} \Delta_{-t} (T_l^{n+1})^{(m)}(i, j) \\
& = G^{(m)} \left[\begin{aligned} & \frac{(T_e^{n+1})^{(m)}(i, j) + (T_e^n)^{(m)}(i, j)}{2} \\ & - \frac{(T_l^{n+1})^{(m)}(i, j) + (T_l^n)^{(m)}(i, j)}{2} \end{aligned} \right] \\
& - (3\lambda^{(m)} + 2\mu^{(m)}) \alpha_T^{(m)} \left[\frac{\Delta_{-t} (\varepsilon_x^{n+1})^{(m)}(i, j)}{\Delta t} + \frac{\Delta_{-t} (\varepsilon_x^n)^{(m)}(i, j)}{\Delta t} \right]
\end{aligned} \tag{4.43}$$

Finally, the displacements, $u^{(m)}$ and $v^{(m)}$, are obtained using the Euler backward scheme for Eq. (4.30) as follows:

$$\frac{1}{\Delta t} \Delta_{-t} (u^{n+1})^{(m)}(i+1/2, j) = (v_1^{n+1})^{(m)}(i+1/2, j), \tag{4.44}$$

$$\frac{1}{\Delta t} \Delta_{-t} (v^{n+1})^{(m)}(i, j+1/2) = (v_2^{n+1})^{(m)}(i, j+1/2), \tag{4.45}$$

The boundary conditions, Eqs. (3.23)-(3.25), are discretized as follows:

$$\begin{aligned} (\sigma_x^{n+1})^{(1)}(1, j) &= 0, \quad (\sigma_x^{n+1})^{(2)}(N+1, j) = 0, \\ (\sigma_{xy}^{n+1})^{(1)}(1 + 1/2, j + 1/2) &= 0, \quad (\sigma_{xy}^{n+1})^{(2)}(2N + 1/2, j + 1/2) = 0, \\ 1 \leq j \leq M+1, \end{aligned} \tag{4.46}$$

$$\begin{aligned} (\sigma_y^{n+1})^{(m)}(i, 1) &= 0, \quad (\sigma_y^{n+1})^{(m)}(M+1, j) = 0, \\ (\sigma_{xy}^{n+1})^{(m)}(i + 1/2, 1 + 1/2) &= 0, \quad (\sigma_{xy}^{n+1})^{(m)}(i + 1/2, M + 1/2) = 0, \\ 1 \leq i \leq N+1, \end{aligned} \tag{4.47}$$

$$\begin{aligned} (T_e^{n+1})^{(1)}(1, j) &= (T_e^{n+1})^{(2)}(2, j), \\ (T_e^{n+1})^{(2)}(N+1, j) &= (T_e^{n+1})^{(2)}(N, j), \\ 1 \leq j \leq M+1, \end{aligned} \tag{4.48a}$$

$$\begin{aligned} (T_e^{n+1})^{(m)}(i, 1) &= (T_e^{n+1})^{(m)}(i, 2), \\ (T_e^{n+1})^{(m)}(i, M+1) &= (T_e^{n+1})^{(m)}(i, M), \\ 1 \leq i \leq N+1, \end{aligned} \tag{4.48b}$$

$$\begin{aligned} (T_l^{n+1})^{(1)}(1, j) &= (T_l^{n+1})^{(2)}(2, j), \\ (T_l^{n+1})^{(2)}(N+1, j) &= (T_l^{n+1})^{(2)}(N, j), \\ 1 \leq j \leq M+1, \end{aligned} \tag{4.49a}$$

$$\begin{aligned} (T_l^{n+1})^{(m)}(i, 1) &= (T_l^{n+1})^{(m)}(i, 2), \\ (T_l^{n+1})^{(m)}(i, M+1) &= (T_l^{n+1})^{(m)}(i, M), \\ 1 \leq i \leq N+1, \end{aligned} \tag{4.49b}$$

for any time level n and $m = 1, 2$.

For the perfect contact interfacial conditions, Eqs. (3.29)-(3.31) are employed and then discretized in this way. First, the interfacial condition for velocity components $v_1^{(m)}$ and $v_2^{(m)}$ based on Eq. (3.29) can be written as $v_1^{(1)} = v_1^{(2)}$ and $v_2^{(1)} = v_2^{(2)}$. Hence, we assume that

$$(v_1^{n+1})^{(1)}(N+1, j) = (v_1^{n+1})^{(2)}(1, j), \quad (4.50a)$$

$$(v_2^{n+1})^{(1)}(N+1, j) = (v_2^{n+1})^{(2)}(1, j). \quad (4.50b)$$

Second, Eq. (3.31) is discretized as follows:

$$\begin{aligned} & k_e^{(1)} \frac{(T_e^{n+1})^{(1)}(N+1, j) - (T_e^{n+1})^{(1)}(N, j)}{\Delta x} \\ &= k_e^{(2)} \frac{(T_e^{n+1})^{(2)}(2, j) - (T_e^{n+1})^{(2)}(1, j)}{\Delta x}, \end{aligned} \quad (4.51a)$$

$$(T_e^{n+1})^{(1)}(N+1, j) = (T_e^{n+1})^{(1)}(1, j). \quad (4.51b)$$

Third, coupled with Eqs. (3.16)-(3.18), Eq. (3.30) is discretized as

$$\begin{aligned} & (\lambda^{(1)} + 2\mu^{(1)})(\varepsilon_x^{n+1})^{(1)}(N+1, j) + \lambda^{(1)}(\varepsilon_y^{n+1})^{(1)}(N+1, j) \\ & - (3\lambda^{(1)} + 2\mu^{(1)})\alpha_T^{(1)}[(T_l^{n+1})^{(1)}(N+1, j) - T_0] \\ &= (\lambda^{(2)} + 2\mu^{(2)})(\varepsilon_x^{n+1})^{(2)}(1, j) + \lambda^{(2)}(\varepsilon_y^{n+1})^{(2)}(1, j) \\ & - (3\lambda^{(2)} + 2\mu^{(2)})\alpha_T^{(2)}[(T_l^{n+1})^{(2)}(1, j) - T_0] \end{aligned} \quad (4.52a)$$

$$\mu^{(1)}(\gamma_{xy}^{n+1})^{(1)}(N+1, j) = \mu^{(2)}(\gamma_{xy}^{n+1})^{(2)}(1, j), \quad (4.52b)$$

where $(\varepsilon_x^{n+1})^{(1)}(N+1, j)$, $(\varepsilon_x^{n+1})^{(2)}(1, j)$, $(\varepsilon_y^{n+1})^{(1)}(N+1, j)$, $(\varepsilon_y^{n+1})^{(2)}(1, j)$, $(\gamma_{xy}^{n+1})^{(1)}(N+1, j)$,

and $(\gamma_{xy}^{n+1})^{(2)}(1, j)$ are obtained based on Eqs. (4.33)-(4.37) as follows:

$$\begin{aligned} (\varepsilon_x^{n+1})^{(1)}(N+1, j) &= \frac{(v_1^{n+1})^{(1)}(N+1, j) - (v_1^{n+1})^{(1)}(N, j)}{\Delta x / 2} \Delta t \\ &+ (\varepsilon_x^n)^{(1)}(N+1, j), \end{aligned} \quad (4.53a)$$

$$\begin{aligned} (\varepsilon_x^{n+1})^{(2)}(1, j) &= \frac{(v_1^{n+1})^{(2)}(2, j) - (v_1^{n+1})^{(2)}(1, j)}{\Delta x / 2} \Delta t \\ &+ (\varepsilon_x^n)^{(2)}(1, j), \end{aligned} \quad (4.53b)$$

$$\begin{aligned} (\varepsilon_y^{n+1})^{(1)}(N+1, j) &= \frac{(v_2)^{(1)}(N+1, j) - (v_2)^{(1)}(N+1, j-1)}{\Delta y} \Delta t \\ &+ (\varepsilon_y^n)^{(1)}(N+1, j), \end{aligned} \quad (4.54a)$$

$$\begin{aligned} (\varepsilon_y^{n+1})^{(2)}(1, j) &= \frac{(v_2)^{(2)}(1, j) - (v_2)^{(2)}(1, j-1)}{\Delta y} \Delta t \\ &+ (\varepsilon_y^n)^{(2)}(1, j), \end{aligned} \quad (4.54b)$$

$$\begin{aligned} (\gamma_{xy}^{n+1})^{(1)}(N+1, j) &= \frac{\Delta t}{\Delta y} \left[(v_1^{n+1})^{(1)}(N+1, j+1) - (v_1^{n+1})^{(1)}(N+1, j) \right] \\ &+ \frac{\Delta t}{\Delta x} \left[(v_2^{n+1})^{(1)}(N+1, j) - (v_2^{n+1})^{(1)}(N, j) \right] \\ &+ (\gamma_{xy}^n)^{(1)}(N+1, j), \end{aligned} \quad (4.55a)$$

$$\begin{aligned} (\gamma_{xy}^{n+1})^{(2)}(1, j) &= \frac{\Delta t}{\Delta y} \left[(v_1^{n+1})^{(2)}(1, j+1) - (v_1^{n+1})^{(2)}(1, j) \right] \\ &+ \frac{\Delta t}{\Delta x} \left[(v_2^{n+1})^{(2)}(2, j) - (v_2^{n+1})^{(2)}(1, j) \right] \\ &+ (\gamma_{xy}^n)^{(2)}(1, j), \end{aligned} \quad (4.55b)$$

where $1 \leq j \leq M + 1$ and $m = 1, 2$.

For the imperfect contact interfacial conditions, Eqs. (3.32)-(3.34) and (3.36) are employed and then discretized in this way. First the interfacial conditions for electron

temperature based on Eq. (3.32) and for velocity based on Eq. (3.34) are discretized as follows:

$$\begin{aligned} k_e^{(1)} & \frac{(T_e^{n+1})^{(1)}(N+1, j) - (T_e^{n+1})^{(1)}(N, j)}{\Delta x} \\ & = k_e^{(2)} \frac{(T_e^{n+1})^{(2)}(2, j) - (T_e^{n+1})^{(2)}(1, j)}{\Delta x}, \end{aligned} \quad (4.56a)$$

$$\begin{aligned} & -k_e^{(1)} \frac{(T_e^{n+1})^{(1)}(N+1, j) - (T_e^{n+1})^{(1)}(N, j)}{\Delta x} \\ & = \sigma \left\{ [(T_e^{n+1})^{(1)}(N+1, j)]^4 - [(T_e^{n+1})^{(2)}(1, j)]^4 \right\}, \end{aligned} \quad (4.56b)$$

$$\mu^{(1)}(v_1^{n+1})^{(1)}(N+1, j) = \mu^{(2)}(v_1^{n+1})^{(2)}(1, j), \quad (4.57a)$$

$$\mu^{(1)}(v_2^{n+1})^{(1)}(N+1, j) = \mu^{(2)}(v_2^{n+1})^{(2)}(1, j). \quad (4.57b)$$

The discrete schemes for strains at this imperfect contact interface are the same as those at perfect contact interface. From Eqs. (3.16) and (3.36), we obtain a discrete interfacial condition for σ_x :

$$\begin{aligned} & \frac{\mu^{(1)}}{E^{(1)}} \left\{ (\lambda^{(1)} + 2\mu^{(1)}) (\varepsilon_x^{n+1})^{(1)}(N+1, j) + \lambda^{(1)} (\varepsilon_y^{n+1})^{(1)}(N+1, j) \right. \\ & \left. - (3\lambda^{(1)} + 2\mu^{(1)}) \alpha_T^{(1)} [(T_l^{n+1})^{(1)}(N+1, j) - T_0] \right\} \\ & = \frac{\mu^{(2)}}{E^{(2)}} \left\{ (\lambda^{(2)} + 2\mu^{(2)}) (\varepsilon_x^{n+1})^{(2)}(1, j) + \lambda^{(2)} (\varepsilon_y^{n+1})^{(2)}(1, j) \right. \\ & \left. - (3\lambda^{(2)} + 2\mu^{(2)}) \alpha_T^{(2)} [(T_l^{n+1})^{(2)}(1, j) - T_0] \right\} \end{aligned} \quad (4.58)$$

Furthermore, from Eqs. (3.3) and (3.18) we have

$$\mu^{(1)}(\gamma_{xy}^{n+1})^{(1)}(N+1, j) = \mu^{(2)}(\gamma_{xy}^{n+1})^{(2)}(1, j). \quad (4.59)$$

where $1 \leq j \leq M+1$.

For both cases, the initial conditions are assumed to be

$$(u^0)^{(m)}(i+1/2, j) = 0, \quad (v^0)^{(m)}(i, j+1/2) = 0, \quad (4.60)$$

$$(v_1^0)^{(m)}(i+1/2, j) = 0, \quad (v_1^0)^{(m)}(i, j+1/2) = 0, \quad (4.61)$$

$$(T_e^0)^{(m)}(i, j) = 0, \quad (T_l^0)^{(m)}(i, j) = 0, \quad (4.62)$$

$$1 \leq i \leq N+1, \quad 1 \leq j \leq M+1, \quad m = 1, 2.$$

For the perfect contact interfacial conditions, the interfacial values are calculated in this order. We first obtain updated $(T_e^{n+1})^{(1)}(N+1, j)$ and $(T_e^{n+1})^{(2)}(1, j)$ from Eq. (4.51) and substitute them into Eq. (4.43) to obtain updated $(T_i^{n+1})^{(1)}(N+1, j)$ and $(T_l^{n+1})^{(2)}(1, j)$; we then substitute Eqs. (4.50), (4.53), and (4.54) into Eq. (4.52a) to obtain updated $(v_1^{n+1})^{(1)}(N+1, j)$ and $(v_1^{n+1})^{(2)}(1, j)$; we further substitute Eqs. (4.50) and (4.55) into Eq. (4.52b) to obtain updated $(v_2^{n+1})^{(1)}(N+1, j)$ and $(v_2^{n+1})^{(2)}(1, j)$; and from the above known variables on the interface nodes we can obtain $(\varepsilon_x^{n+1})^{(m)}$, $(\varepsilon_y^{n+1})^{(m)}$, $(\gamma_{xy}^{n+1})^{(m)}$, $(\sigma_x^{n+1})^{(m)}$, $(\sigma_y^{n+1})^{(m)}$, $(\sigma_{xy}^{n+1})^{(m)}$, $(u^{n+1})^{(m)}$ and $(v^{n+1})^{(m)}$ on the interface nodes using Eqs. (4.53)-(4.55), (4.39)-(4.41), and Eqs. (4.44) and (4.45), respectively.

For the imperfect contact interfacial conditions, the interfacial values are calculated in this order. From Eq. (4.56b), $(T_e^{n+1})^{(1)}(N+1, j)$ is solved iteratively:

$$\begin{aligned} & \left[(T_e^{n+1})^{(1)}(N+1, j) \right]^{new} = \\ & - \frac{\sigma \cdot \Delta x}{k_e^{(1)}} \left\{ \left\{ \left[(T_e^{n+1})^{(1)}(N+1, j) \right]^{old} \right\}^4 \right\} + \left[(T_e^{n+1})^{(1)}(N, j) \right]^{old}, \end{aligned} \quad (4.65)$$

and then $(T_e^{n+1})^{(2)}(1, j)$ is solved based on Eq. (4.56a):

$$\begin{aligned} & \left[(T_e^{n+1})^{(2)}(1, j) \right]^{new} \\ &= \left[(T_e^{n+1})^{(2)}(2, j) \right]^{old} - \frac{k_e^{(1)}}{k_e^{(2)}} \left\{ \left[(T_e^{n+1})^{(1)}(N+1, j) \right]^{old} - \left[(T_e^{n+1})^{(1)}(N, j) \right]^{old} \right\}. \end{aligned} \quad (4.66)$$

Once updated $(T_e^{n+1})^{(1)}(N+1, j)$ and $(T_e^{n+1})^{(2)}(1, j)$ are obtained, we substitute them into Eq. (4.43) to obtain updated $(T_l^{n+1})^{(1)}(N+1, j)$ and $(T_l^{n+1})^{(2)}(1, j)$. We then substitute Eqs. (4.53), (4.54) and (4.57) into Eq. (4.58) to obtain updated $(v_1^{n+1})^{(1)}(N+1, j)$ and $(v_1^{n+1})^{(2)}(1, j)$, and substitute Eqs. (4.55) and (4.57) into Eq. (4.59) to obtain updated $(v_2^{n+1})^{(1)}(N+1, j)$ and $(v_2^{n+1})^{(2)}(1, j)$. Finally, from the above known interfacial values, we obtain updated $(\varepsilon_x^{n+1})^{(m)}$, $(\varepsilon_y^{n+1})^{(m)}$, $(\gamma_{xy}^{n+1})^{(m)}$, $(\sigma_x^{n+1})^{(m)}$, $(\sigma_y^{n+1})^{(m)}$, $(\sigma_{xy}^{n+1})^{(m)}$, $(u^{n+1})^{(m)}$ and obtain updated $(\varepsilon_x^{n+1})^{(m)}$, $(\varepsilon_y^{n+1})^{(m)}$, $(\gamma_{xy}^{n+1})^{(m)}$, $(\sigma_x^{n+1})^{(m)}$, $(\sigma_y^{n+1})^{(m)}$, $(\sigma_{xy}^{n+1})^{(m)}$, $(u^{n+1})^{(m)}$ and $(v^{n+1})^{(m)}$ at the interface.

It can be seen that the truncation error of Eqs. (4.34) and (4.35) is $O(\Delta t + \Delta x^2 + \Delta y^2)$ and the truncation error of Eqs. (4.42) and (4.43) is $O(\Delta t^2 + \Delta x^2 + \Delta y^2)$. It should be pointed out that Eqs. (4.34) and (4.35) are nonlinear since the terms $\delta_x [(T_e^2)^{n+1}]^{(m)}(i+1/2, j)$ and $\delta_y [(T_e^2)^{n+1}]^{(m)}(i, j+1/2)$ are nonlinear. Also, it can be seen that Eqs. (4.41) and (4.56b) are nonlinear. Therefore, the above scheme must be solved iteratively. An algorithm for solving the above scheme at time level $n+1$ can be described as follows:

Step 1. Guess $(\varepsilon_x^{n+1})^{(m)}$, $(\varepsilon_y^{n+1})^{(m)}$ and $(\gamma_{xy}^{n+1})^{(m)}$, solve Eqs. (4.42) and (4.43) iteratively for $(T_e^{n+1})^{(m)}$ and $(T_l^{n+1})^{(m)}$.

Step 2. Solve for $(\sigma_x^{n+1})^{(m)}$, $(\sigma_y^{n+1})^{(m)}$ and $(\sigma_{xy}^{n+1})^{(m)}$ using Eqs. (4.39)-(4.41).

Step 3. Solve for $(v_1^{n+1})^{(m)}$ and $(v_2^{n+1})^{(m)}$ using Eqs. (4.34) and (4.35).

Step 4. Update $(\varepsilon_x^{n+1})^{(m)}$, $(\varepsilon_y^{n+1})^{(m)}$ and $(\gamma_{xy}^{n+1})^{(m)}$ using Eqs. (4.36)-(4.38).

Repeat the above steps until a convergent solution is obtained based on the following criteria:

$$\max_{i,j} \left| \left[(T_e^{n+1})^{(1)}(i,j) \right]^{new} - \left[(T_e^{n+1})^{(1)}(i,j) \right]^{old} \right| < \varepsilon_1,$$

$$\max_{i,j} \left| \left[(\varepsilon_x^{n+1})^{(1)}(i,j) \right]^{new} - \left[(\varepsilon_x^{n+1})^{(1)}(i,j) \right]^{old} \right| < \varepsilon_2,$$

$$\max_{i,j} \left| \left[(\varepsilon_y^{n+1})^{(1)}(i,j) \right]^{new} - \left[(\varepsilon_y^{n+1})^{(1)}(i,j) \right]^{old} \right| < \varepsilon_2,$$

$$\max_{i,j} \left| \left[(\gamma_{xy}^{n+1})^{(1)}(i,j) \right]^{new} - \left[(\gamma_{xy}^{n+1})^{(1)}(i,j) \right]^{old} \right| < \varepsilon_2.$$

CHAPTER FIVE

NUMERICAL RESULTS AND DISCUSSIONS

In this chapter, we are going to test our numerical method by using two examples.

In example 1, we apply our numerical method for single-layered thin film model to investigate the thermal deformation in a microscale gold thin film exposed to an ultrashort laser pulse heating. In example 2, we apply our numerical method for double-layered thin film model to investigate the thermal deformation in a double-layered microscale thin film consisting of a gold layer padding on a chromium layer exposed to an ultrashort laser pulse heating. At interface of double-layered thin film we also consider two cases: perfectly thermal contact and imperfectly thermal contact.

5.1 Description of the Examples

5.1.1 Example 1: Single-Layered Gold Thin Film

In the first example, the thickness and length of the thin film is $0.1\mu m \times 1\mu m$ as shown in Fig. 3.1. The thermophysical properties for gold are listed in Table 5.1. The two constants in the artificial viscosity are set to be $\omega_L = 0.1$ and $\omega_Q = 2.0$, and the characteristic dimension $\Delta\bar{x} = \Delta x$ is employed. Three meshes of 80×40 , 160×80 , 300×150 were chosen in order to test the convergence of the scheme. The time

increment is 0.005ps. The laser fluence was chosen to be $J = 500 J/m^2$. The initial temperature T_0 is 300 K [Chen 2002a].

Table 5.1 Thermophysical properties for gold [Tzou 2002, Chen 2002a, Kaye 1973, Touloukian 1970a, Touloukian 1970b].

Properties	Unit	Value
ρ	kg/m^3	19,300
Λ	$Jm^{-3}K^{-2}$	70
K	Pa	217×10^9
μ	Pa	27×10^9
α_T	K^{-1}	14.2×10^{-6}
$C_{e\delta}$	$J/(m^3K)$	2.1×10^4
C_l	$J/(m^3K)$	2.5×10^6
G	$W/(m^3K)$	2.6×10^{16}
K_e	$W/(mK)$	315
R		0.93
t_p	s	0.1×10^{-12}
x_s	m	15.3×10^{-9}
y_s	m	1.0×10^{-6}
J	J/m^2	500
T_0	K	300

5.1.2 Example 2: Gold Layer Padding on Chromium Layer Thin Film

In the second example, the thickness and length of each thin film is $0.1\mu m \times 1\mu m$ as shown in Fig. 3.2. The thermophysical properties for gold and chromium are listed in Table 5.2. Three meshes of 80×40 , 160×80 , 300×150 were chosen in order to test the convergence of the scheme. The time increment was chosen to be 0.005ps and T_0 was set to be 300K. The values of those parameters for laser were chosen to be $R = 0.93$, $t_p = 0.1 \times 10^{-12} s$, $x_s = 15.3 \times 10^{-9} m$, and $y_s = 1.0 \times 10^{-9} m$ [Chen 2002a]. Three different values of laser fluences ($J = 500 Jm^{-2}$, $1000 Jm^{-2}$ and $2000 Jm^{-2}$) were chosen to study the hot-electron balst force. The convergence criteria were chosen to be $\varepsilon_1 = 10^{-8}$ for temperature and $\varepsilon_2 = 10^{-16}$ for thermal deformation, respectively.

Table 5.2 Thermophysical properties for gold and Chromium [Tzou 2002, Chen 2002a, Kaye 1973, Touloukian 1970a, Touloukian 1970b].

Properties	Unit	Gold	Chromium
ρ	kg/m^3	19,300	7190
E	Pa	77.97×10^9	279.45×10^9
Λ	$Jm^{-3}K^{-2}$	70	193.3
λ	Pa	199.0×10^9	83.3×10^9
μ	Pa	27.0×10^9	115.0×10^9
α_T	K^{-1}	14.2×10^{-6}	4.9×10^{-6}
C_{e0}	$J/(m^3 K)$	2.1×10^4	5.8×10^4
C_l	$J/(m^3 K)$	2.5×10^6	3.3×10^6
G	$W/(m^3 K)$	2.6×10^{16}	42.0×10^{16}
K_e	$W/(mK)$	315	94

5.2 Numerical Results and Discussions

5.2.1 Figures and Discussions of Example 1

Fig. 5.1 shows the change in electron temperature $\left[\frac{\Delta T_e}{(\Delta T_e)_{\max}} \right]$ at $x = 0 \mu m$

and $y = 0 \mu m$. The maximum temperature rise of T_e (i.e. $(\Delta T_e)_{\max}$) is about 3791 K, which is very close to that obtained by Qiu and Tien [Qiu 1994].

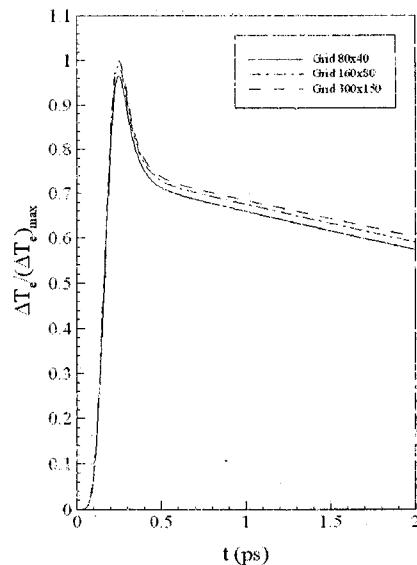


Fig. 5.1 Change in electron temperature at $x = 0$ and $y = 0$ versus time for various meshes (80×40 , 160×80 , and 300×150).

Fig. 5.2 shows the displacement (u) at $x = \frac{1}{2}\Delta x$, and $y = \Delta y$ versus time. It can be

seen from both figures that the solutions are convergent as the mesh is getting finer.

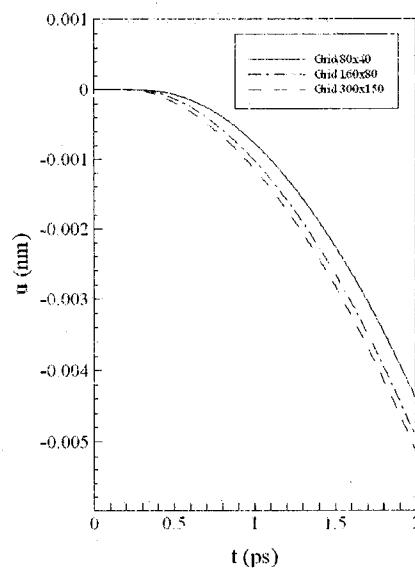


Fig. 5.2 Displacement (u) at $x = \frac{1}{2}\Delta x$ and $y = \Delta y$ versus time for various meshes (80×40 , 160×80 , and 300×150).

Fig. 5.3 shows comparison of the present method with Chen et al.'s method in [Chen 2002a] with regard to the normal stress (σ_x) at $y = \Delta y$ at $t = 10 \text{ ps}$. There is no non-physical oscillation in present method but it still exists in Chen et al.'s method.

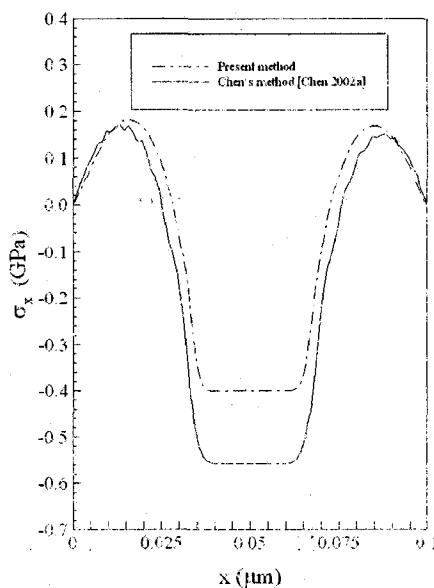


Fig. 5.3 Comparison of the present method with Chen et al.'s method in [Chen 2002a] with regard to the normal stress (σ_x) at $y = \Delta y$ at $t = 10 \text{ ps}$.

Fig. 5.4-5.9 were plotted based on the results obtained in a mesh of 160×80 and $\Delta t = 0.005 \text{ ps}$. Fig. 5.4 and 5.5 show electron temperature and lattice temperature profiles, respectively, at different times (a) $t = 0.25 \text{ ps}$, (b) $t = 0.5 \text{ ps}$, (c) $t = 1 \text{ ps}$, (d) $t = 10 \text{ ps}$ and (e) $t = 20 \text{ ps}$. It can be seen that the electron temperature rises to its maximum rapidly at the beginning and then decreases to a uniform distribution at $t = 20 \text{ ps}$ while the lattice temperature rises gradually with time to a uniform temperature distribution at $t = 20 \text{ ps}$. This change is mainly due to the effect of heat diffusion in the electron gas and the constant heat flow from hot electrons to metal lattices. The uniform electron and lattice temperatures are probably due to an increased rate of collision between electrons and

phonons in the gold layer as boundary is thermally insulated. Meanwhile, a negative temperature gradient in the electron gas ($\partial T_e / \partial x < 0$), clearly shown in Fig. 5.4, results in a negative blasting force, $2T_e(\partial T_e / \partial x) < 0$.

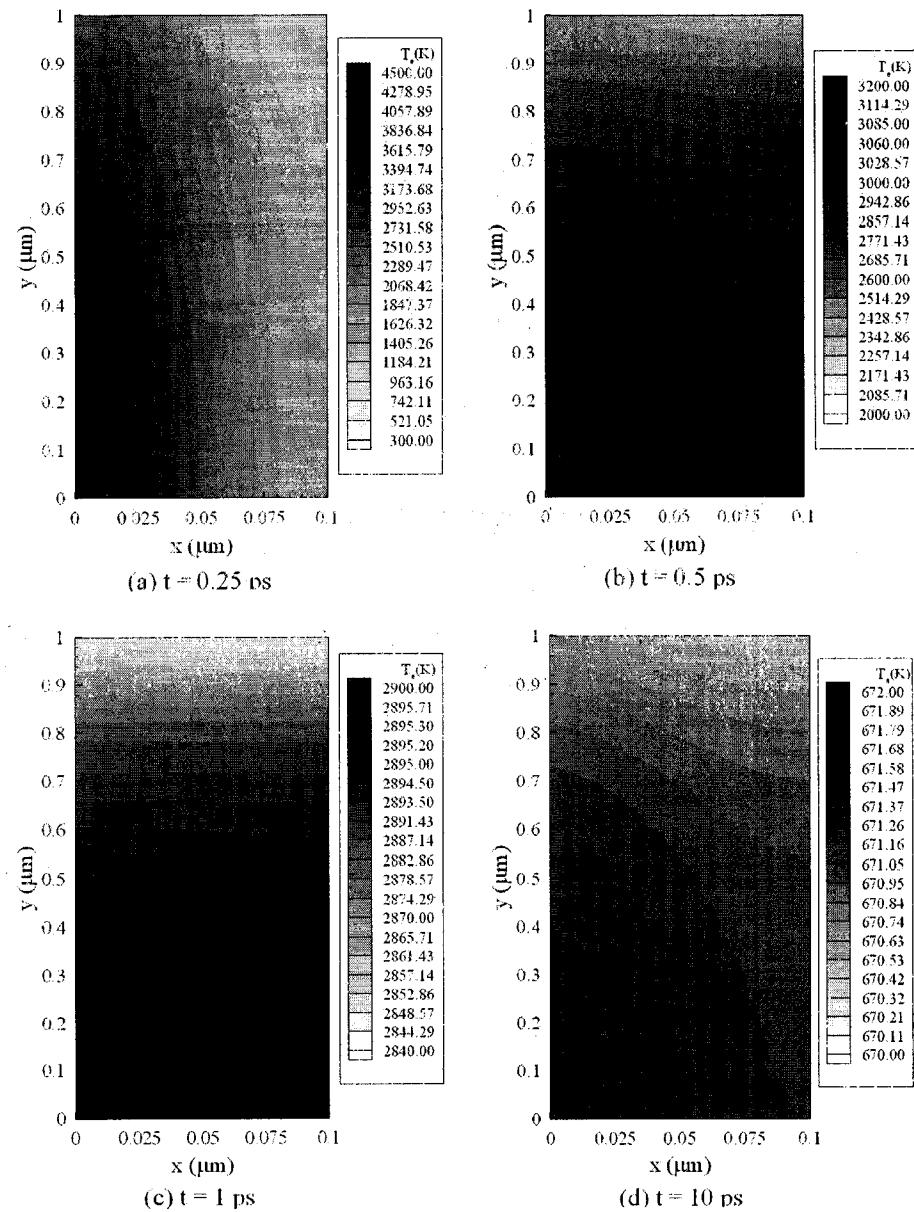


Fig. 5.4 Electron temperature (T_e) profiles at different times.

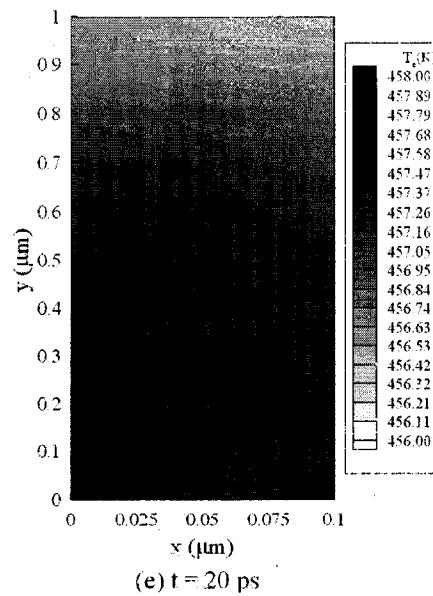


Fig. 5.4 Continued.

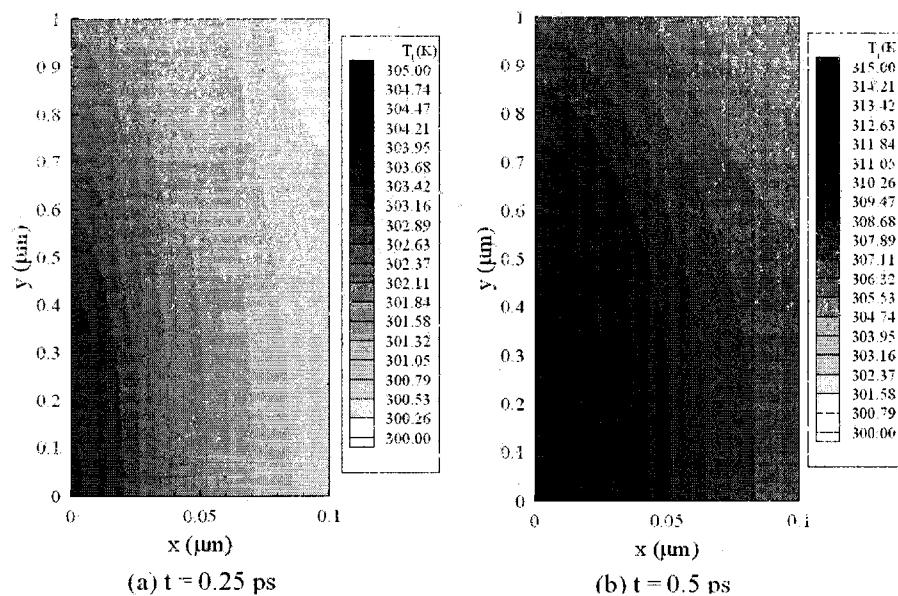


Fig. 5.5 Lattice temperature (T_l) profiles at different times.

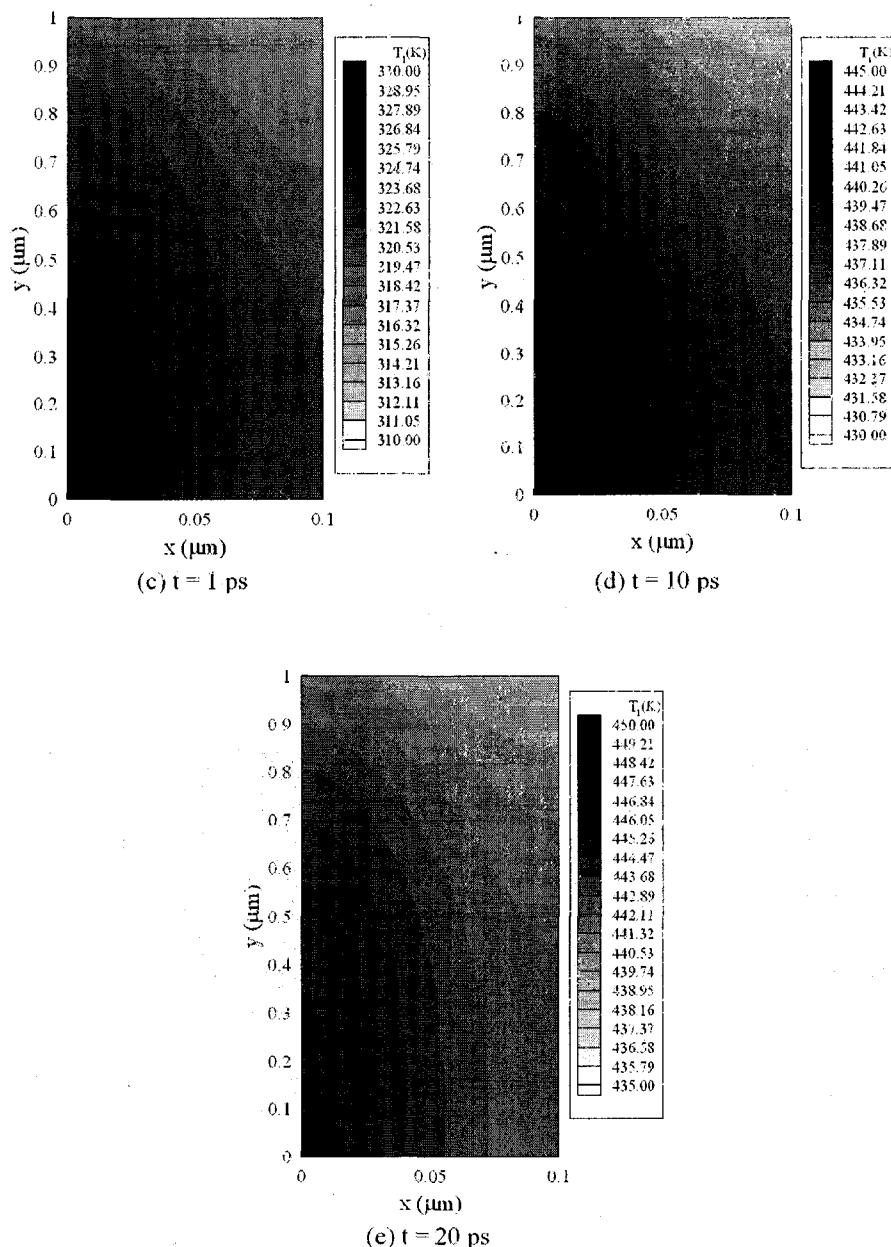


Fig. 5.5 Continued.

Fig. 5.6 shows displacement u (thickness direction) profiles at different times (a) $t = 1 \text{ ps}$, (b) $t = 5 \text{ ps}$, (c) $t = 10 \text{ ps}$, (d) $t = 15 \text{ ps}$, and (e) $t = 20 \text{ ps}$. Fig. 5.7 shows displacement v (length direction) profiles at different times (a) $t = 1 \text{ ps}$, (b) $t = 5 \text{ ps}$, (c) $t = 10 \text{ ps}$, (d) $t = 15 \text{ ps}$, and (e) $t = 20 \text{ ps}$. From the figures, we can see that the displacements are mainly along the direction of thickness, which reveals the fact that

laser heating of microscale thin film along the thickness direction produces the displacement of thin film along the corresponding direction.

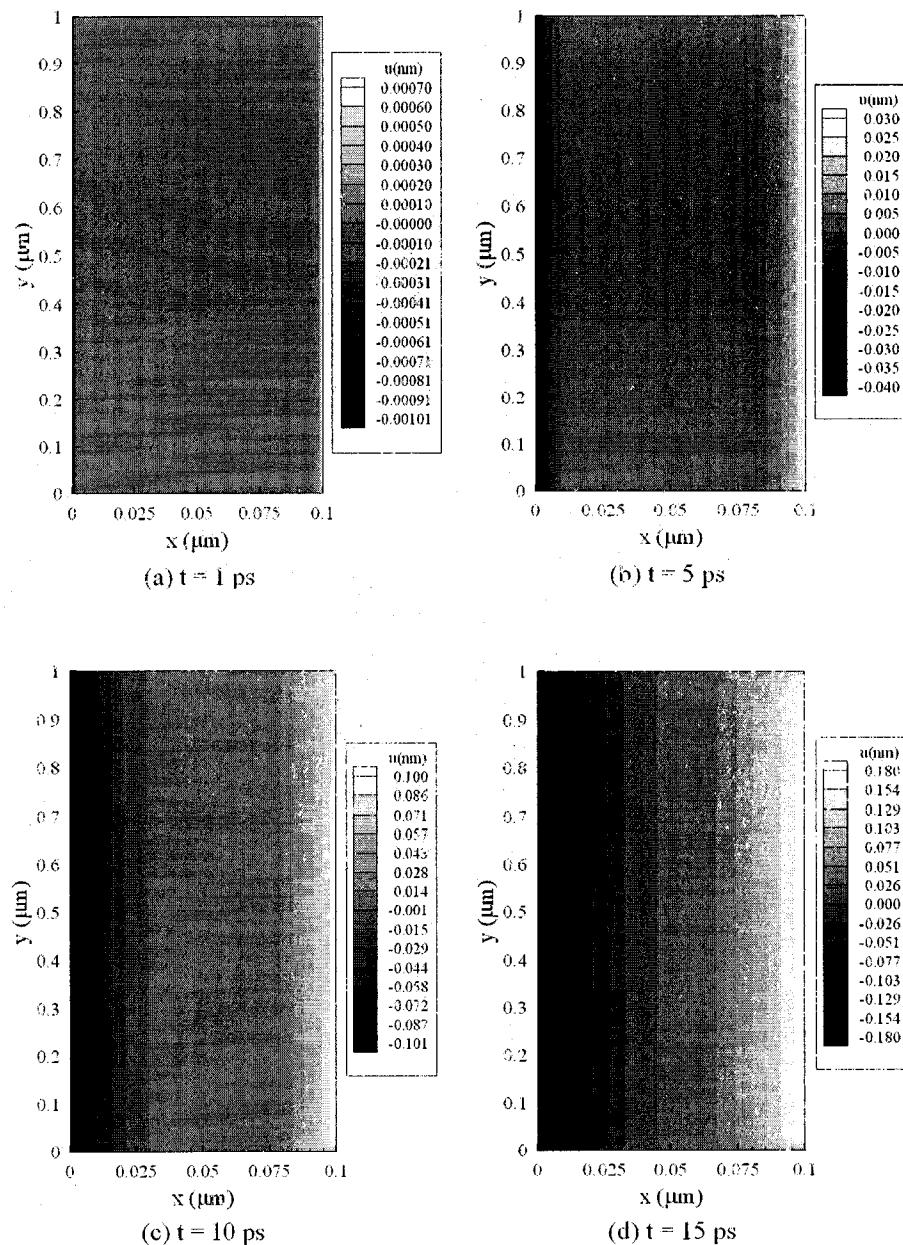


Fig. 5.6 Displacement (u) profiles at different times.

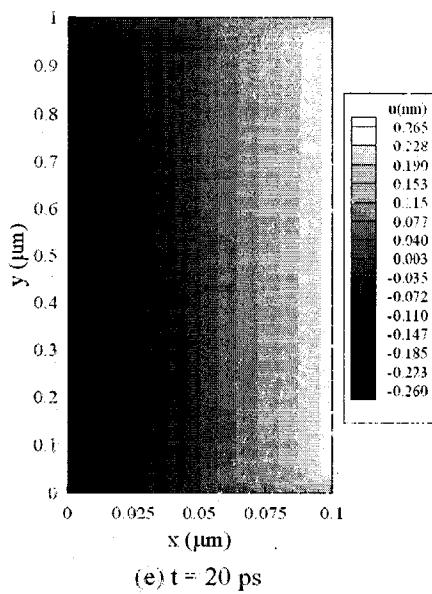


Fig. 5.6 Continued.

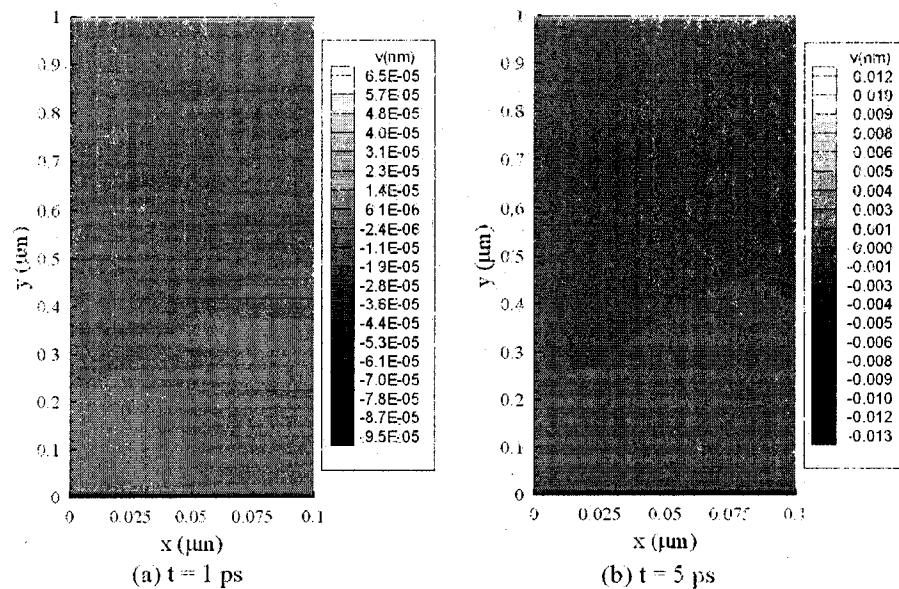


Fig. 5.7 Displacement (v) profiles at different times.

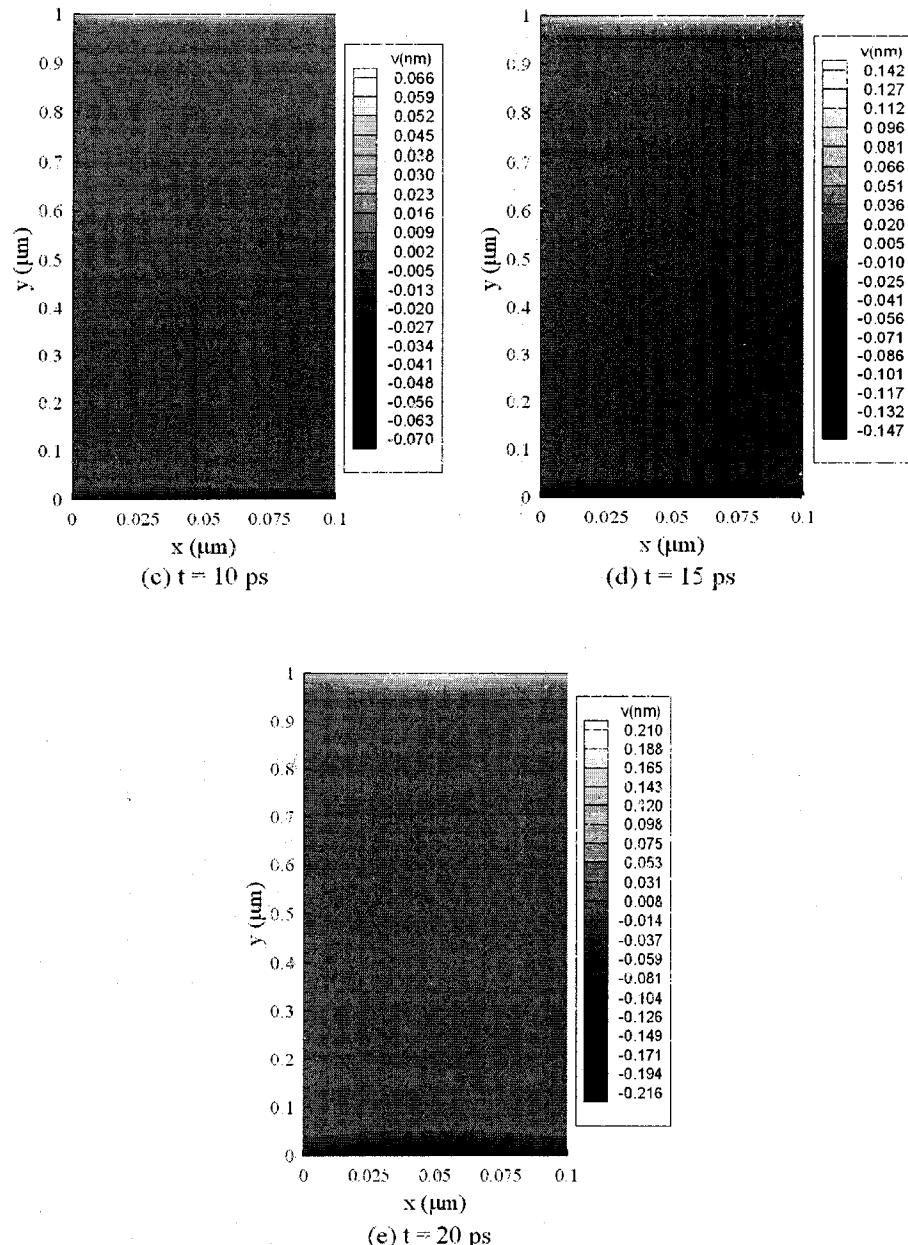


Fig. 5.7 Continued.

Fig. 5.8 shows normal stress σ_x (thickness direction) profiles at different times (a) $t = 1 \text{ ps}$, (b) $t = 5 \text{ ps}$, (c) $t = 10 \text{ ps}$, (d) $t = 15 \text{ ps}$, and (e) $t = 20 \text{ ps}$. Fig. 5.9 shows normal stress σ_y (length direction) profiles at different times (a) $t = 1 \text{ ps}$, (b) $t = 5 \text{ ps}$, (c) $t = 10 \text{ ps}$, (d) $t = 15 \text{ ps}$, and (e) $t = 20 \text{ ps}$. The negative blasting forces produce

compressive stresses at first 5 ps, then as the wave of stress propagates along the thickness direction, severe stress alteration appears in the gold layer. Since metal, including gold, is weaker in general when resisting tension, the tensile region of film would be more detrimental. For this reason, it's very hard for gold thin film to resist the damage brought by ultrafast laser heating.

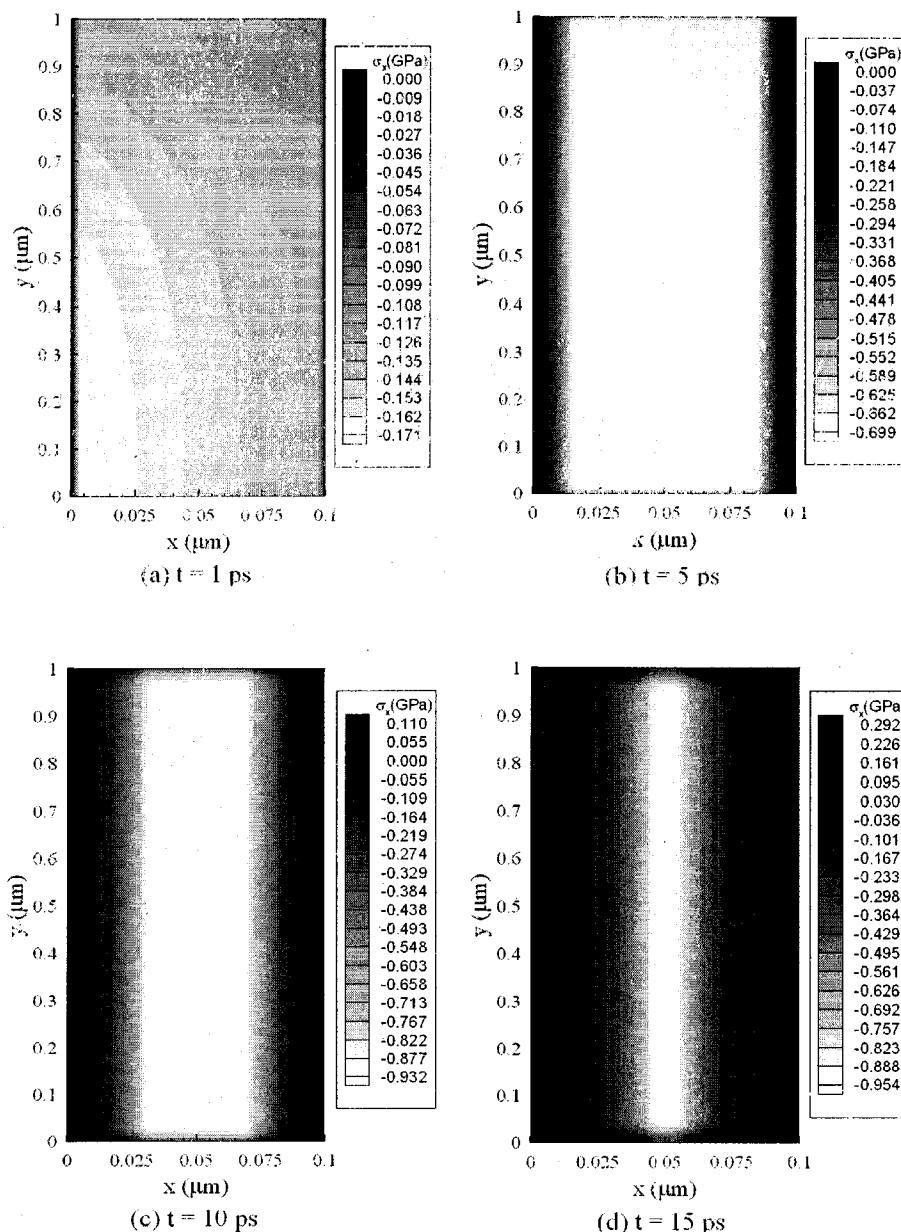


Fig. 5.8 Normal stress (σ_x) profiles at different times.

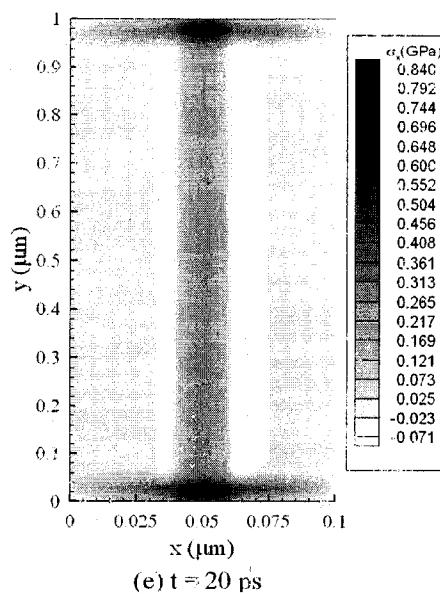


Fig. 5.8 Continued.

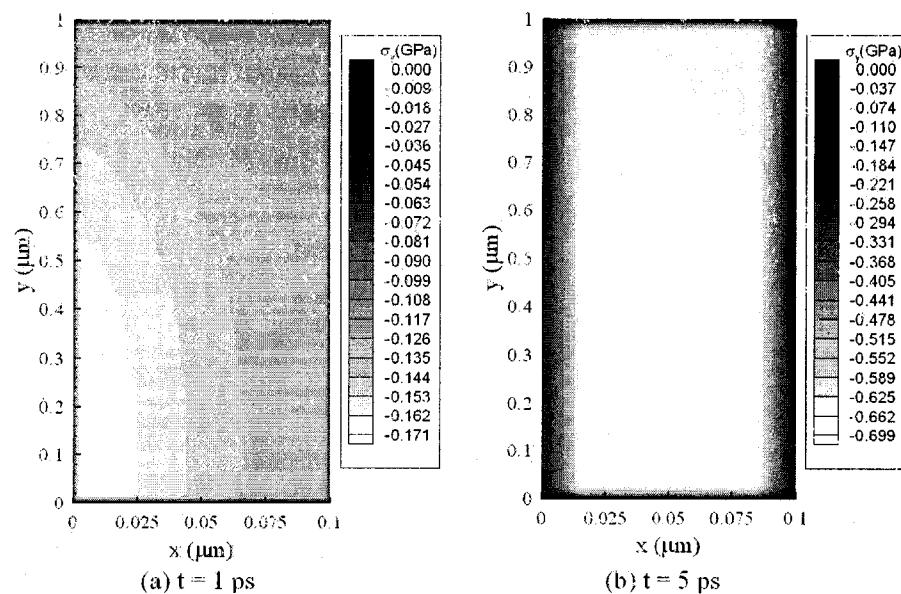


Fig. 5.9 Normal stress (σ_y) profiles at different times.

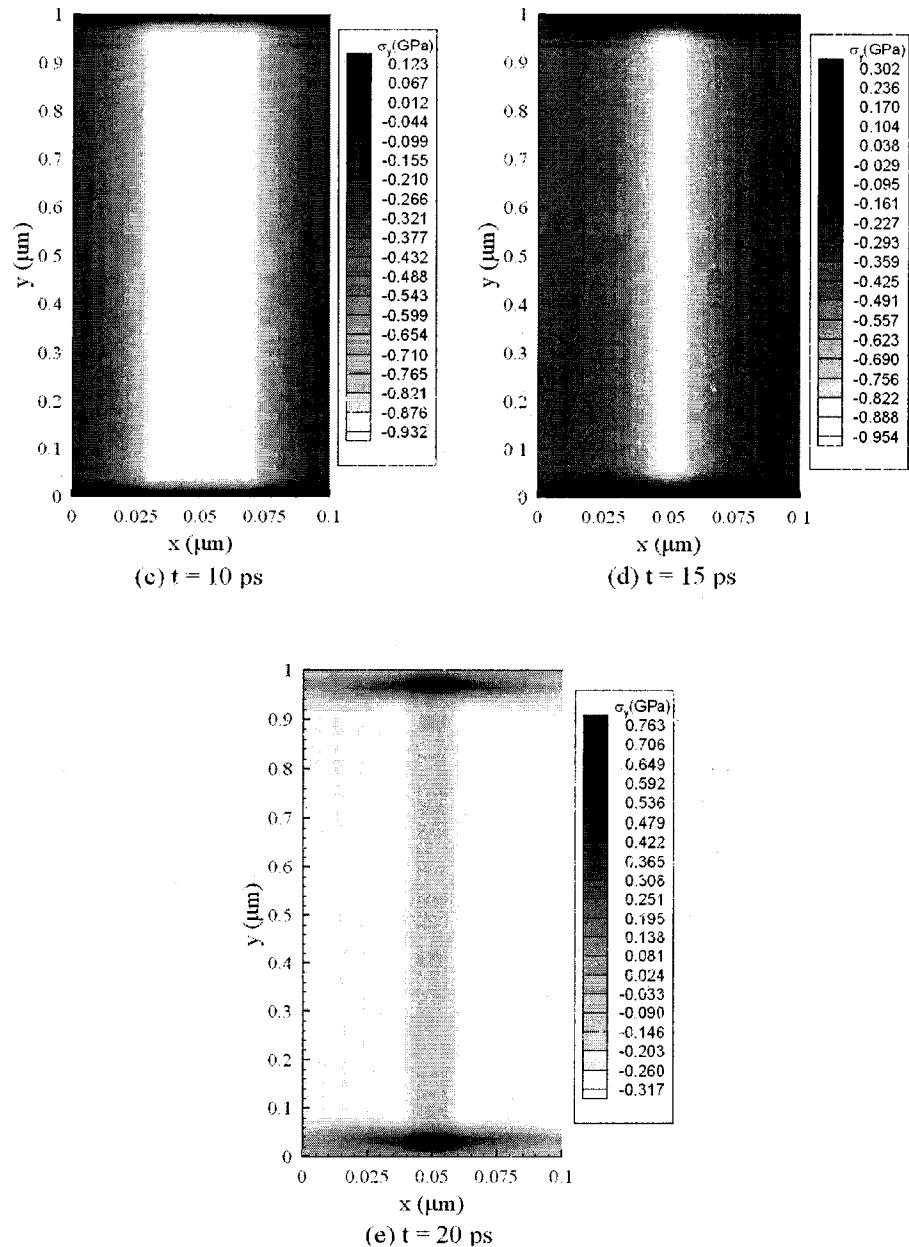


Fig. 5.9 Continued.

5.2.2 Figures and Explanations of Example 2

Case 1: Perfectly thermal contact at interface

Fig. 5.10 shows the change in electron temperature $\left[\frac{\Delta T_e}{(\Delta T_e)_{\max}} \right]$ at $x = 0\mu m$ and $y = 0\mu m$ with laser fluence $J = 500Jm^{-2}$. The maximum temperature rise of T_e (i.e. $(\Delta T_e)_{\max}$) is about $3790 K$, which is very close to that obtained by Qiu and Tien [Qiu 1994].

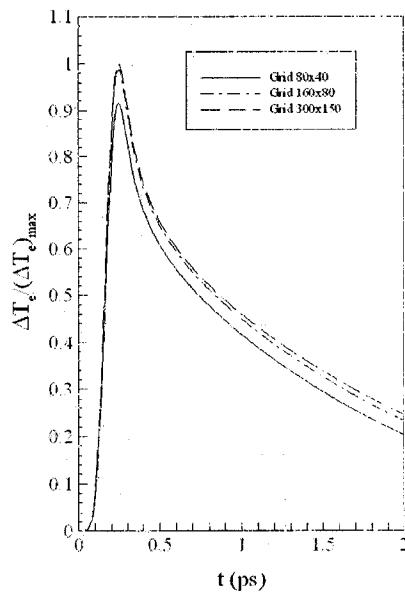


Fig. 5.10 Change in electron temperature at $x = 0\mu m$ and $y = 0\mu m$ versus time for various meshes (80×40 , 160×80 , 300×150) with laser fluence $J = 500Jm^{-2}$.

Fig. 5.11 shows the displacement (u) at $x = \frac{1}{2}\Delta x$, and $y = \Delta y$ versus time. It can

be seen from both figures that mesh size had no significant effect on the solutions, and hence this method is only weakly dependent on the grid.

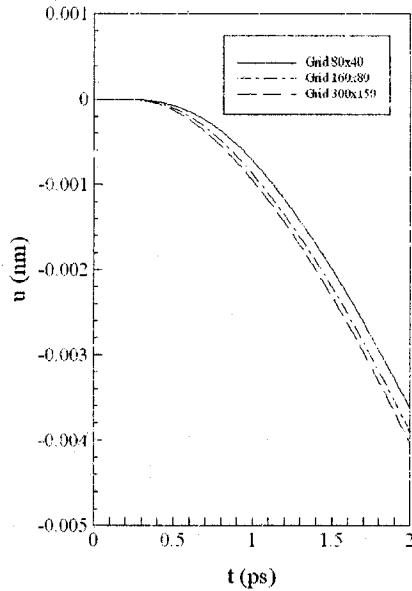


Fig. 5.11 Displacement (u) at $x = \frac{1}{2}\Delta x$ and $y = \Delta y$ with laser fluence $J = 500 Jm^{-2}$ versus time for various meshes (80×40 , 160×80 , 300×150)

Figs. 5.12-5.17 were plotted based on the results obtained in a mesh of 160×80 and $\Delta t = 0.005 ps$. Figs. 5.12 and 5.13 show, respectively, the comparison of electron temperature and lattice temperature along x at $y = 0 \mu m$ with three different laser fluences ($J = 500 Jm^{-2}$, $1000 Jm^{-2}$ and $2000 Jm^{-2}$) at different times (a) $t = 0.25 ps$, (b) $t = 0.5 ps$, (c) $t = 1 ps$, (d) $t = 10 ps$ and (e) $t = 20 ps$. Electron temperature decays much more slowly in the gold film ($0 < x < 0.1 \mu m$) than in the chromium film $0.1 < x < 0.2 \mu m$. In transition from the gold layer to chromium layer, an abrupt increase of the temperature gradient ($\partial T_e / \partial x$) is present at the interface. Electron temperature decreases with time in the gold layer due to the effect of heat diffusion in the electron gas and the constant heat flow from hot electrons to metal lattices (phonon-electron interactions). In the chromium layer, however, electron temperatures established at later times (0.5 , $1 ps$) may become

higher than the early-time temperature (0.25 ps) due to the combined effect of continuous heat diffusion and phonon-electron interactions. The lattice temperature increases with time, in both gold and chromium films, due to constant heating of acoustic phonons by electrons.

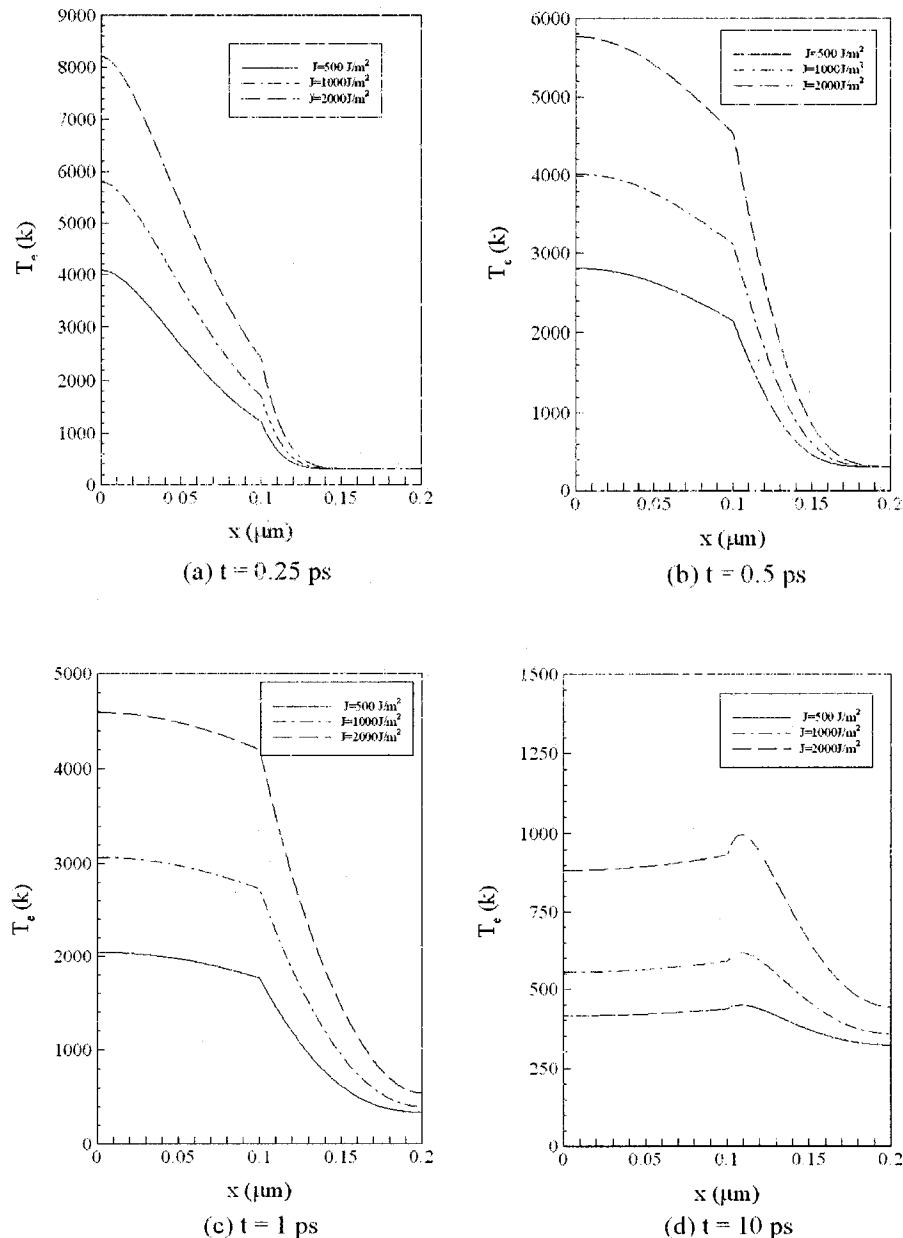


Fig. 5.12 Comparison of electron temperature at $y = 0 \mu\text{m}$ at different times with three different laser fluences.

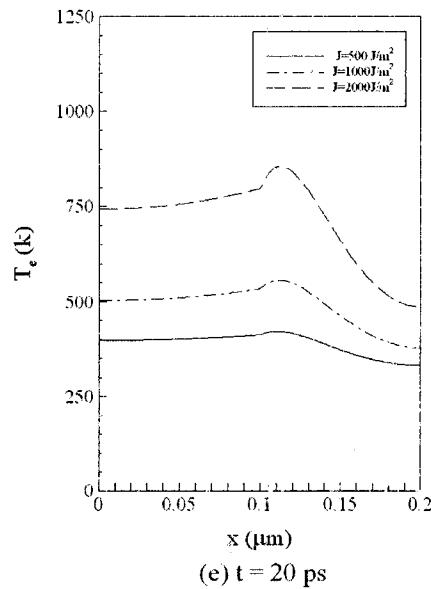


Fig. 5.12 Continued.

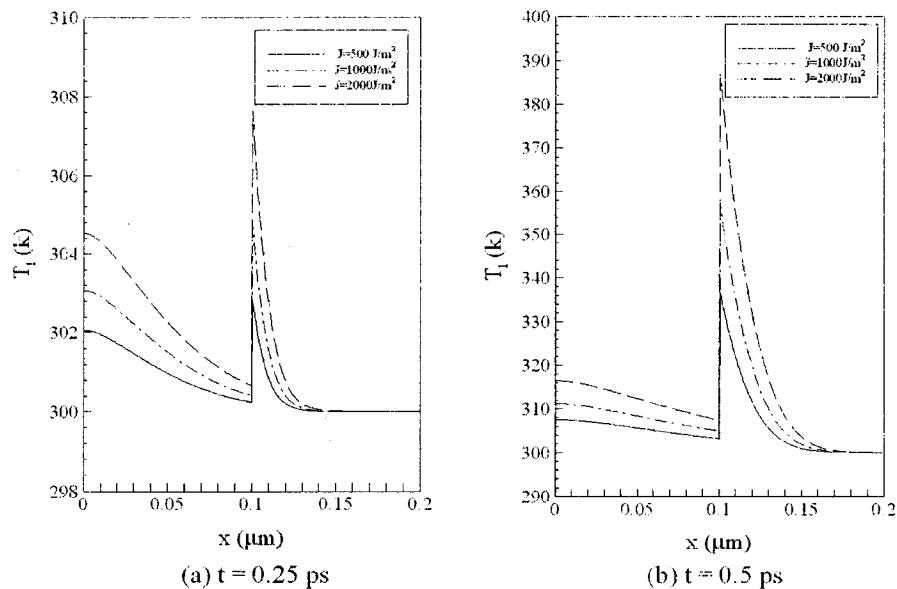


Fig. 5.13 Comparison of lattice temperature at $y = 0 \mu\text{m}$ at different times with three different laser fluences.

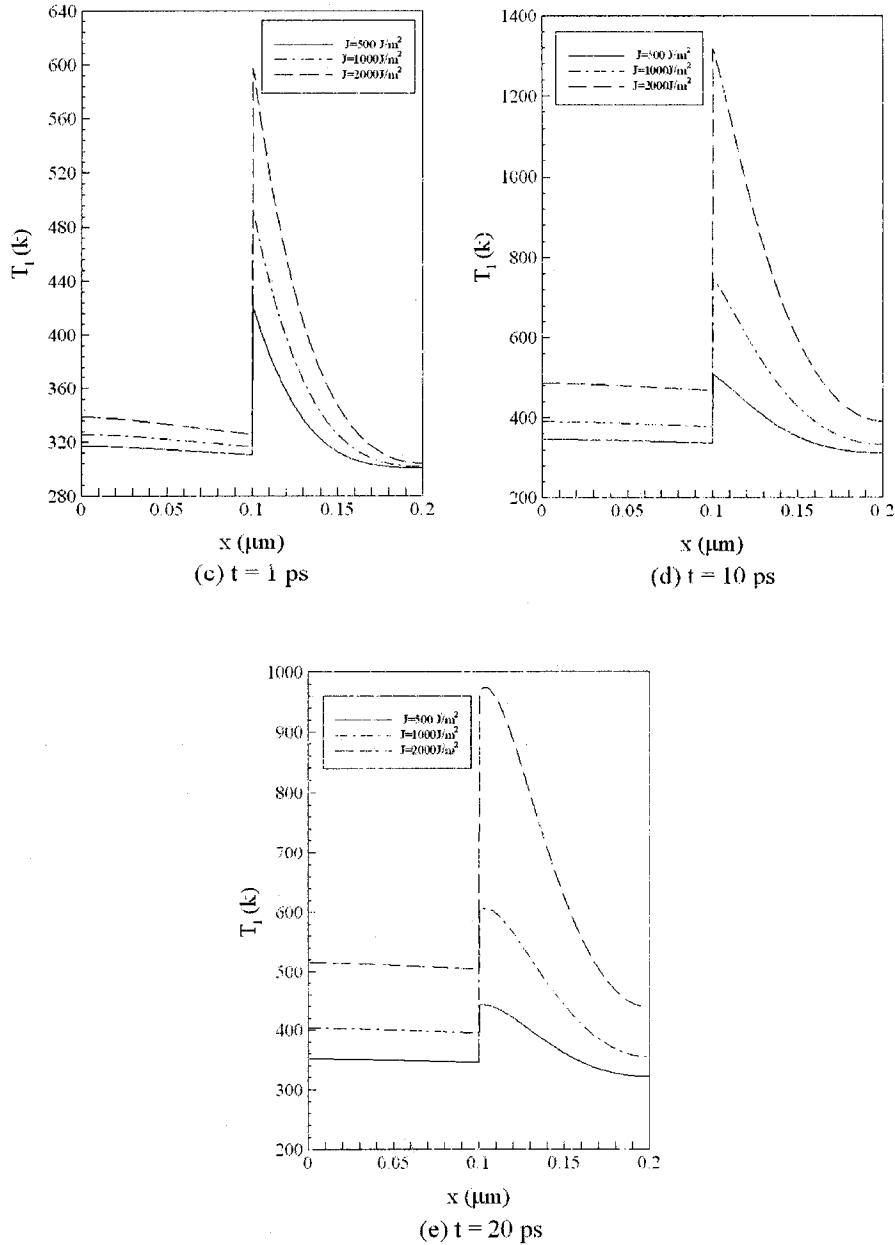


Fig. 5.13 Continued.

Figs. 5.14 and 5.15 show comparison of displacement u (thickness direction) along x at $y = \Delta y$ and v (length direction) along x at $y = \frac{1}{2}\Delta y$ with three different laser fluences ($J = 500 \text{ J m}^{-2}$, 1000 J m^{-2} and 2000 J m^{-2}) at different times (a) $t = 1 \text{ ps}$, (b) $t = 5 \text{ ps}$, (c) $t = 10 \text{ ps}$, and (d) $t = 20 \text{ ps}$. It can be seen that the existence of sharp

discontinuity of displacement at interface during the first 15 ps due to the discontinuous blasting force across the interface may result in the damage of thin film.

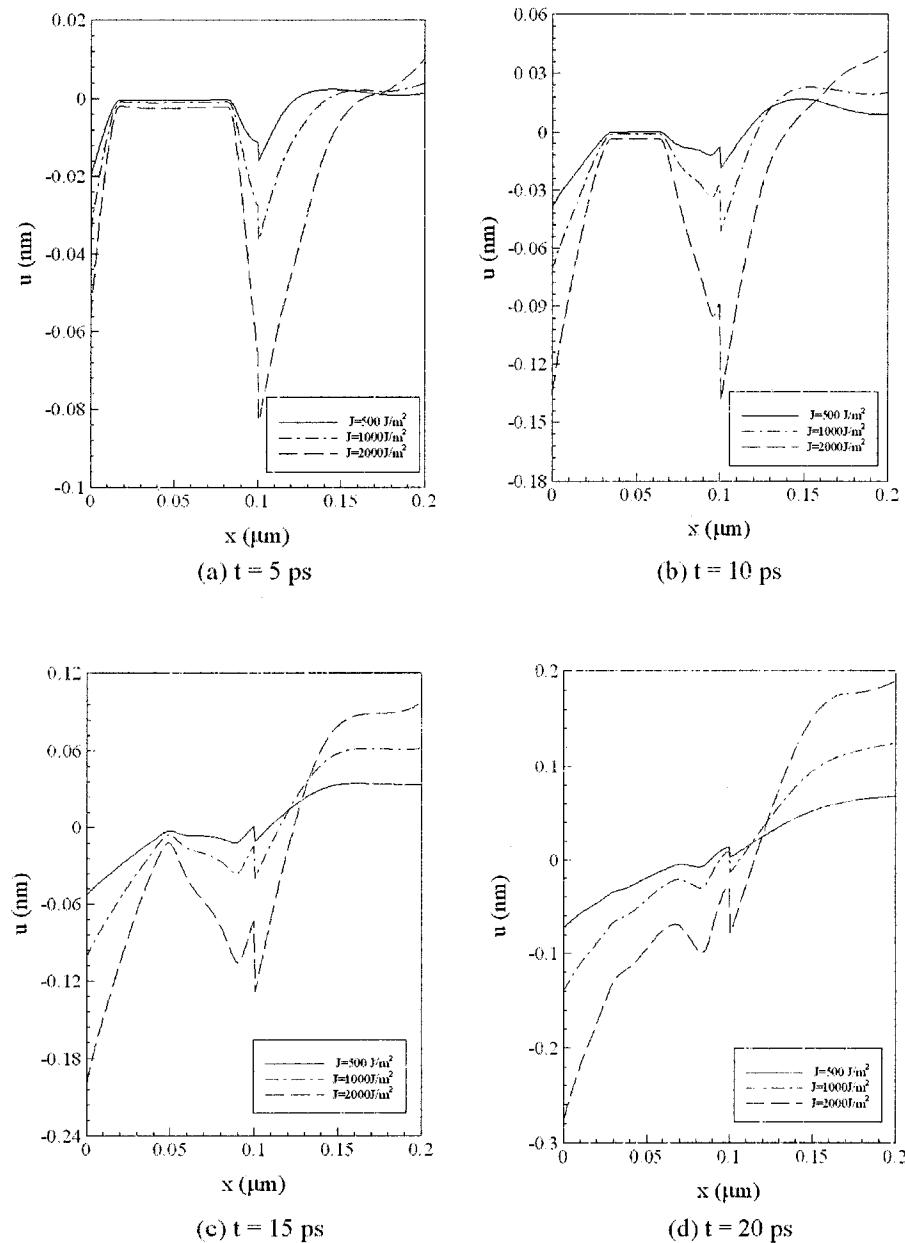


Fig 5.14 Comparison of displacement (u) at $y = \Delta y$ at different times with three different laser fluences

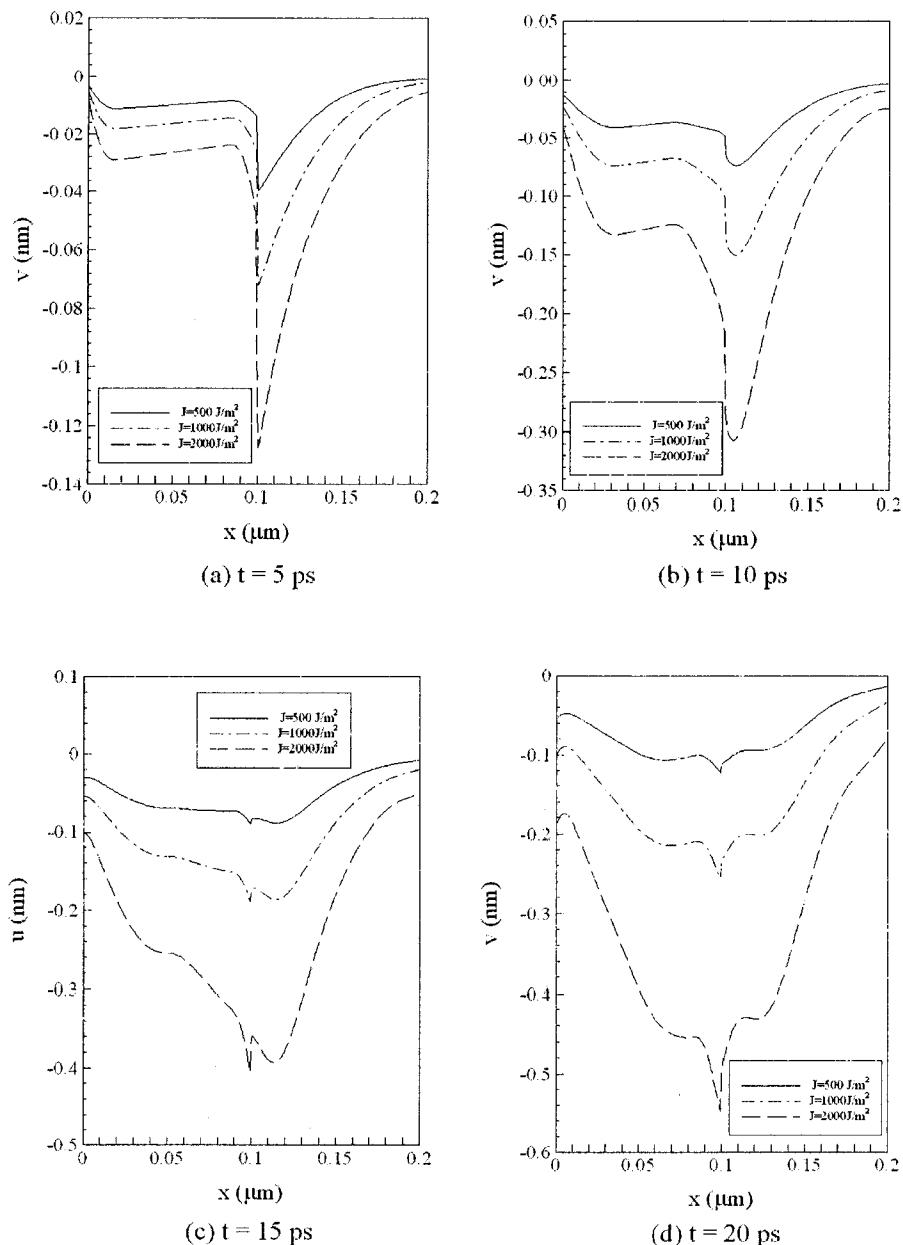


Fig 5.15 Comparison of displacement (v) at $y = \frac{1}{2}\Delta y$ at different times with three different laser fluences.

Figs. 5.16 and 5.17 show comparison of normal stress σ_x (thickness direction) and σ_y (length direction) along x at $y = \Delta y$ with three different laser fluences ($J = 500 \text{ J m}^{-2}$, 1000 J m^{-2} and 2000 J m^{-2}) at different times (a) $t = 1 \text{ ps}$, (b) $t = 5 \text{ ps}$, (c) t

$= 10 \text{ ps}$, and (d) $t = 20 \text{ ps}$. The discontinuous blasting force across the interface produces severe stress distributions in the gold and chromium thin film, and large compression is rapidly formed in the vicinity of the interface. The peak value of stress (σ_x) almost reaches 2.0 GPa at interface at $t = 5 \text{ ps}$ with laser fluence $J = 2000 \text{ J/m}^2$. These levels of stress at the most exaggerated state would damage the gold and chromium film in the picosecond domain.

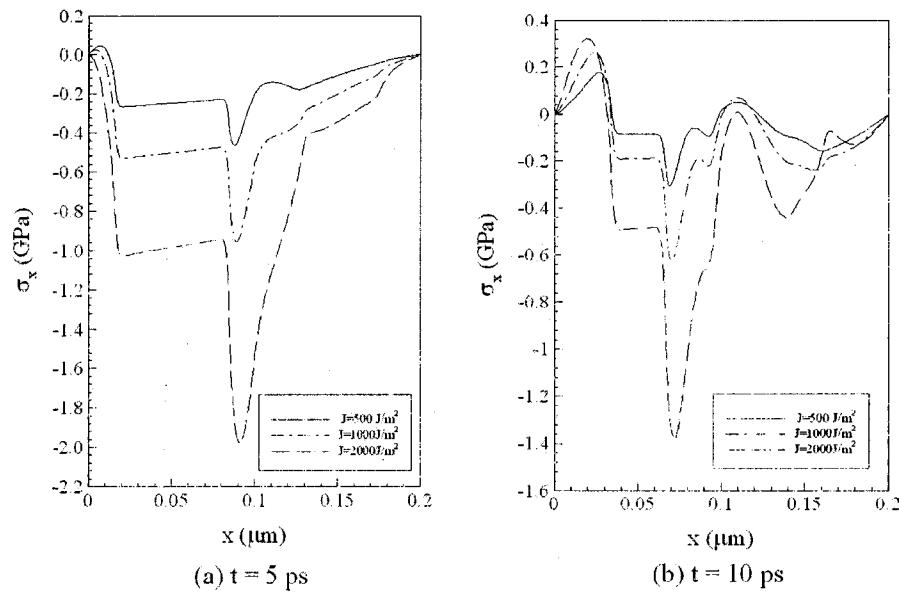


Fig. 5.16 Comparison of normal stress (σ_x) at $y = \Delta y$ at different times with three different laser fluences.

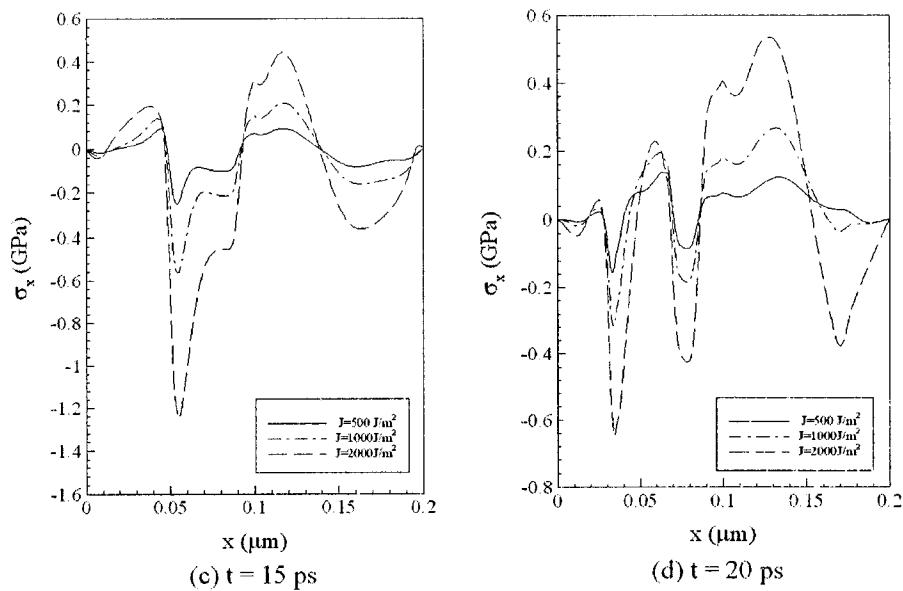


Fig. 5.16 Continued.

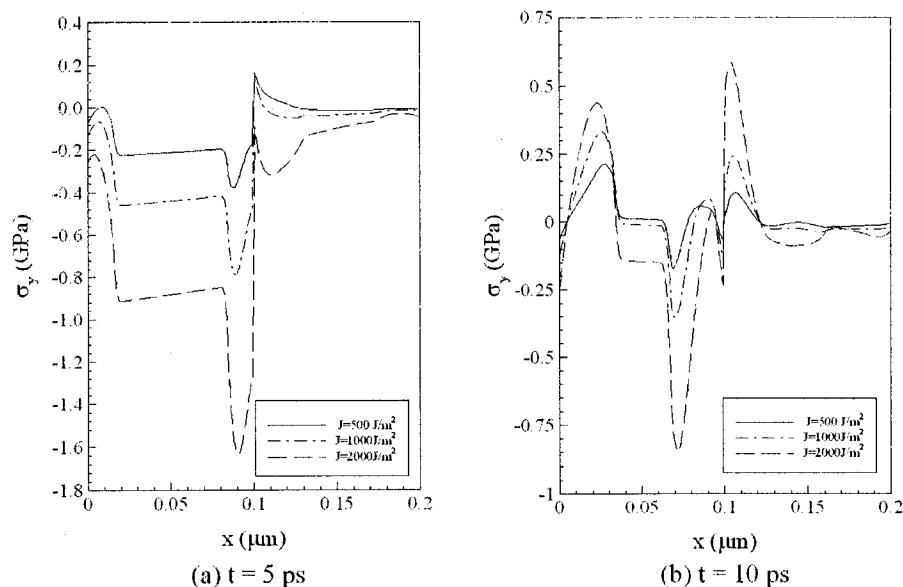


Fig. 5.17 Comparison of normal stress (σ_y) at $y = \Delta y$ at different times with three different laser fluences.

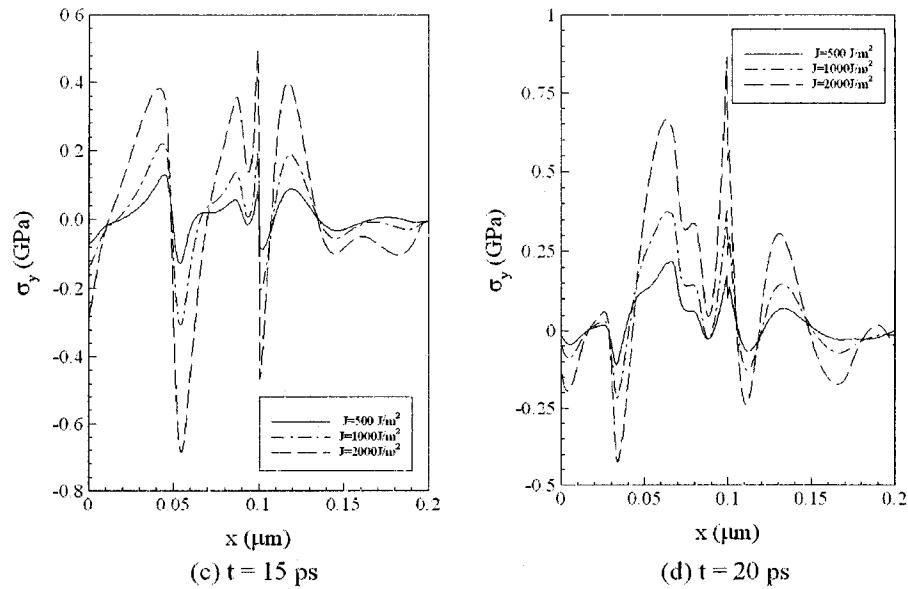


Fig. 5.17 Continued.

Figs. 5.18 and 5.19 show the contours of electron temperature profile and lattice temperature profile with the laser fluence of $J = 1000 \text{ J m}^{-2}$ at different times (a) $t = 0.25 \text{ ps}$, (b) $t = 0.5 \text{ ps}$, (c) $t = 1 \text{ ps}$, (d) $t = 10 \text{ ps}$, respectively.

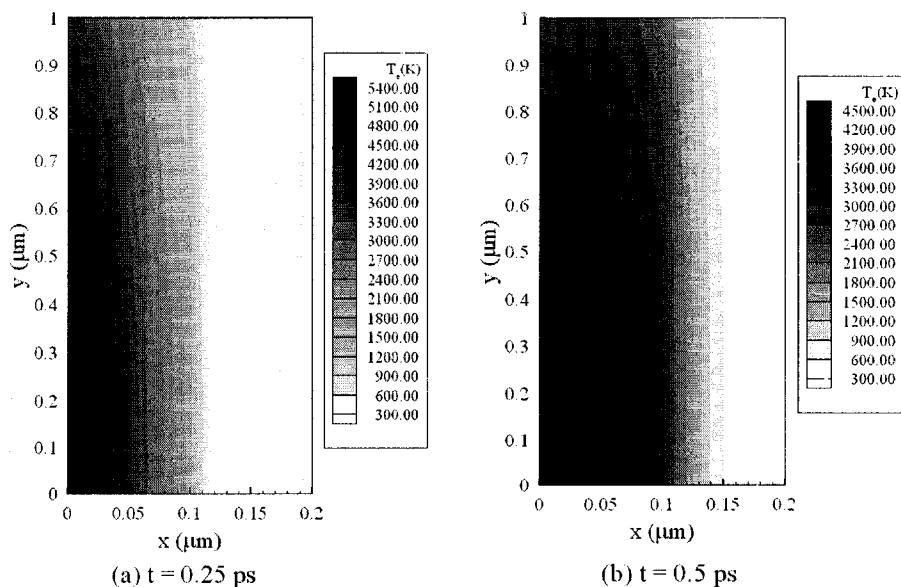


Fig 5.18 Electron temperature (T_e) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

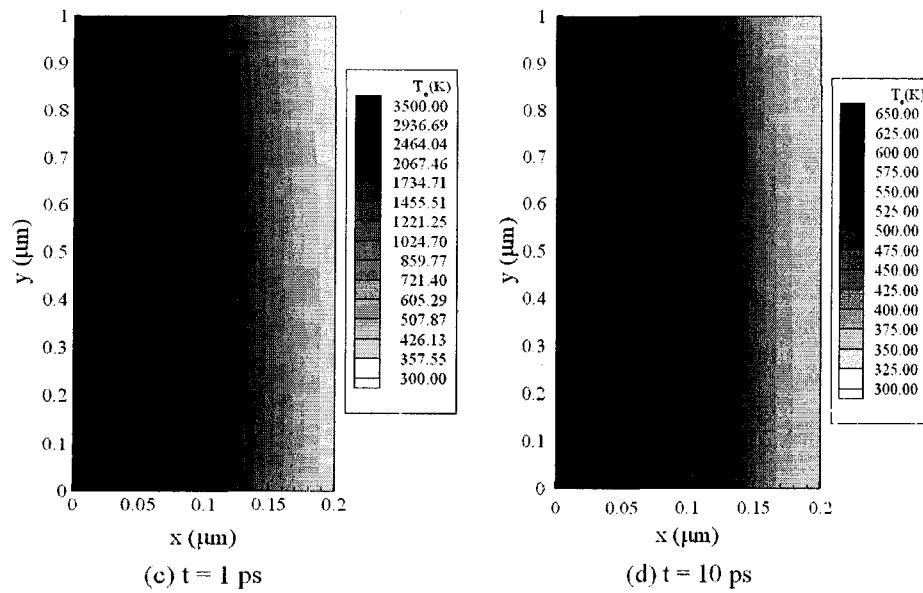


Fig 5.18 Continued.

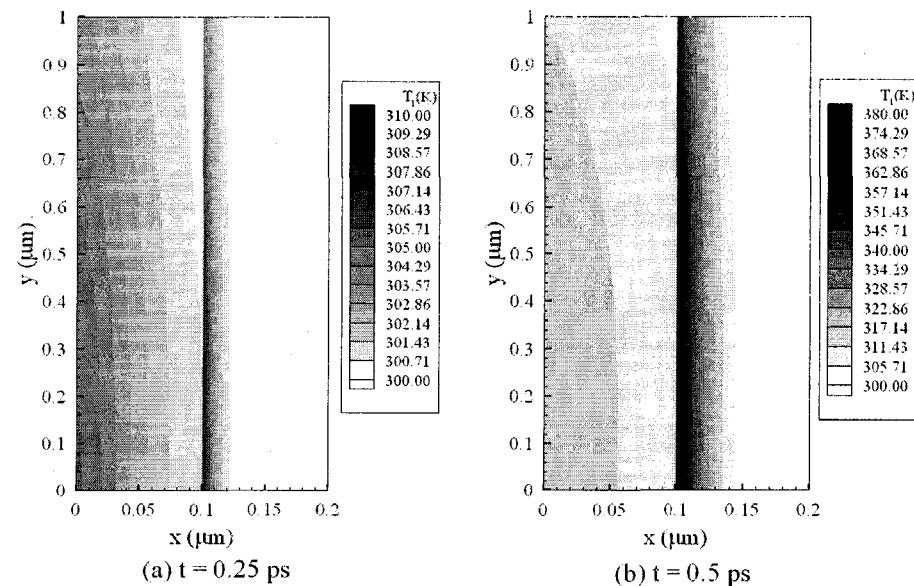


Fig 5.19 Lattice temperature (T_l) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

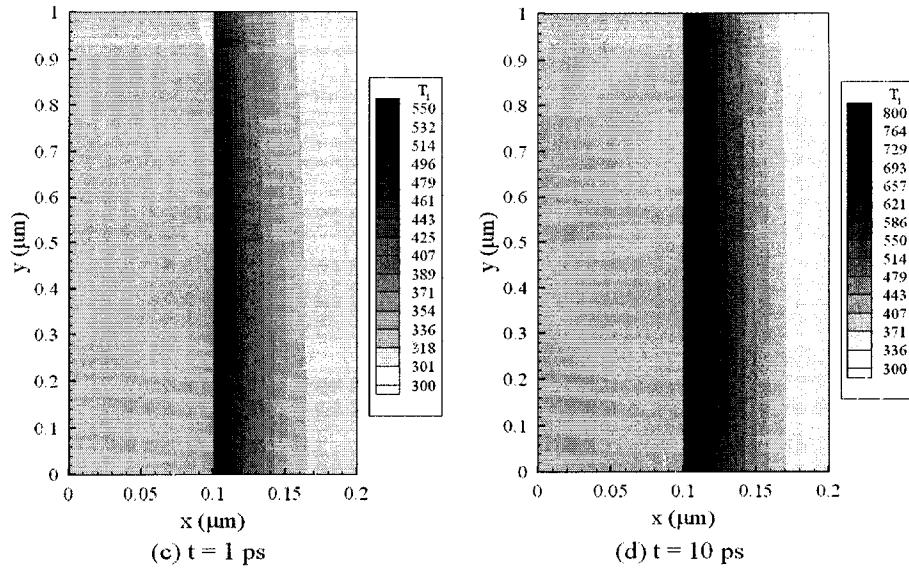


Fig 5.19 Continued.

Figs 5.20-5.23 show the contours of displacement u (thickness direction) profile, displacement v (length direction) profile, normal stress σ_x (thickness direction) profile, and normal stress σ_y (length direction) profile with the laser fluence of $J = 1000 \text{ J m}^{-2}$ at different times (a) $t = 5 \text{ ps}$, (b) $t = 10 \text{ ps}$, (c) $t = 15 \text{ ps}$, and (d) $t = 20 \text{ ps}$, respectively.

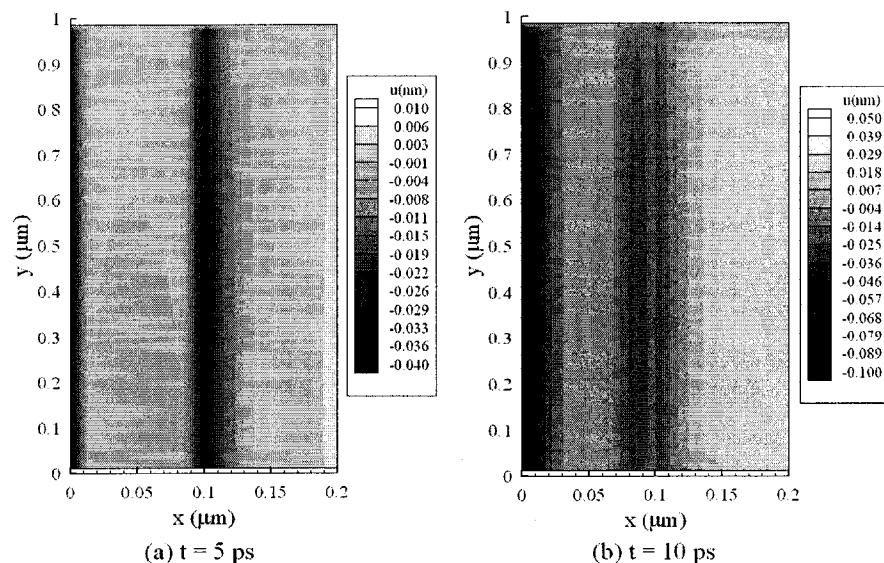


Fig. 5.20 Displacement (u) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

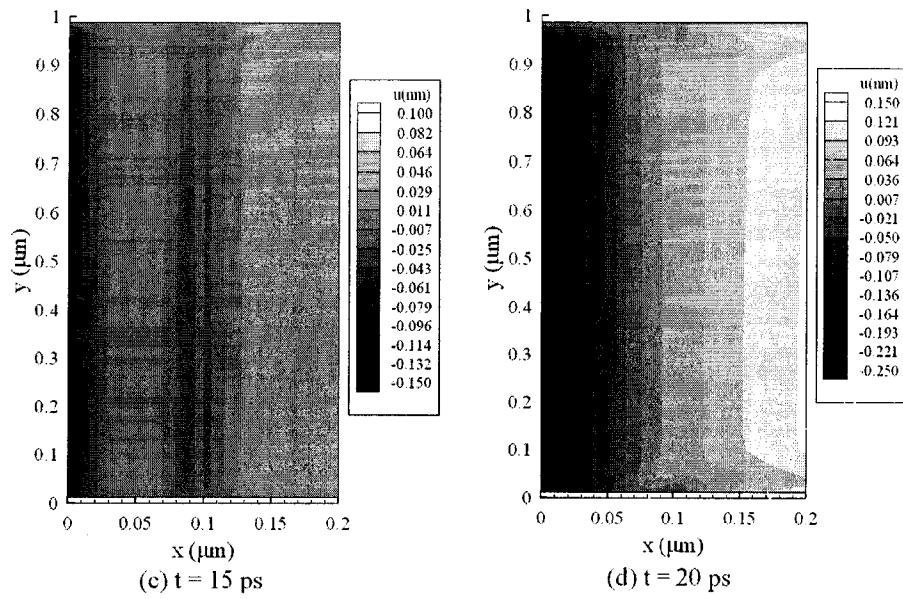


Fig. 5.20 Continued.

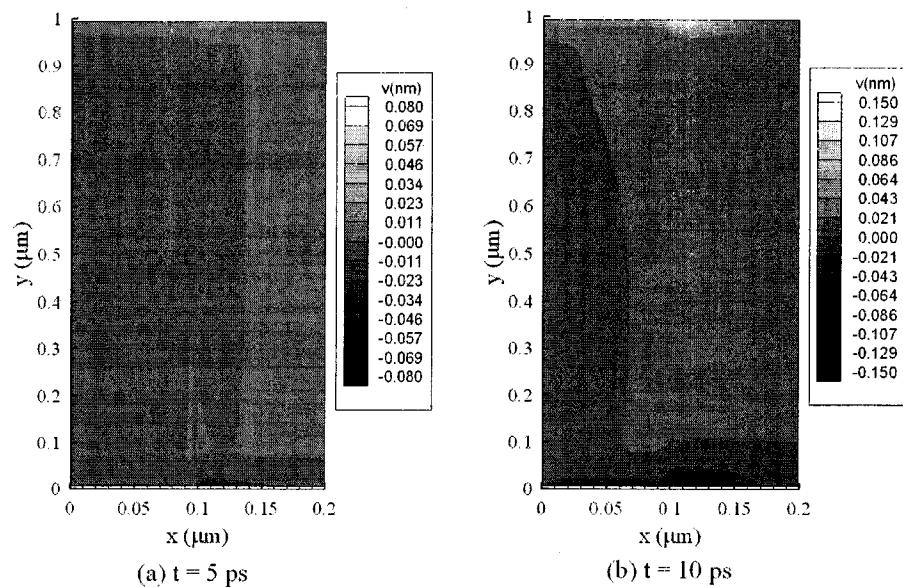


Fig. 5.21 Displacement (v) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

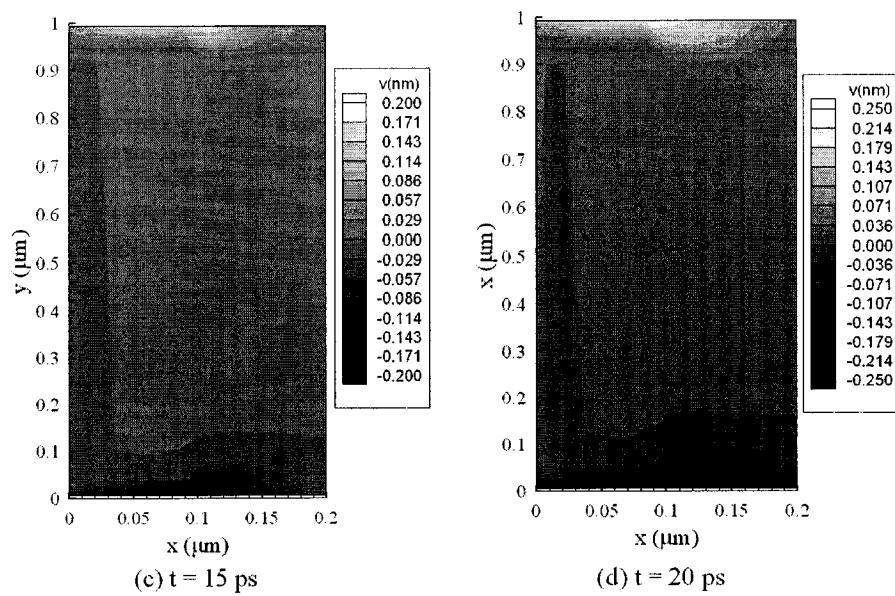


Fig. 5.21 Continued.

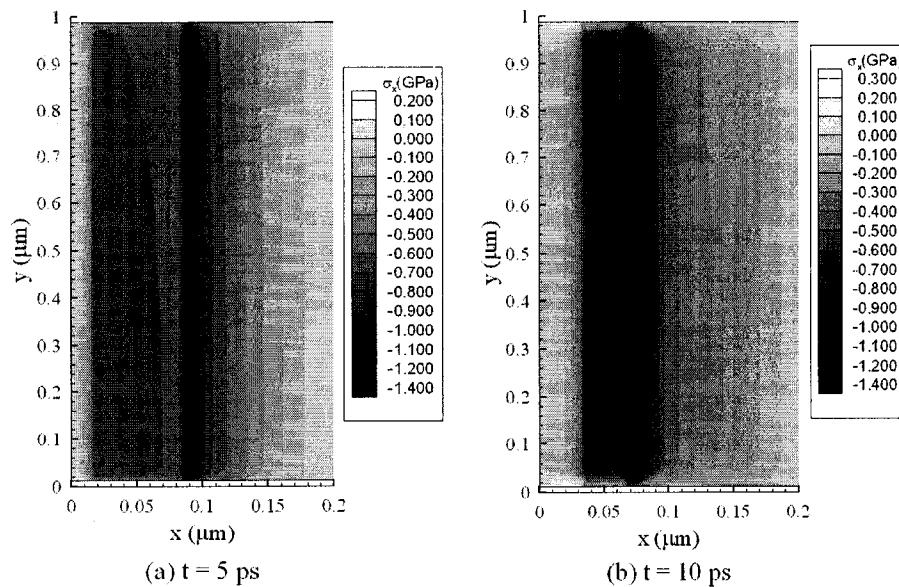


Fig. 5.22 Normal stress (σ_x) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

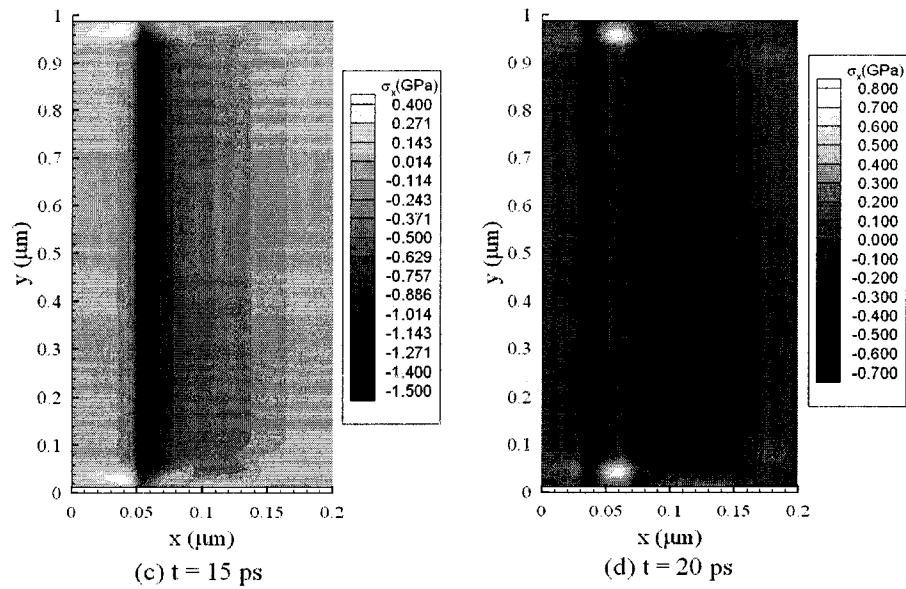


Fig. 5.22 Continued.

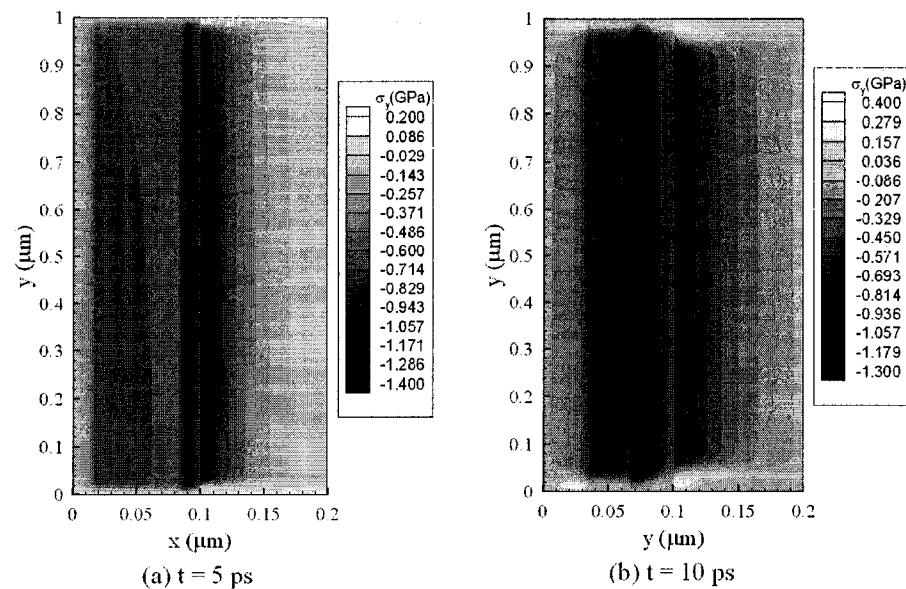


Fig. 5.23 Normal stress (σ_y) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

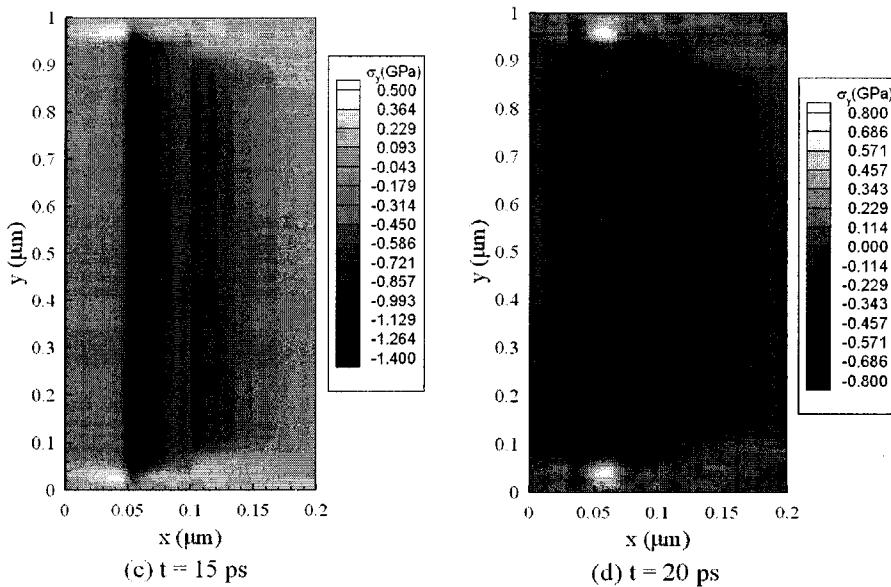


Fig. 5.23 Continued.

The analysis of displacement and stress waves reveals the significance of the hot-electron blast effect on the ultrafast deformation mainly along the thickness direction. Furthermore, the proposed methodology allows us to obtain the solution free from non-physical oscillations.

Case 2: Imperfectly thermal contact at interface

Fig. 5.24 shows the temperature change in electron temperature $\left[\frac{\Delta T_e}{(\Delta T_e)_{\max}} \right]$ at $x = 0 \mu\text{m}$ and $y = 0 \mu\text{m}$ with laser $J = 1000 \text{ J m}^{-2}$. The maximum temperature rise of T_e (i.e., $(\Delta T_e)_{\max}$) is about 5823K.

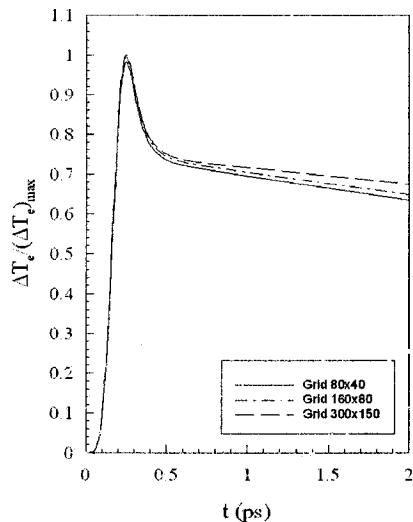


Fig. 5.24 Change in electron temperature at $x = 0 \mu\text{m}$ and $y = 0 \mu\text{m}$ versus time for various meshes (80×40 , 160×80 , 300×150).

Fig. 5.25 shows the displacement (u) at $x = \frac{1}{2} \Delta x$, and $y = \Delta y$ versus time. It can be seen from both figures that mesh size has no significant effect on the solutions, and hence this method is only weakly dependent on the grid.

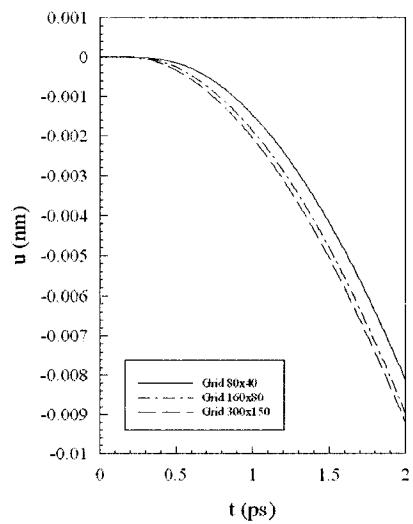


Fig. 5.25 Displacement (u) at $x = \frac{1}{2} \Delta x$ and $y = \Delta y$ with laser $J = 500 \text{ J m}^{-2}$ versus time for various meshes (80×40 , 160×80 , 300×150).

Figs. 5.26 and 5.27 show comparisons of electron temperature and lattice temperature, respectively, along x at $y = 0\mu m$ between the perfect thermal contact and the imperfect thermal contact at interface with three different laser fluences ($J = 500 Jm^{-2}$, $1000 Jm^{-2}$ and $2000 Jm^{-2}$) at different times (a) $t = 0.25 ps$, (b) $t = 0.5 ps$, (c) $t = 1 ps$, (d) $t = 10 ps$ and (e) $t = 20 ps$. It can be seen that the electron temperature rises to its maximum at the beginning and then decreases while the lattice temperature rises gradually with time. Fig 5.26 shows clearly that there is a sharp discontinuity of electron temperature at the interface when imperfectly thermal contact exists between two bonded thin layers. Similar temperature discontinuity is observed at the interface for lattice temperature in Fig. 5.27. These results indicate that imperfect thermal contact at the interface provides a barrier to thermal energy diffusion across the interface. These two figures also show that electron temperature and lattice temperature are uniform throughout the chromium layer, and uniform throughout the gold layer after a long period. The uniform electron and lattice temperatures are probably due to increased rate of collision between electrons and phonons in the gold layer as electron energy diffusion is inhibited at the interface.

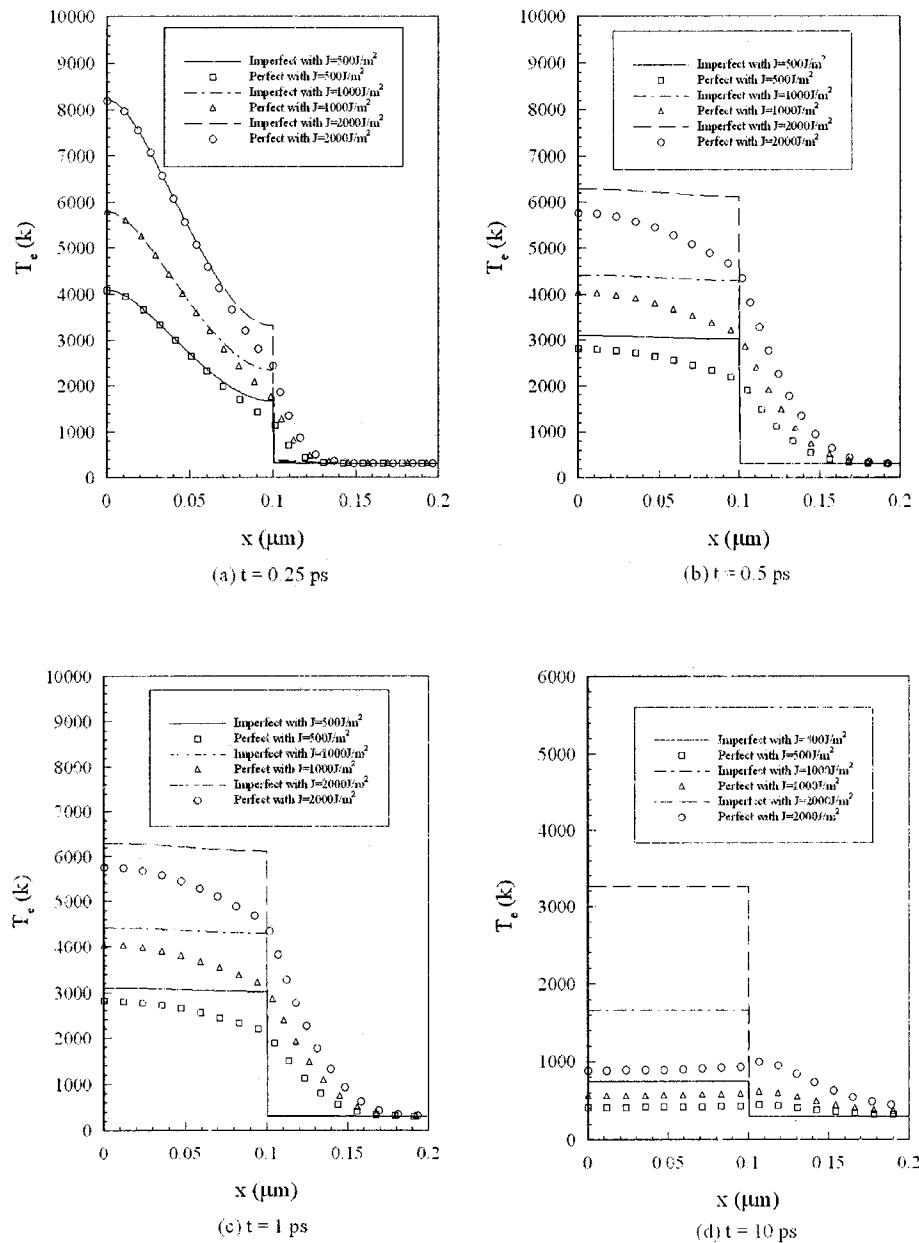


Fig. 5.26 Comparison of electron temperature at $y = 0 \mu\text{m}$ at different times between perfect and imperfect contact at interface with three different laser fluences.

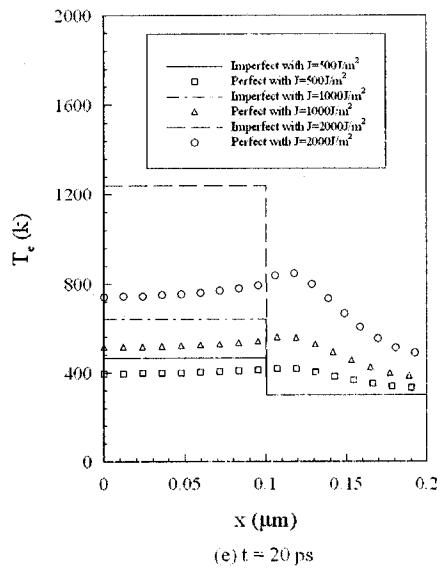


Fig. 5.26 Continued.

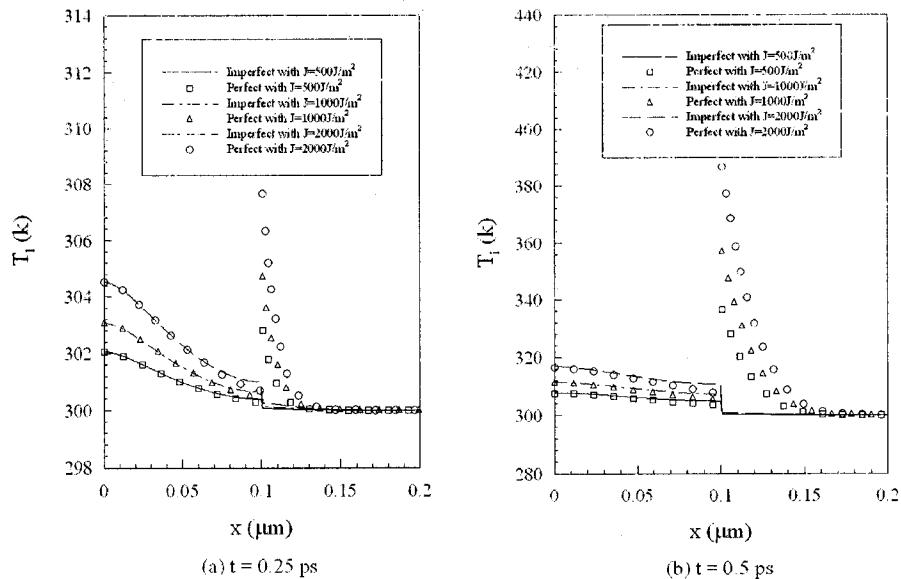


Fig. 5.27 Comparison of lattice temperature at $y = 0 \mu\text{m}$ at different times between perfect and imperfect contact at interface with three different laser fluences.

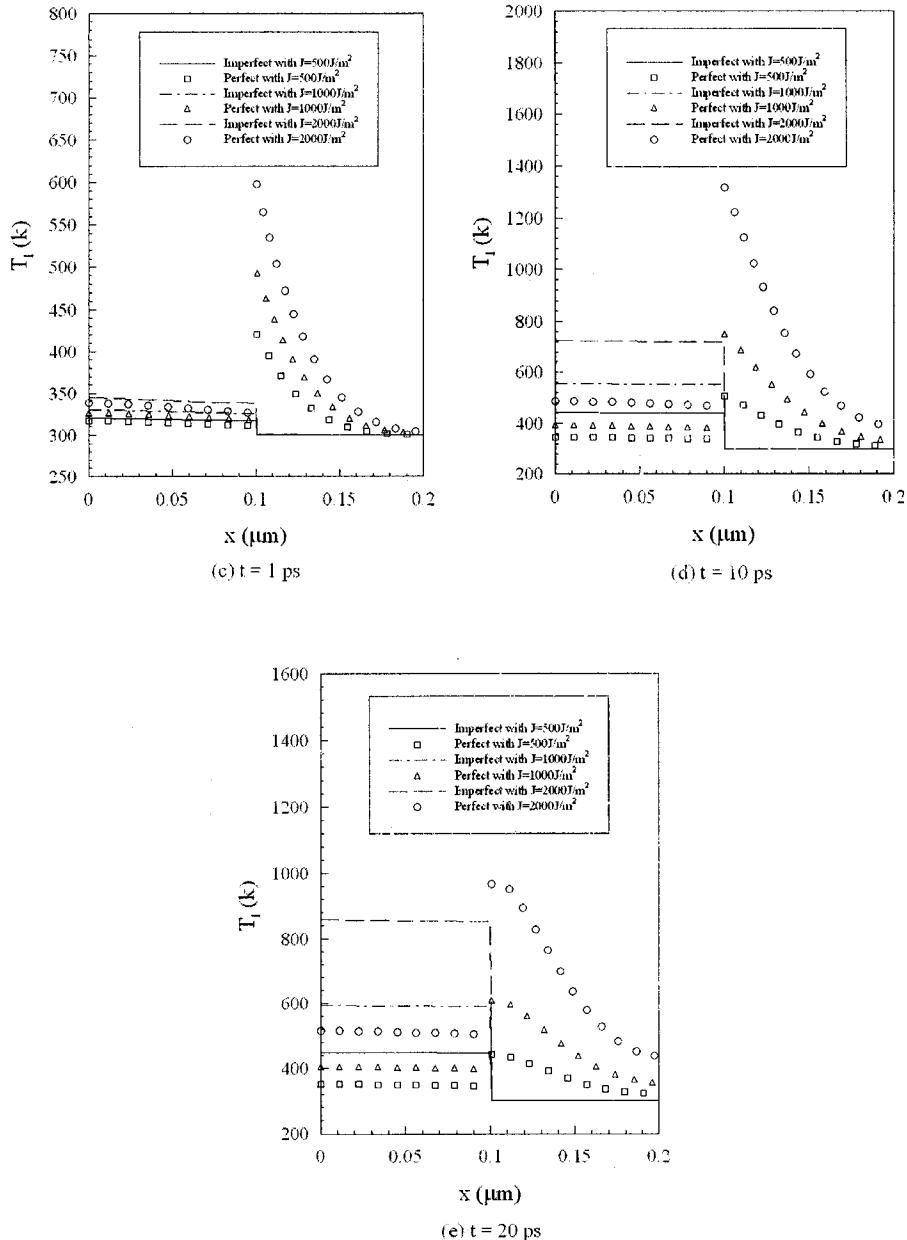


Fig. 5.27 Continued.

Figs. 5.28 and 5.29 show comparisons of displacement u (thickness direction) along x at $y = \Delta y$ and v (length direction) along x at $y = \frac{1}{2}\Delta y$ between the perfect thermal contact [Wang 2006b] and the imperfect thermal contact at interface with three different laser fluences ($J = 500 \text{ J m}^{-2}$, 1000 J m^{-2} and 2000 J m^{-2}) at different times (a) t

= 5 ps, (b) $t = 10$ ps, (c) $t = 15$ ps, and (d) $t = 20$ ps, respectively. It can be seen that for the imperfect thermal contact case sharp discontinuity of displacement exists at the interface, and the gold layer undergoes severe displacement alterations from negative to positive while the displacement alteration in the chromium layer is almost absent. However, the sharp discontinuity of displacement that exists at the interface may result in shear failure. Severe displacement alteration which exists in the gold layer may produce internal damages within the layer. Displacement alteration in the gold layer is more pronounced for bonded films with the imperfect thermal contact.

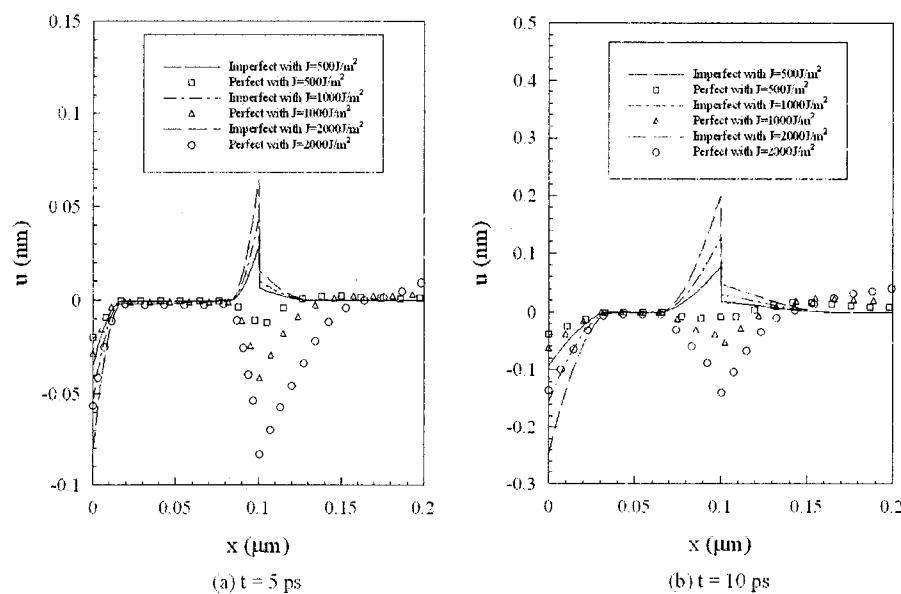
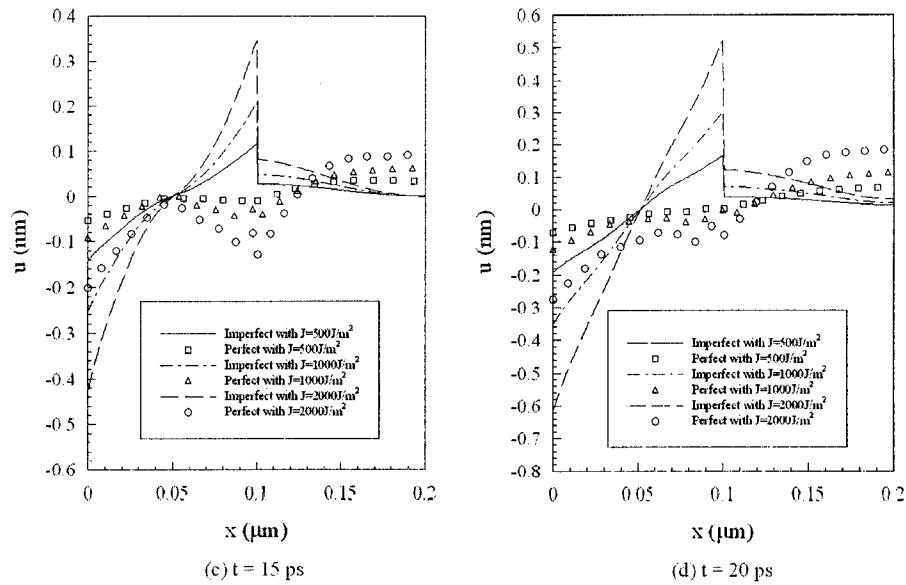
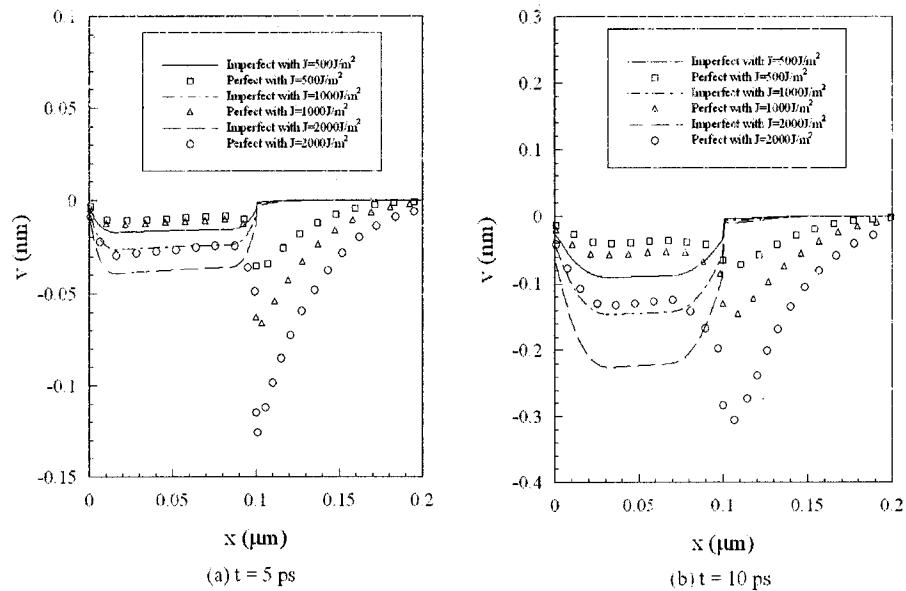


Fig. 5.28 Comparison of displacement (u) at $y = \Delta y$ at different times between perfect and imperfect contact at interface with three different laser fluences.

**Fig. 5.28** Continued.**Fig. 5.29** Comparison of displacement (v) at $y = \frac{1}{2} \Delta y$ at different times between perfect and imperfect contact at interface with three different laser fluences.

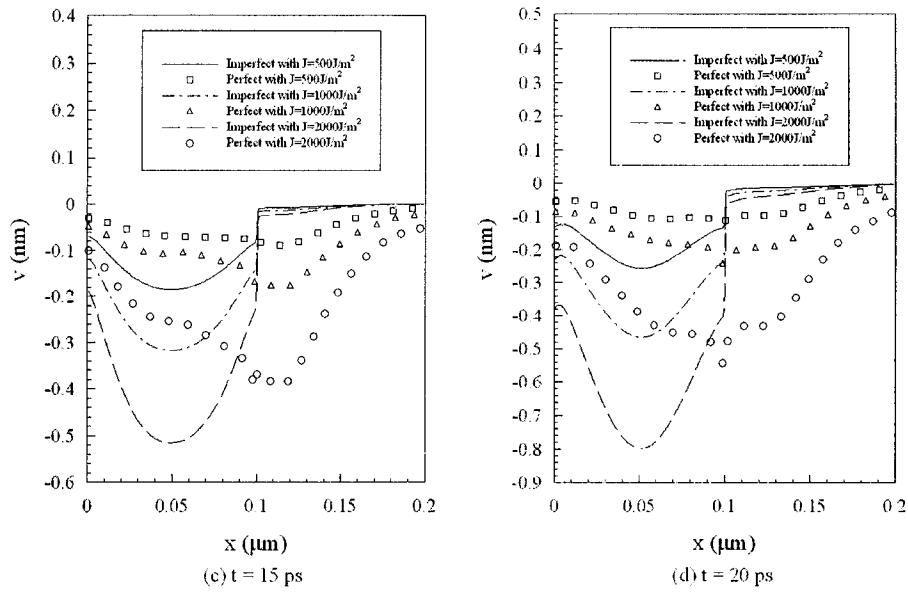


Fig. 5.29 Continued.

Figs. 5.30 and 5.31 show comparison of normal stress σ_x (thickness direction) and σ_y (length direction) along x at $y = \Delta y$ between the perfect thermal contact [Wang 2006b] and the imperfect thermal contact at interface with three different laser fluences ($J = 500Jm^{-2}$, $1000Jm^{-2}$ and $2000Jm^{-2}$) at different times (a) $t = 5 ps$, (b) $t = 10 ps$, (c) $t = 15 ps$, and (d) $t = 20 ps$, respectively. The ultrashort-pulsed laser heating produced severe stress distributions in the gold layer for the imperfect contact case. However, in the chromium layer, stress distribution is less severe. This stress distribution implies that the gold layer may undergo severe structural deformation.

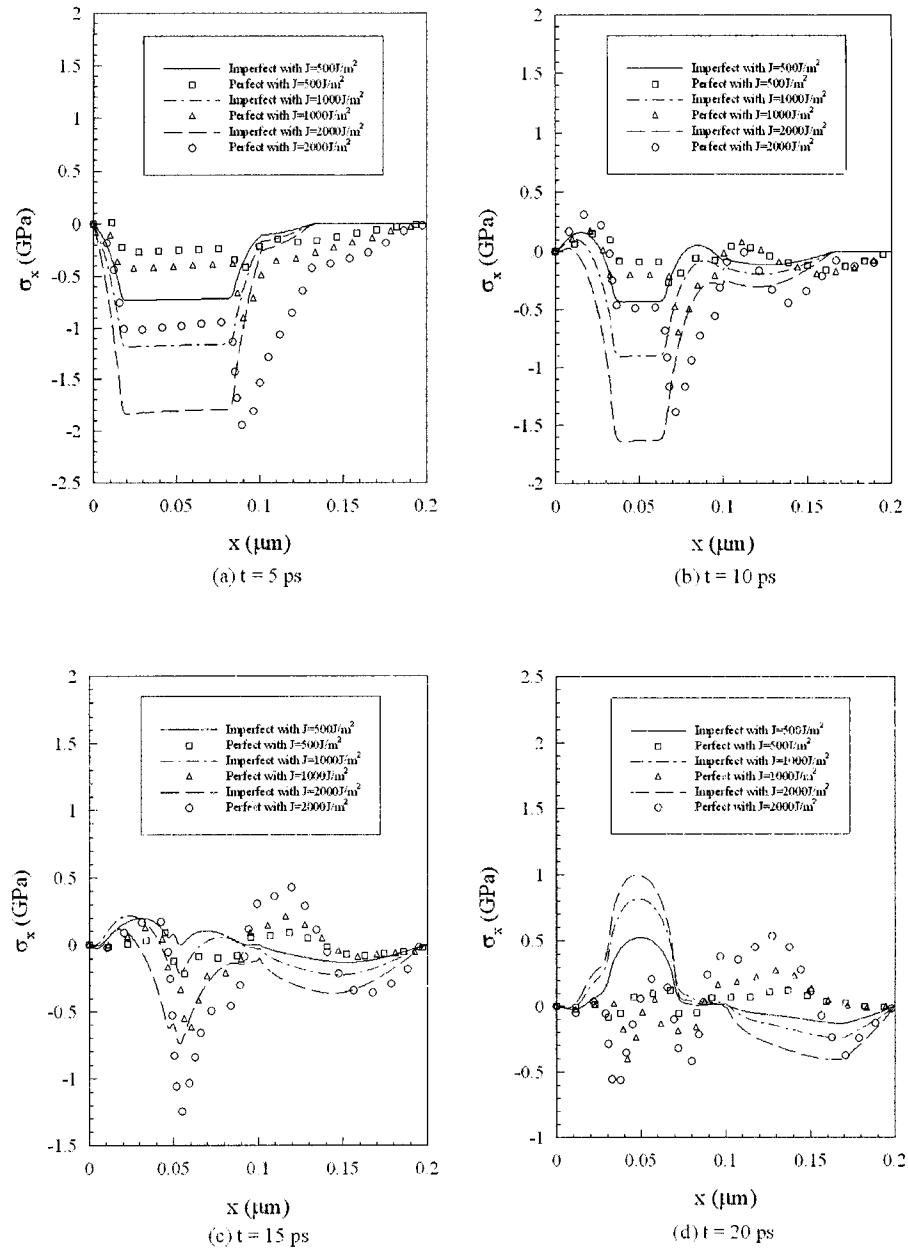


Fig. 5.30 Comparison of stress (σ_x) at $y = \Delta y$ at different times between perfect and imperfect contact at interface with three different laser fluences.

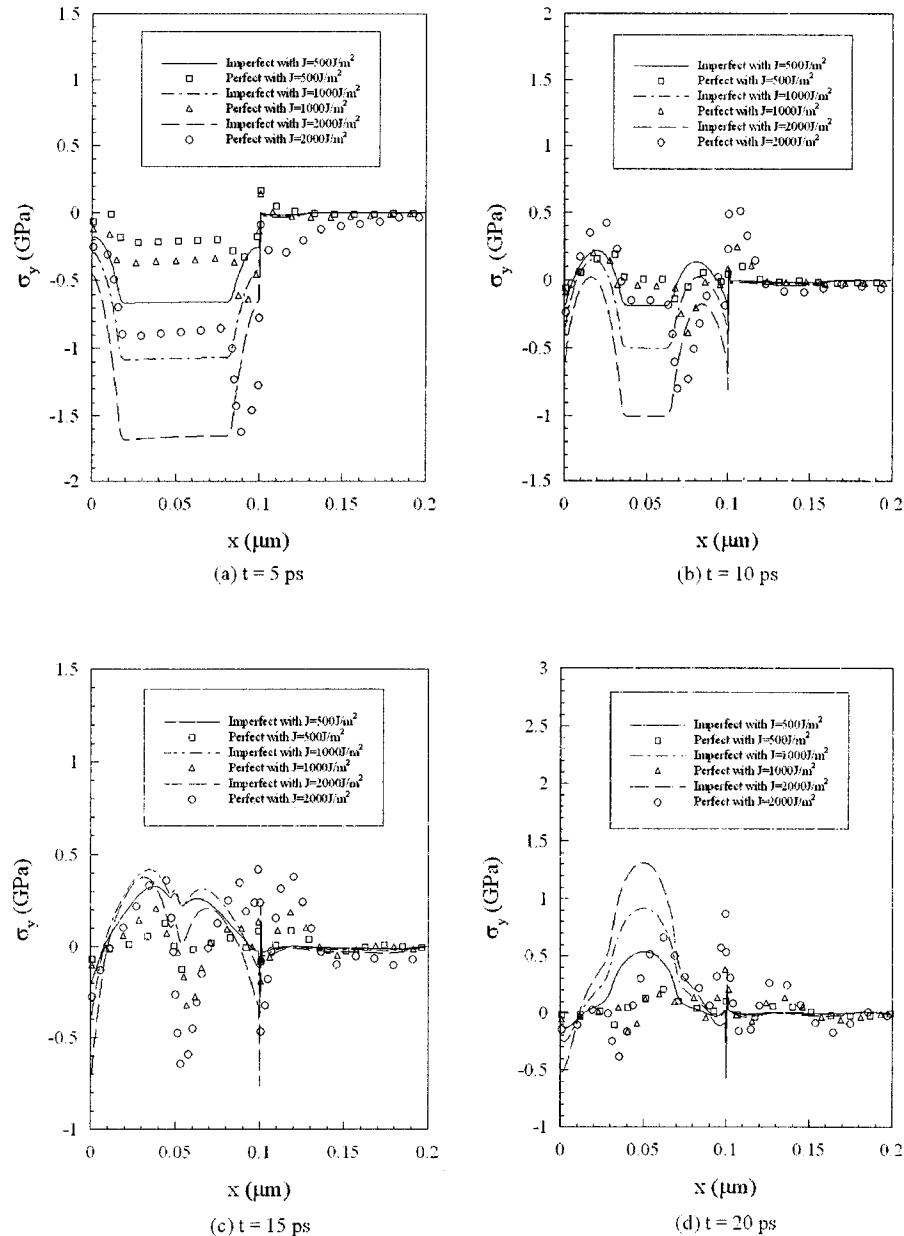


Fig. 5.31 Comparison of stress (σ_y) at $y = \Delta y$ at different times between perfect and imperfect contact at interface with three different laser fluences.

Figs. 5.32 and 5.33 show the contours of electron temperature profile and lattice temperature profile with the laser fluence of $J = 1000 J m^{-2}$ at different times (a) $t = 0.25$ ps, (b) $t = 0.5$ ps, (c) $t = 1$ ps, (d) $t = 10$ ps, respectively.

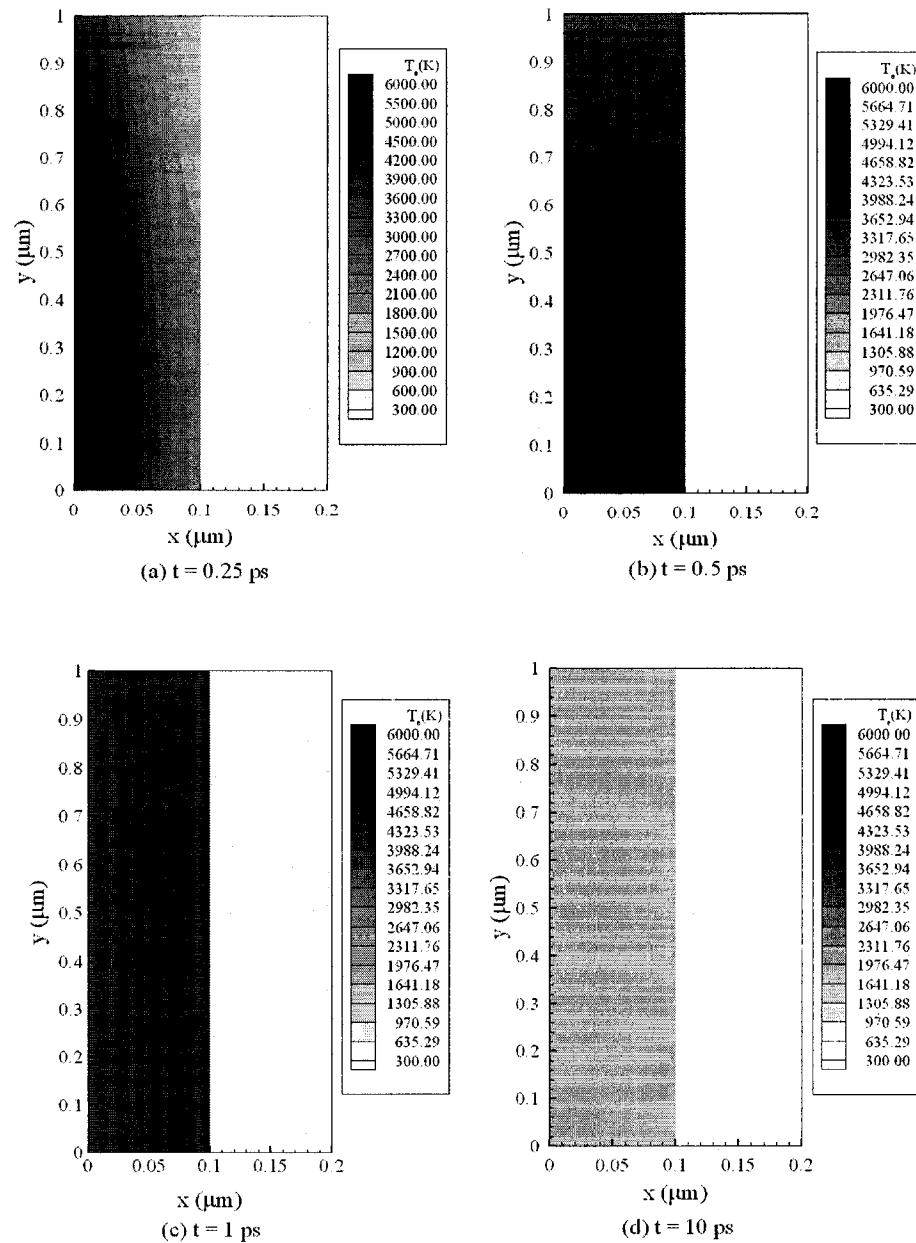


Fig. 5.32 Electron temperature (T_e) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

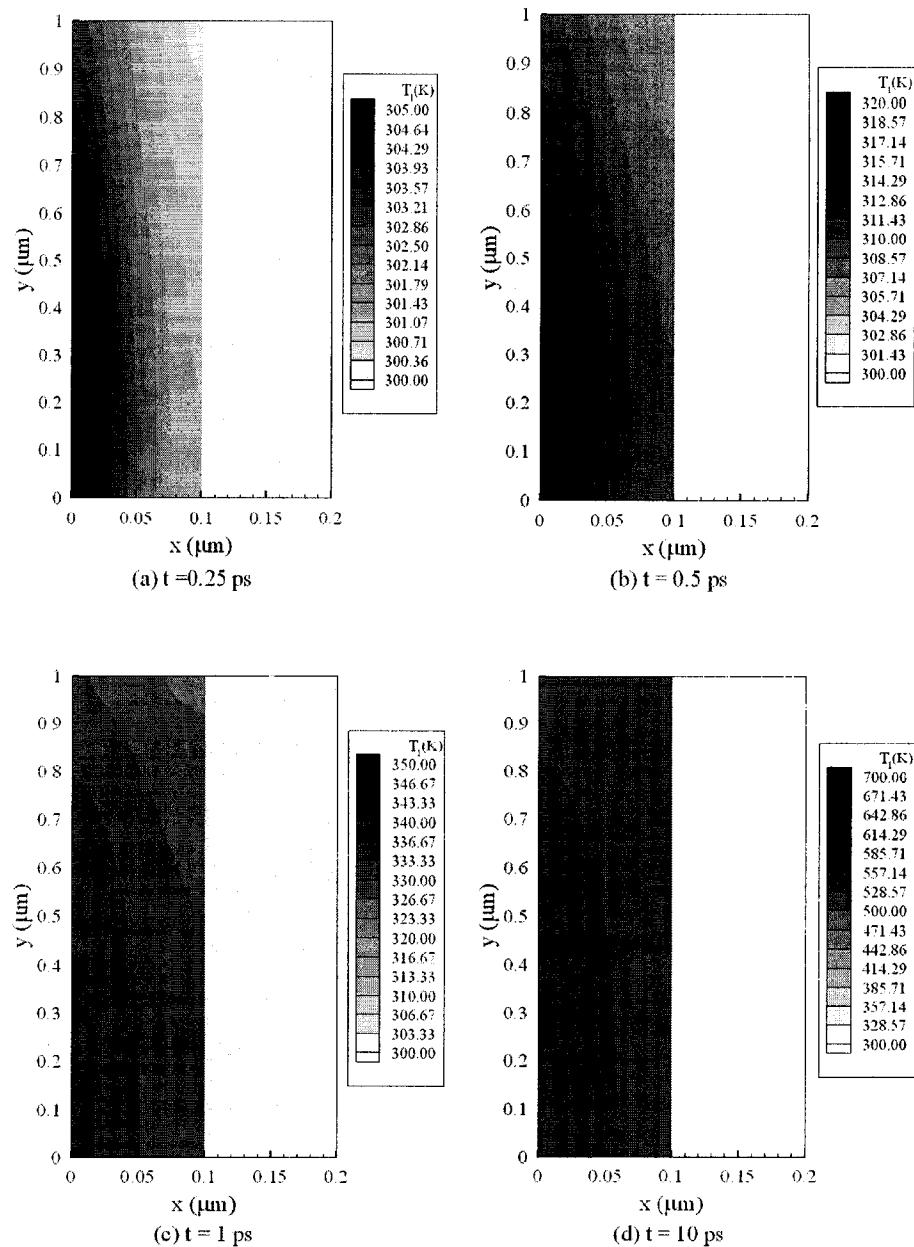


Fig. 5.33 Lattice temperature (T_l) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

Figs 5.34-5.37 show the contours of displacement u (thickness direction) profile, displacement v (length direction) profile, normal stress σ_x (thickness direction) profile,

and normal stress σ_y (length direction) profile with the laser fluence of $J = 1000 Jm^{-2}$ at different times (a) $t = 5 \text{ ps}$, (b) $t = 10 \text{ ps}$, (c) $t = 15 \text{ ps}$, and (d) $t = 20 \text{ ps}$, respectively.

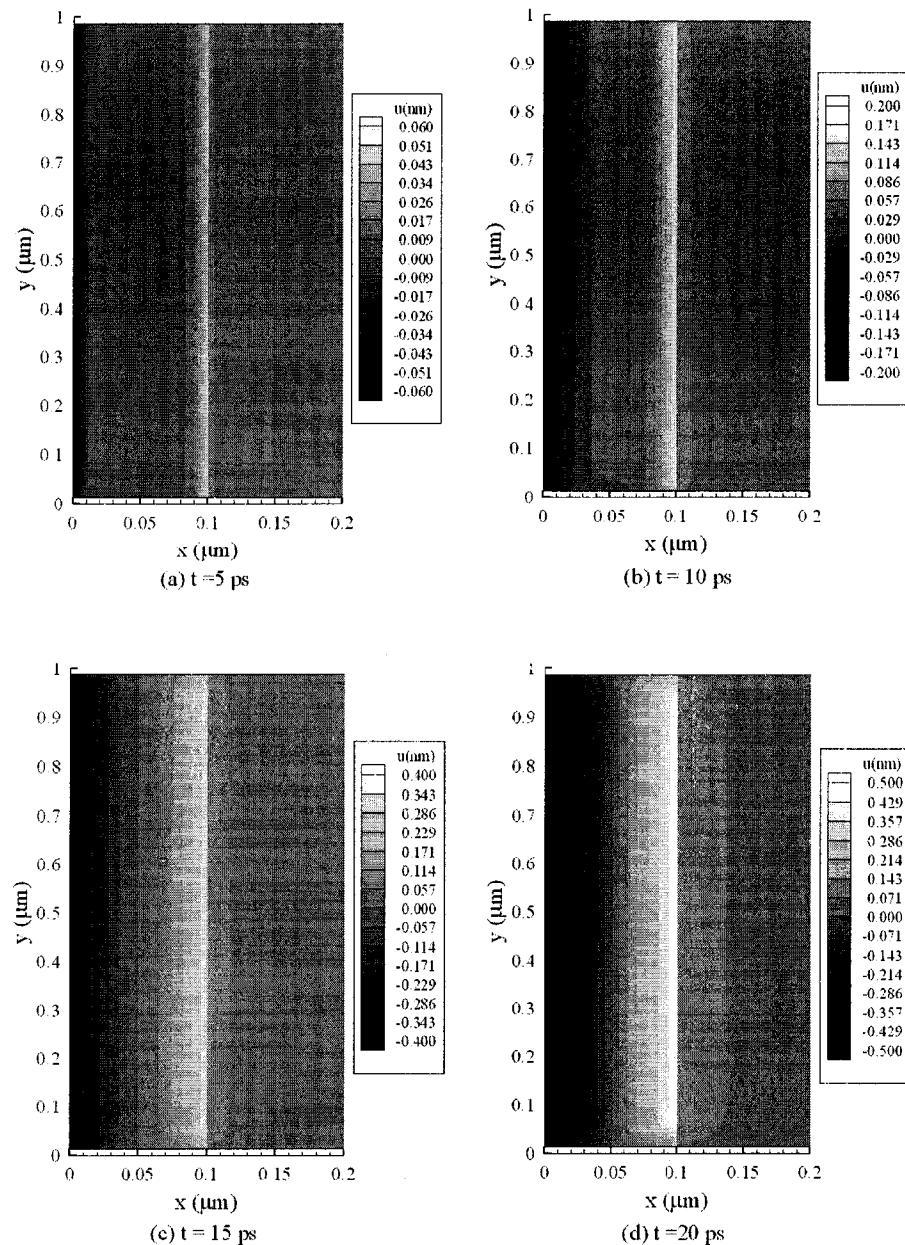


Fig. 5.34 Displacement (u) profiles at different times with laser fluence $J = 1000 Jm^{-2}$.

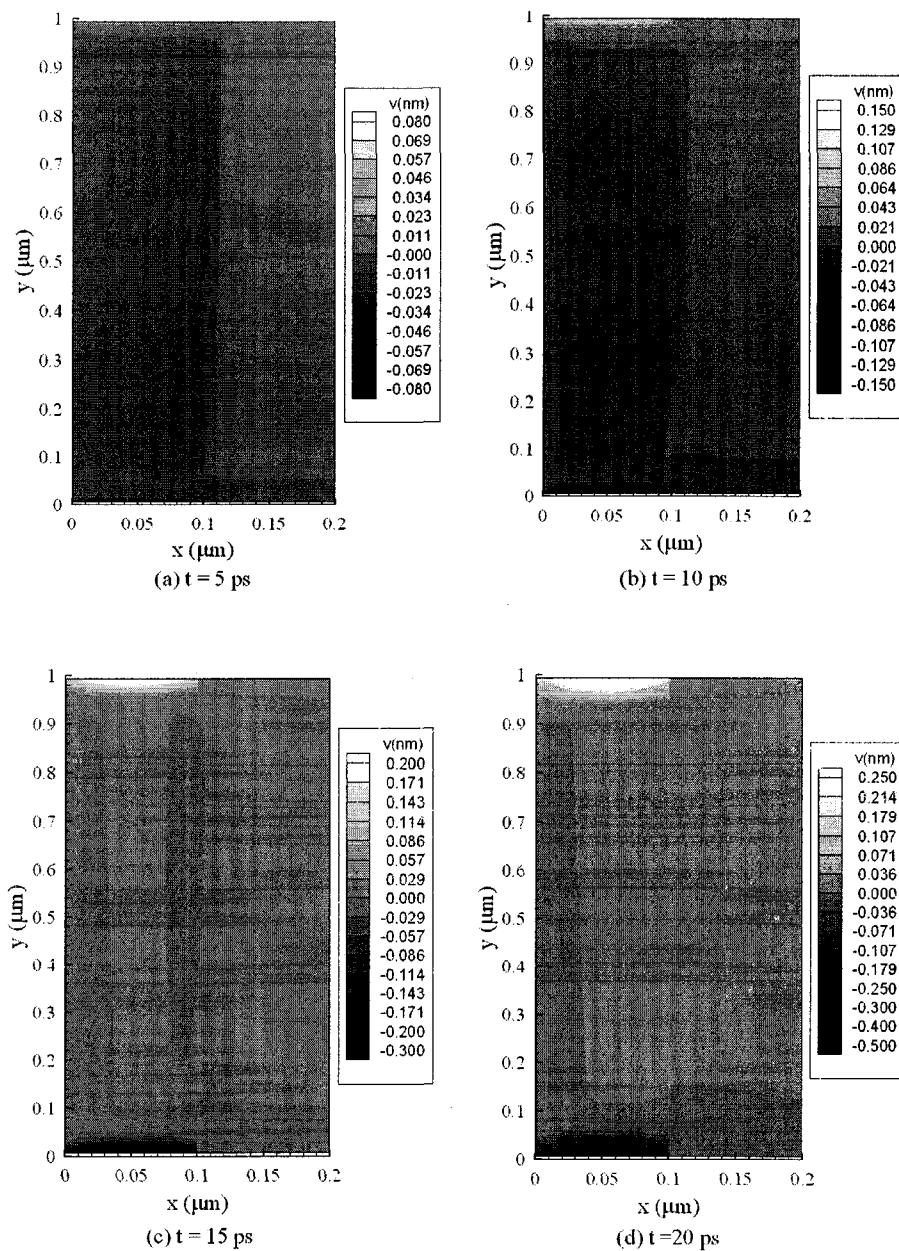


Fig. 5.35 Displacement (v) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

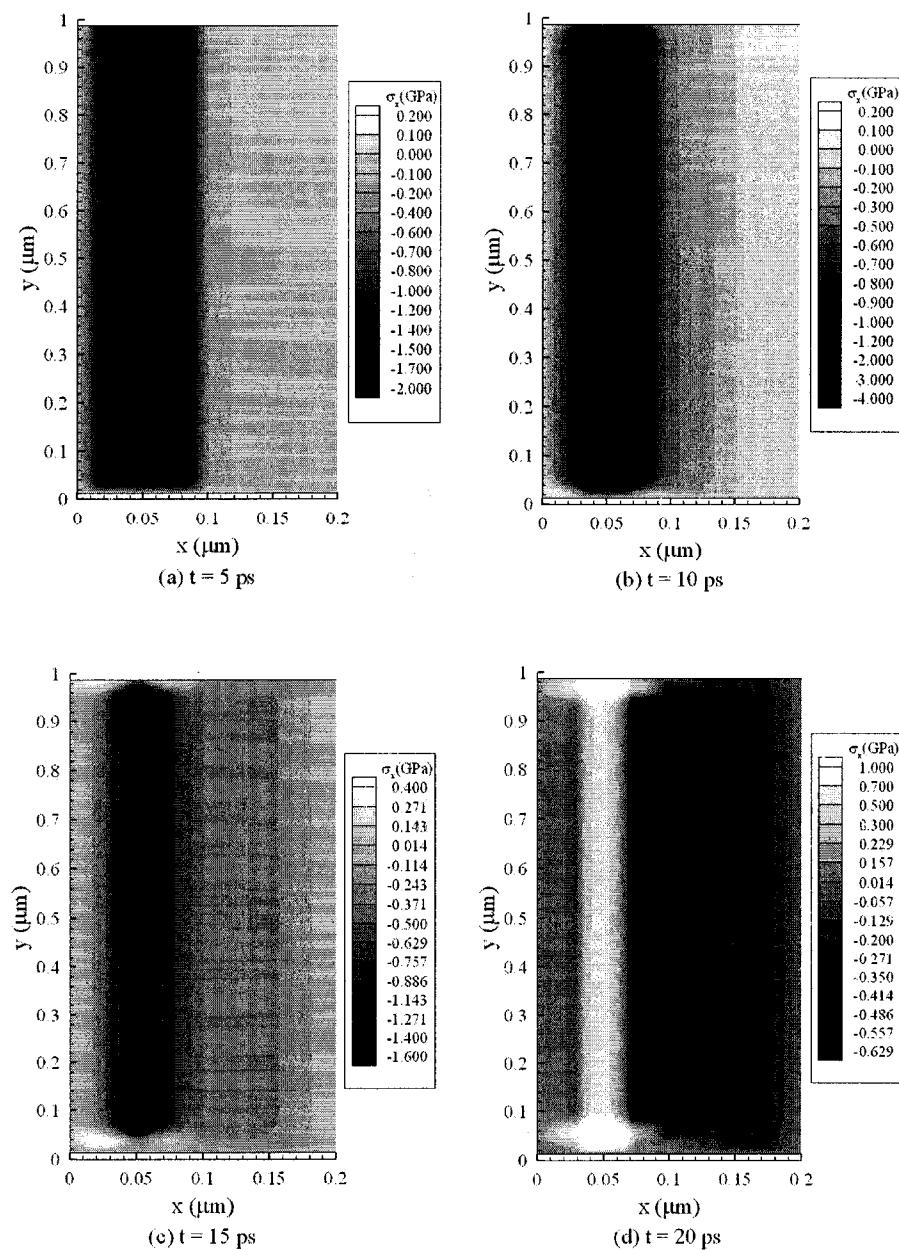


Fig. 5.36 Normal stress (σ_x) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

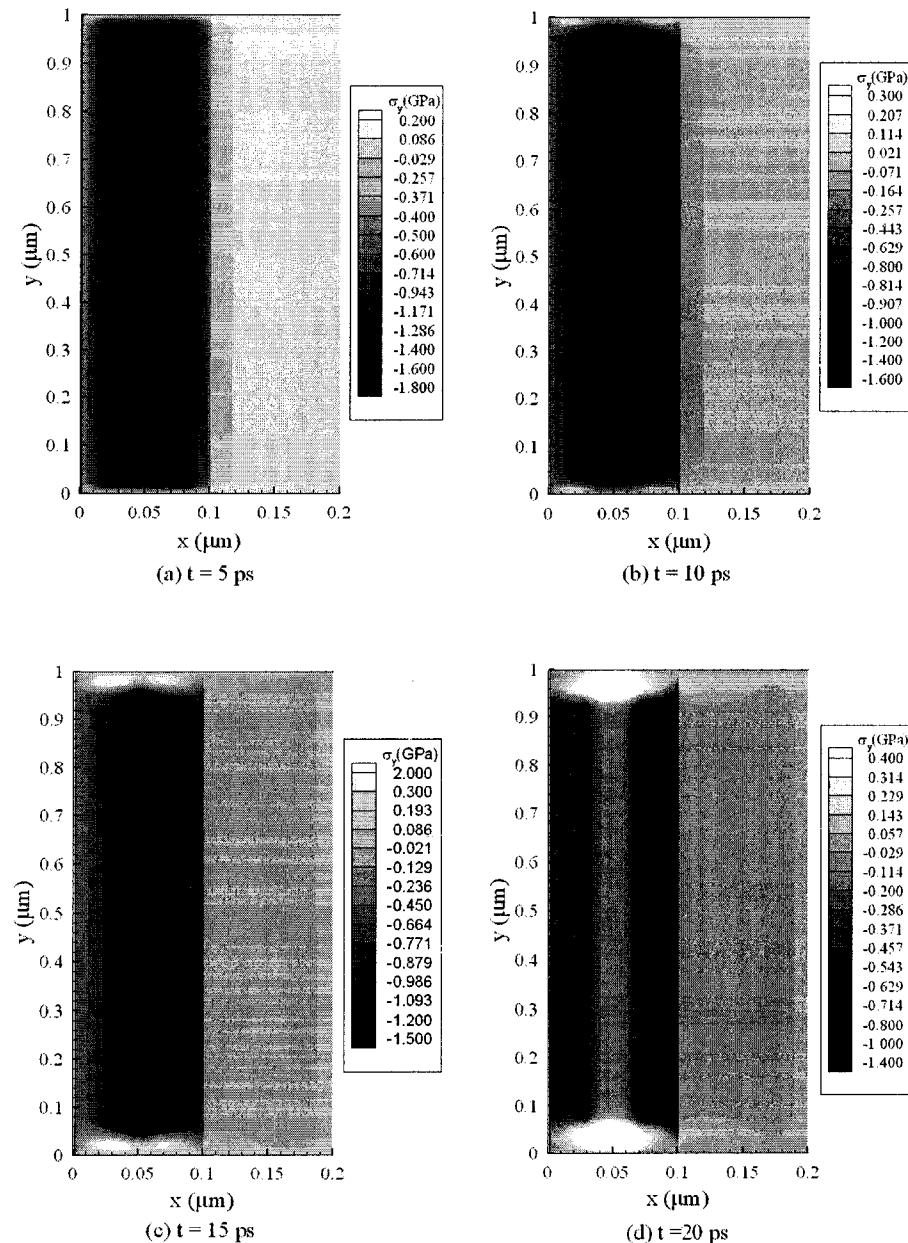


Fig. 5.37 Normal stress (σ_y) profiles at different times with laser fluence $J = 1000 \text{ J m}^{-2}$.

The analysis of displacement and stress waves reveals the significance of the hot-electron blast effect on the ultrafast deformation mainly along the thickness direction. Furthermore, the proposed methodology allows us to obtain the solution free from non-physical oscillations.

CHAPTER SIX

SUMMARY AND CONCLUSION

In this dissertation, we have done several things as follows: (1) reviewed several mathematical models for microscale heat transfer, classical thermomechanics, and ultrafast thermomechanics, (2) set up mathematical models for a single-layered thin film and a double-layered thin film with perfectly thermal contact at interface and imperfectly thermal contact at interface (the model consists of dynamic equations of motion and parabolic two-step heat transport equations), (3) developed an implicit finite difference method with second-order truncation error by employing a staggered grid for studying thermal deformation in microscale thin film exposed to ultrashort pulsed lasers (the scheme is unconditionally stable), and (4) applied the numerical method to investigate the thermal deformation in a single-layered gold thin film and gold layer padding on chromium layer thin film with perfectly thermal contact at interface and imperfectly thermal contact at interface. Numerical results show the significance of the hot-electron blast effect on the ultrafast deformation mainly along the thickness direction. Furthermore, the proposed methodology allows us to obtain the solution free from non-physical oscillations.

Future studies will consist of extending our mathematical model and numerical method to solve thermal deformation in a three-dimensional multi-layered microscale

thin film and microsphere, which are important components in the fabrication of many microelectronic devices, analyzing the thermal damage induced by ultrashort-pulsed lasers, and developing higher order (fourth-order) methods based on the current method (second-order). Such future research will offer a more complete understanding of microscale heat transfer and thermal deformation for microscale thin film and microsphere irradiated by ultrashort-pulsed-high-intensity lasers.

APPENDIX

SOURCE CODE OF THE NUMERICAL

METHOD

A.1 Source Code for Single-Layered Thin Film

```

c All the units are SI
c Program main
    implicit double precision (a-h,l,o-z)
    dimension t(4001),t1(4001),x(400),y(200)
    dimension
    eto(400,200),etn(400,200),lto(400,200),ltn(400,200),
    $ etm(4001),ltm(4001),u1m(4001),u2m(4001),
    v1m(4001),v2m(4001),
    $ xsao(401,201),ysao(401,201),ssao(401,201),
    $ xsao(401,201),ysao(401,201),ssao(401,201),
    $ xsan(401,201),ysan(401,201),ssan(401,201),
    $ xseo(401,201),yseo(401,201),sse(401,201),
    $ xsen(401,201),ysen(401,201),ssen(401,201),
    $
    v1o(401,201),v2o(401,201),v1n(401,201),v2n(401,201),
    $
    u1o(401,201),u2o(401,201),u1n(401,201),u2n(401,201)
c   $
c   u1xt(401,4001),xsext(401,4001),u2xt(401,4001),ysext(4
01,4001),
c   $ u1xt1(401,4001),xsext1(401,4001),
c   $ u2xt1(401,4001),ysext1(401,4001)
c
c
c     integer p, counter
c
c
c Lame constant
    lemta=199.0d+9
c Shear modulus
    cmiu=27.0d+9
c Thermal expansion coefficient
    alphat=14.2d-6
c Density
    lou=1.93d+4
    theta=1.0
c
c
    lx=1.0D-7
    ly=1.0D-6
    n=40
    m=20
    h1=lx/n
    h2=ly/m
    p=400
    dt=0.005d-12
    counter=0
    t(1)=0
    x(1)=0
    y(1)=0
c
c initial condition
c
    k=1
    do j=1,m+1
    do i=1,n+1
    eto(i,j)=300.0
    lto(i,j)=300.0
    xsao(i,j)=0.0
    ysao(i,j)=0.0
    ssao(i,j)=0.0
    xsao(1,j)=0.0
    ysao(1,j)=0.0
    ssao(1,j)=0.0
    xseo(i,j)=0.0
    yseo(i,j)=0.0
    sseo(i,j)=0.0
    v1o(i,j)=0.0
    v2o(i,j)=0.0
    u1o(i,j)=0.0
    u2o(i,j)=0.0
    end do
    end do
    etm(k)=300.0
    ltm(k)=300.0
c
    do j=2,m+1
    y(j)=y(j-1)+h2
    end do
    do i=2,n+1
    x(i)=x(i-1)+h1
    end do
c
    write(*,*) 'start'
c
c
    do 1 k=2,p+1
c
    t(k)=t(k-1)+dt
    t1(k)=t(k-1)+dt/2.0
c
c
    do j=1,m+1
    do i=1,n+1
    xsan(i,j)=xsao(i,j)
    ysan(i,j)=ysao(i,j)
    enddo
    enddo
c
    tol=1d-16
    detuvmax=tol+1d-5
    do while (detuvmax.gt.tol)
    detuvmax=0.0
c
c Call the subroutine to compute temperature
c
    call temp(n,m,h1,h2,x,y,t1(k),dt,lto,ltn,eto,etn,
    $           xsan,ysan,xsao,ysao)
c
c
c Compute stress
c
c
    do j=1,m+1
    xsen(1,j)=0.0
    xsen(n+1,j)=0.0
    end do
c
    do i=1,n+1

```

```

ysen(i,1)=0.0
ysen(i,m+1)=0.0
end do
c
do j=2,m
do i=2,n
xsen(i,j)=(lemta+2.0*cmiu)*xsan(i,j)+lemta*ysan(i,j)
$ -(3.0*lemta+2.0*cmiu)*alphat*(ltn(i,j)-300.0)
c
ysen(i,j)=lemta*xsan(i,j)+(lemta+2.0*cmiu)*ysan(i,j)
$ -(3.0*lemta+2.0*cmiu)*alphat*(ltn(i,j)-300.0)
c
end do
end do
c
do j=1,m
ssen(1,j)=0.0
ssen(n,j)=0.0
end do
do i=2,n-1
ssen(i,1)=0.0
ssen(i,m)=0.0
end do
c
do j=2,m-1
do i=2,n-1
ssen(i,j)=cmiu*ssan(i,j)
end do
end do
c
c
c Calculate velocity
c
c
call velocity(n,m,h1,h2,dt,eto,etn,xseo,yseo,sseo,
$ xsen,ysen,ssen,v1o,v2o,v1n,v2n,u1o,u2o,u1n,u2n)
c
c
c Calculate strain
c
c
do j=2,m
do i=2,n
xsan(i,j)=((theta*(v1n(i,j)-v1n(i-1,j)))
$ +(1.0-theta)*(v1o(i,j)-v1o(i-1,j)))/h1
$ *dt+xsao(i,j)
c
ysan(i,j)=((theta*(v2n(i,j)-v2n(i,j-1)))
$ +(1.0-theta)*(v2o(i,j)-v2o(i,j-1)))/h2
$ *dt+ysao(i,j)
end do
end do
c
c Shear strain
c
do j=2,m-1
do i=2,n-1
ssan(i,j)=((theta*(v1n(i,j+1)-v1n(i,j)))
$ +(1.0-theta)*(v1o(i,j+1)-v1o(i,j)))/h2
$ +(theta*(v2n(i+1,j)-v2n(i,j)))
$ +(1.0-theta)*(v2o(i+1,j)-v2o(i,j)))/h1
$ *dt+ssao(i,j)
c
end do
c
c Completion of calculation of strain
c
do j=1,m+1
do i=1,n+1
det1=xsan(i,j)-xsao(i,j)
det2=ysan(i,j)-ysao(i,j)
det3=ssan(i,j)-ssao(i,j)
det=max(abs(det1),abs(det2),abs(det3))
if( abs(det).gt.detuvmax) detuvmax=abs(det)
end do
end do
c
do j=1,m+1
do i=1,n+1
xsao(i,j)=xsan(i,j)
ysao(i,j)=ysan(i,j)
ssao(i,j)=ssan(i,j)
end do
end do
c
write(*,*) 'detuvmax=', detuvmax
c
c End do with deimax
c
end do
c
c
c
do j=1,m+1
do i=1,n+1
eto(i,j)=etn(i,j)
lto(i,j)=ltn(i,j)
xsao(i,j)=xsan(i,j)
ysao(i,j)=ysan(i,j)
ssao(i,j)=ssan(i,j)
xseo(i,j)=xsen(i,j)
yseo(i,j)=ysen(i,j)
sseo(i,j)=ssen(i,j)
v1o(i,j)=v1n(i,j)
v2o(i,j)=v2n(i,j)
u1o(i,j)=u1n(i,j)
u2o(i,j)=u2n(i,j)
end do
end do
c
etm(k)=etn(1,1)
ltm(k)=ltn(1,1)
u1m(k)=u1n(1,2)
u2m(k)=u2n(2,1)
v1m(k)=v1n(1,2)
v2m(k)=v2n(2,1)
c
c
c do i=1,n+1
c u1xt(i,k)=u1n(i,2)
c sext(i,k)=xsen(i,2)
c u2xt(i,k)=u2n(i,2)
c ysext(i,k)=ysen(i,2)

```

```

c   end do
c
c
c   do i=1,m+1
c     u1xt1(i,k)=u1n(2,i)
c     xsext1(i,k)=xsen(2,i)
c     u2xt1(i,k)=u2n(2,i)
c     ysext1(i,k)=ysen(2,i)
c   end do
c
c
c   counter=counter+1
c   write(*,*) counter
c
c
c Output intermediate result
c
c
c   if (k.eq.50) then
c
c The result at time t=0.25ps
c
c   open(unit=9,file='etn01.txt')
c   do j=1,81
c     write(9,1010) (etn(i,j),i=1,n+1)
c   enddo
c
c   open(unit=10,file='ltn01.txt')
c   do j=1,81
c     write(10,1010) (ltn(i,j),i=1,n+1)
c   enddo
c   end if
c
c
c   if (k.eq.100) then
c
c The result at time t=0.5ps
c
c   open(unit=11,file='etn02.txt')
c   do j=1,81
c     write(11,1010) (etn(i,j),i=1,n+1)
c   enddo
c
c   open(unit=12,file='ltn02.txt')
c   do j=1,81
c     write(12,1010) (ltn(i,j),i=1,n+1)
c   enddo
c   end if
c
c
c   if (k.eq.200) then
c
c The result at time t=1ps
c
c   open(unit=15,file='etn03.txt')
c   do j=1,81
c     write(15,1010) (etn(i,j),i=1,n+1)
c   enddo
c
c   open(unit=16,file='ltn03.txt')
c   do j=1,81
c     write(16,1010) (ltn(i,j),i=1,n+1)
c   enddo
c
c
c   open(unit=17,file='un01.txt')
c   do j=2,80
c     write(17,1010) (u1n(i,j),i=1,n)
c   enddo
c
c   open(unit=18,file='vn01.txt')
c   do j=1,80
c     write(18,1010) (u2n(i,j),i=2,n)
c   enddo
c
c   open(unit=19,file='xse01.txt')
c   do j=2,80
c     write(19,1010) (xsen(i,j),i=1,n+1)
c   enddo
c
c   open(unit=20,file='yse01.txt')
c   do j=1,81
c     write(20,1010) (ysen(i,j),i=2,n)
c   enddo
c
c   end if
c
c   if (k.eq.400) then
c
c The result at time t=2ps
c
c   open(unit=13,file='etn04.txt')
c   do j=1,81
c     write(13,1010) (etn(i,j),i=1,n+1)
c   enddo
c
c   open(unit=14,file='ltn04.txt')
c   do j=1,81
c     write(14,1010) (ltn(i,j),i=1,n+1)
c   enddo
c   end if
c
c
c   if (k.eq.1000) then
c
c The result at time t=5ps
c
c   open(unit=21,file='etn1.txt')
c   do j=1,81
c     write(21,1010) (etn(i,j),i=1,n+1)
c   enddo
c
c   open(unit=22,file='ltn1.txt')
c   do j=1,81
c     write(22,1010) (ltn(i,j),i=1,n+1)
c   enddo
c
c   open(unit=23,file='un1.txt')
c   do j=2,80
c     write(23,1010) (u1n(i,j),i=1,n)
c   enddo
c
c   open(unit=24,file='vn1.txt')
c   do j=1,80
c

```

```

        write(24,1010) (u2n(i,j),i=2,n)
        enddo
c
c      open(unit=25,file='xse1.txt')
c      do j=2,80
c      write(25,1010) (xsen(i,j),i=1,n+1)
c      enddo
c
c      open(unit=26,file='yse1.txt')
c      do j=1,81
c      write(26,1010) (ysen(i,j),i=2,n)
c      enddo
c
c      end if
c
c
c the result at time t=10ps
c
c
c      if (k.eq.2000) then
c      open(unit=27,file='etn2.txt')
c      do j=1,81
c      write(27,1010) (etn(i,j),i=1,n+1)
c      enddo
c
c      open(unit=28,file='ltn2.txt')
c      do j=1,81
c      write(28,1010) (ltn(i,j),i=1,n+1)
c      enddo
c
c      open(unit=29,file='un2.txt')
c      do j=2,80
c      write(29,1010) (u1n(i,j),i=1,n)
c      enddo
c
c      open(unit=30,file='vn2.txt')
c      do j=1,80
c      write(30,1010) (u2n(i,j),i=2,n)
c      enddo
c
c      open(unit=31,file='xse2.txt')
c      do j=2,80
c      write(31,1010) (xsen(i,j),i=1,n+1)
c      enddo
c
c      open(unit=32,file='yse2.txt')
c      do j=1,81
c      write(32,1010) (ysen(i,j),i=2,n)
c      enddo
c
c      end if
c
c
c the result at time t=15ps
c
c
c      if (k.eq.3000) then
c      open(unit=33,file='etn3.txt')
c      do j=1,81
c      write(33,1010) (etn(i,j),i=1,n+1)
c      enddo
c
c      open(unit=34,file='ltn3.txt')
c      do j=1,81
c      write(34,1010) (ltn(i,j),i=1,n+1)
c      enddo
c
c      open(unit=35,file='un3.txt')
c      do j=2,80
c      write(35,1010) (u1n(i,j),i=1,n)
c      enddo
c
c      open(unit=36,file='vn3.txt')
c      do j=1,80
c      write(36,1010) (u2n(i,j),i=2,n)
c      enddo
c
c      open(unit=37,file='xse3.txt')
c      do j=2,80
c      write(37,1010) (xsen(i,j),i=1,n+1)
c      enddo
c
c      open(unit=38,file='yse3.txt')
c      do j=1,81
c      write(38,1010) (ysen(i,j),i=2,n)
c      enddo
c
c      end if
c
c
c      i end do
c
c      open(unit=39,file='etn4.txt')
c      do j=1,81
c      write(39,1010) (etn(i,j),i=1,n+1)
c      enddo
c
c      open(unit=40,file='ltn4.txt')
c      do j=1,81
c      write(40,1010) (ltn(i,j),i=1,n+1)
c      enddo
c
c      open(unit=41,file='eltm3.txt')
c      do k=1,p+1
c      write(41,1020) t(k),etm(k),lrm(k)
c      enddo
c
c      open(unit=42,file='xse4.txt')
c      do j=2,80
c      write(42,1010) (xsen(i,j),i=1,n+1)
c      enddo
c
c      open(unit=43,file='yse4.txt')
c      do j=1,81
c      write(43,1010) (ysen(i,j),i=2,n)
c      enddo
c
c      open(unit=44,file='um3.txt')
c      do k=1,p+1
c      write(44,1020) t(k),u1m(k),u2m(k)
c      enddo
c

```

```

open(unit=45,file='vm3.txt')
do k=1,p+1
write(45,1020) t(k),v1m(k),v2m(k)
enddo
c
c   open(unit=46,file='un4.txt')
do j=2,80
write(46,1010) (u1n(i,j),i=1,n)
enddo
c
c   open(unit=47,file='vn4.txt')
do j=1,80
write(47,1010) (u2n(i,j),i=2,n)
enddo
c
c
c   1010    format(401e15.6)
1020    format(e15.6,2e15.6)
c
      end

      subroutine temp(n,m,h1,h2,x,y,t,dt,lto,ln,eto,etn,
$      xsan,ysan,xsao,ysao)
c
      implicit double precision (a-h,l,o-z)
      dimension x(400),y(200)
      dimension
      eto(400,200),etn(400,200),lto(400,200),ln(400,200),
$      ewein(400,200),oldet(400,200),oldlt(400,200),
$      xsan(401,201),ysan(401,201),
$      xsao(401,201),ysao(401,201)
c
      integer iteration
c
c
c Lame constant
      lennta=199.0d+9
c Shear modulus
      cmiu=27.0d+9
c Thermal expansion coefficient
      alphat=14.2d-6
c Electron heat capacity
      ce0=2.1d+4
c Lattice heat capacity
      cl=2.5d+6
c Electron - lattic coupling factor
      g=2.6d+16
c Electron thermal conductivity
      cke0=315.0
c Laser fluence
      flu=500.0
c Laser pulse duration
      tp=0.1d-12
c Optical penetration depth
      delta=15.3d-9
c Surface reflectivity
      sur=0.93
c Spatial profile parameters
      rs=1d-6
c
iteration=0
d=g*dt/(2.0*cl)
ee=(3.0*lemta+2.0*cmiu)*alphat/cl
c
c   write(*,*) x
c   pause
do j=1,m+1
do i=1,n+1
oldet(i,j)=eto(i,j)
oldlt(i,j)=lto(i,j)
end do
end do
c
tol=1e-3
detmax=tol+0.001
do while (detmax.gt.tol)
c
detmax=0.0
do j=2,m
do i=2,n
q=0.94*flu*(1.0-sur)/(tp*delta)
$      *exp(-x(i)/delta-y(j)*y(j)/(rs*rs))
$      -2.77*(t-2.0*tp)*(t-2.0*tp)/(tp*tp))
c
a=cke0*(eto(i,j)+oldet(i,j))/(2.0*300.0)
b1=cke0*(oldet(i+1,j)/oldlt(i+1,j)+oldet(i,j)/oldlt(i,j))
$      /(4.0*h1*h1)*dt
b2=cke0*(oldet(i,j)/oldlt(i,j)+oldet(i-1,j)/oldlt(i-1,j))
$      /(4.0*h1*h1)*dt
b3=cke0*(oldet(i,j+1)/oldlt(i,j+1)+oldet(i,j)/oldlt(i,j))
$      /(4.0*h2*h2)*dt
b4=cke0*(oldet(i,j)/oldlt(i,j)+oldet(i,j-1)/oldlt(i,j-1))
$      /(4.0*h2*h2)*dt
c
c1=cke0*(eto(i+1,j)/lto(i+1,j)+eto(i,j)/oldlt(i,j))
$      /(4.0*h1*h1)*dt
c2=cke0*(eto(i,j)/lto(i,j)+eto(i-1,j)/lto(i-1,j))
$      /(4.0*h1*h1)*dt
c3=cke0*(eto(i,j+1)/lto(i,j+1)+eto(i,j)/lto(i,j))
$      /(4.0*h2*h2)*dt
c4=cke0*(eto(i,j)/lto(i,j)+eto(i,j-1)/lto(i,j-1))
$      /(4.0*h2*h2)*dt
c
ewetn(i,j)=(b1*oldet(i+1,j)+b2*oldet(i-1,j)
$      +b3*oldet(i,j+1)+b4*oldet(i,j-1)
$      +g*dt*etn(i,j)-lto(i,j))/(2.0*(1.0+d))
$      +g*dt*lto(i,j)/(2.0*(1.0+d))
$      -g*dt*ee*((xsan(i,j)+ysan(i,j))-
(xsao(i,j)+ysao(i,j)))
$      /(2.0*(1.0+d))
$      +c1*(eto(i+1,j)-eto(i,j))-c2*(eto(i,j)-eto(i-1,j))
$      +c3*(eto(i,j+1)-eto(i,j))-c4*(eto(i,j)-eto(i,j-1))
$      -g*dt*(eto(i,j)-lto(i,j))/2.0+q*dt+a*eto(i,j))
$      /(a+b1+b2+b3+b4+g*dt/2.0-g*dt*d/(2.0*(1.0+d)))
c
det=ewetn(i,j)-oldet(i,j)
if (abs(det).gt.detmax) detmax=abs(det)
oldet(i,j)=ewetn(i,j)
end do
end do
c
c   do j=2,m

```

```

c   do i=2,n
c   det=ewetn(i,j)-oldet(i,j)
c   if (abs(det).gt.detmax) detmax=abs(det)
c   oldet(i,j)=ewetn(i,j)
c   end do
c   end do
c
do j=1,m+1
oldet(1,j)=oldet(2,j)
oldet(n+1,j)=oldet(n,j)
end do
c
do i=1,n+1
oldet(i,1)=oldet(i,2)
oldet(i,m+1)=oldet(i,m)
end do
c
do j=1,m+1
do i=1,n+1
oldlt(i,j)=d/(1.0+d)*oldet(i,j)+d/(1.0+d)*(eto(i,j)-
lto(i,j))
$      +1.0/(1.0+d)*lto(i,j)
$      -ee/(1.0+d)
$      *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
end do
end do
c
iteration=iteration+1
c
end do

write(*,*) 'iteration=',iteration

do j=1,m+1
do i=1,n+1
etn(i,j)=oldet(i,j)
end do
end do
c
do j=2,m
do i=1,n
v1n(i,j)=((theta*(xsen(i+1,j))-xsen(i,j))
$ +(1.0-theta)*(xseo(i+1,j)-xseo(i,j)))/(h1)
$ +(theta*(ssen(i,j)-ssen(i,j-1)))
$ +(1.0-theta)*(sseo(i,j)-sseo(i,j-1)))/(h2)
$ +tri*theta*(etn(i+1,j)*etn(i+1,j)-
etn(i,j)*etn(i,j))/(h1)
$ +tri*(1.0-theta)*(eto(i+1,j)*eto(i+1,j)-
eto(i,j)*eto(i,j))
$ /(h1))*dt/lou+v1o(i,j)
c
u1n(i,j)=(theta*v1n(i,j)+(1.0-
theta)*v1o(i,j))*dt+u1o(i,j)
end do
end do
c
do j=1,m
do i=2,n
v2n(i,j)=((theta*(ssen(i,j)-ssen(i-1,j)))
$ +(1.0-theta)*(sseo(i,j)-sseo(i-1,j)))/(h1)
$ +(theta*(ysen(i,j+1)-ysen(i,j)))
$ +(1.0-theta)*(yseo(i,j+1)-yseo(i,j)))/(h2)
$ +tri*theta*(etn(i,j+1)*etn(i,j+1)-
etn(i,j)*etn(i,j))/(h2)
$ +tri*(1.0-theta)*(eto(i,j+1)*eto(i,j+1)-
eto(i,j)*eto(i,j))
$ /(h2))
$ *dt/lou+v2o(i,j)
c
u2n(i,j)=(theta*v2n(i,j)+(1.0-
theta)*v2o(i,j))*dt+u2o(i,j)
end do
end do
c
return
end

```

A.2 Source Code for Double-Layered Thin Film with Perfectly Interfacial Thermal Contact

```

c All the units are SI
c Program main
    implicit double precision (a-h,l,o-z)
    dimension t(4001),tl(4001),x(401),y(201)
    dimension
    eto(401,201),etn(401,201),lto(401,201),ltn(401,201),
    $ etm(4001),ltm(4001),u1m(4001),u2m(4001),
    v1m(4001),v2m(4001),
    $ xsao(401,201),ysao(401,201),ssao(401,201),
    $ xsao(401,201),ysao(401,201),ssao(401,201),
    $ xsan(401,201),ysan(401,201),ssan(401,201),
    $ xseo(401,201),yseo(401,201),sse(401,201),
    $ xsen(401,201),ysen(401,201),ssen(401,201),
    $
    v1o(401,201),v2o(401,201),v1n(401,201),v2n(401,201),
    $
    u1o(401,201),u2o(401,201),u1n(401,201),u2n(401,201)
    c
    c
    ulxt(401,2001),xsext(401,2001),u2xt(401,2001),ysext(4
    01,2001),
    c   $ ulxt(401,2001),xsext(401,2001),
    c   $ u2xt(401,2001),ysext(401,2001)
    c
    integer p, counter
    c
    c
c Gold lame constant
    lemta1=199.0d+9
c Gold shear modulus
    cmiu1=27.0d+9
c Gold thermal expansion coefficient
    alphat1=14.2d-6
c Gold density
    lou1=1.93d+4
    c
c Chromium lame constant
    lemta2=83.3d+9
c Chromium shear modulus
    cmiu2=115.0d+9
c Chromium thermal expansion coefficient
    alphat2=4.9d-6
c Chromium density
    lou2=7.19d+3
    c
    lx=1.0D-7
    ly=1.0D-6
    n=160
    m=80
    h1=lx/n
    h2=ly/m
    p=4000
    dt=0.005d-12
    counter=0
    t(1)=0
    x(1)=0
    do i=1,2,n+1
        eto(i,j)=300.0
        lto(i,j)=300.0
        xsao(i,j)=0.0
        ysao(i,j)=0.0
        ssao(i,j)=0.0
        xsao(1,j)=0.0
        ysao(1,j)=0.0
        ssao(1,j)=0.0
        xseo(i,j)=0.0
        yseo(i,j)=0.0
        sseo(i,j)=0.0
        v1o(i,j)=0.0
        v2o(i,j)=0.0
        u1o(i,j)=0.0
        u2o(i,j)=0.0
        end do
        end do
        etm(k)=300.0
        ltm(k)=300.0
    c
    do j=2,m+1
        y(j)=y(j-1)+h2
    end do
    do i=2,2*n+1
        x(i)=x(i-1)+h1
    end do
    c
    write(*,*) 'start'
    c
    c
    c
    do k=2,p+1
    c
    c
    c
    do j=1,m+1
        do i=1,2*n+1
            xsan(i,j)=xsao(i,j)
            ysan(i,j)=ysao(i,j)
        enddo
        enddo
        c
        do j=1,m
            do i=1,2*n
                ssan(i,j)=ssao(i,j)
            end do
            end do
            c
            tol=1d-14
            detuvmax=tol+1d-5
            do while (detuvmax.gt.tol)
                detuvmax=0.0
            c
            t(k)=t(k-1)+dt

```

```

t1(k)=t(k-1)+dt/2.0
c
c c Call the subroutine to compute temperature
c
call temp(n,m,h1,h2,x,y,t1(k),dt,lto,ltm,etn,
$      xsan,ysan,xsao,ysao)
c
do j=1,m+1
do i=1,2*n+1
xsan(i,j)=xsao(i,j)
ysan(i,j)=ysao(i,j)
enddo
enddo
c
c
do j=1,m
do i=1,2*n
ssan(i,j)=ssao(i,j)
end do
end do
c
c
tol=1d-14
detuvmax=tol+1d-5
do while (detuvmax.gt.tol)
detuvmax=0.0
c
c
c Compute stress
c
c
do j=1,m+1
xsen(1,j)=0.0
xsen(2*t1+1,j)=0.0
end do
c
do i=1,2*n+1
ysen(i,1)=0.0
ysen(i,m+1)=0.0
end do
c
do j=2,m
c
c The thin film of gold
c
do i=2,n
ssen(i,j)=cmiu1*ssan(i,j)
end do
c
c The thin film of chromium
c
do i=n+1,2*n-1
ssen(i,j)=cmiu2*ssan(i,j)
end do
c
end do
c
ssen(n,1)=cmiu1*ssan(n,1)
ssen(n,m)=cmiu1*ssan(n,m)
ssen(n+1,1)=cmiu2*ssan(n+1,1)
ssen(n+1,m)=cmiu2*ssan(n+1,m)
c
c
c Calculate velocity
c
c
call velocity(n,m,h1,h2,dt,etn,ltm,
$      xsen,ysen,ssen,xsao,ysao,ssao,v1o,v2o,v1n,v2n,u1o,u2o,
u1n,u2n)
c
c
c Calculate strain
c
c
do j=2,m
c
c The thin film of gold
c

```

```

do i=2,n
  xsan(i,j)=((v1n(i,j)-v1n(i-1,j))/h1)
  $ *dt+xsao(i,j)
c
  ysan(i,j)=((v2n(i,j)-v2n(i,j-1))/h2)
  $ *dt+ysao(i,j)
  end do
c
c At interface
c
  xsan(n+1,j)=((v1n(n+1,j)-v1n(n,j))*2.0/h1)
  $ *dt+xsao(i,j)
c
  ysan(n+1,j)=((v2n(n+1,j)-v2n(n+1,j-1))/h2)
  $ *dt+ysao(i,j)
c
c The thin film of chromium
c
  do i=n+2,2*n
    xsan(i,j)=((v1n(i+1,j)-v1n(i,j))/h1)
    $ *dt+xsac(i,j)
  c
    ysan(i,j)=((v2n(i,j)-v2n(i,j-1))/h2)
    $ *dt+ysao(i,j)
    end do
  c
    end do
c
c
c Shear strain
c
  do j=2,m-1
c
c The thin film of gold
c
  do i=2,n
    ssan(i,j)=((v1n(i,j+1)-v1n(i,j))/h2
    $ +(v2n(i+1,j)-v2n(i,j))/h1)
    $ *dt+ssao(i,j)
    end do
c
c The thin film of chromium
c
  do i=n+1,2*n-1
    ssan(i,j)=((v1n(i+1,j+1)-v1n(i+1,j))/h2
    $ +(v2n(i+1,j)-v2n(i,j))/h1)
    $ *dt+ssao(i,j)
    end do
c
  end do
c
  ssan(n,1)=((v1n(n,2)-v1n(n,1))/h2
  $ +(v2n(n+1,1)-v2n(n,1))/h1)
  $ *dt+ssao(n,1)
  ssan(n,m)=((v1n(n,m+1)-v1n(n,m))/h2
  $ +(v2n(n+1,m)-v2n(n,m))/h1)
  $ *dt+ssao(n,m)
  ssan(n+1,1)=((v1n(n+2,2)-v1n(n+2,1))/h2
  $ +(v2n(n+2,1)-v2n(n+1,1))/h1)
  $ *dt+ssao(n+1,1)
  ssan(n+1,m)=((v1n(n+2,m+1)-v1n(n+2,m))/h2
  $ +(v2n(n+2,m)-v2n(n+1,m))/h1)
c
c
c *dt+ssao(n+1,m)
c
c Completion of calculation of strain
c
  do j=1,m+1
  do i=1,2*n-1
    det1=xсан(i,j)-xsao(i,j)
    det2=ysан(i,j)-ysao(i,j)
    det3=ssан(i,j)-ssao(i,j)
    det=max(abs(det1),abs(det2),abs(det3))
    if( abs(det).gt.detuvmax) detuvmax=abs(det)
    end do
  end do
c
  do j=1,m+1
  do i=1,2*n-1
    xsao(i,j)=xсан(i,j)
    ysao(i,j)=ysан(i,j)
    ssao(i,j)=ssан(i,j)
    end do
  end do
c
  write(*,*) 'detuvmax=', detuvmax
c
c End do with detmax
c
  end do
c-----
```

```

  do j=1,m+1
  do i=1,2*n-1
    eto(i,j)=etn(i,j)
    lto(i,j)=ltn(i,j)
    xsao(i,j)=xсан(i,j)
    ysao(i,j)=ysан(i,j)
    ssao(i,j)=ssан(i,j)
    xseo(i,j)=xsen(i,j)
    yseo(i,j)=ysen(i,j)
    sseo(i,j)=ssen(i,j)
    v1o(i,j)=v1n(i,j)
    v2o(i,j)=v2n(i,j)
    u1o(i,j)=u1n(i,j)
    u2o(i,j)=u2n(i,j)
    end do
  end do
c
  etm(k)=etn(1,1)
  ltm(k)=ltn(1,1)
  u1m(k)=u1n(1,2)
  u2m(k)=u2n(2,1)
  v1m(k)=v1n(1,2)
  v2m(k)=v2n(2,1)
c
c
c do i=1,2*n+1
c   u1xt(i,k)=u1n(i,2)
c   xsext(i,k)=xsen(i,2)
c   u2xt(i,k)=u2n(i,2)
c   ysext(i,k)=ysen(i,2)
c   end do
c
```

```

c   do i=1,m+1                           end if
c     u1xt1(i,k)=u1n(2,i)                 c
c     xsext1(i,k)=xsen(2,i)               c
c     u2xt1(i,k)=u2n(2,i)                 c
c     ysext1(i,k)=ysen(2,i)               c
c   end do

c
c
c
c   counter=counter+1
c   write(*,*) counter
c
c
c Output intermediate result
c
c
c   if (k.eq.50) then
c
c The result at time t=0.25ps
c
c   open(unit=9,file='etn01.dat')
c   do j=1,m+1
c     write(9,1010) (etn(i,j),i=1,2*n+1)
c   enddo

c   open(unit=10,file='ltn01.dat')
c   do j=1,m+1
c     write(10,1010) (ltn(i,j),i=1,2*n+1)
c   enddo
c   end if

c
c
c   if (k.eq.100) then
c
c The result at time t=0.5ps
c
c   open(unit=11,file='etn02.dat')
c   do j=1,m+1
c     write(11,1010) (etn(i,j),i=1,2*n+1)
c   enddo

c   open(unit=12,file='ltn02.dat')
c   do j=1,m+1
c     write(12,1010) (ltn(i,j),i=1,2*n+1)
c   enddo
c   end if

c
c
c   if (k.eq.400) then
c
c The result at time t=2ps
c
c   open(unit=13,file='etn03.dat')
c   do j=1,m+1
c     write(13,1010) (etn(i,j),i=1,2*n+1)
c   enddo

c   open(unit=14,file='ltn03.dat')
c   do j=1,m+1
c     write(14,1010) (ltn(i,j),i=1,2*n+1)
c   enddo

c   end if

c
c
c   if (k.eq.200) then
c
c The result at time t=1ps
c
c   open(unit=15,file='etn04.dat')
c   do j=1,m+1
c     write(15,1010) (etn(i,j),i=1,2*n+1)
c   enddo

c   open(unit=16,file='ltn04.dat')
c   do j=1,m+1
c     write(16,1010) (ltn(i,j),i=1,2*n+1)
c   enddo

c   open(unit=17,file='un01.dat')
c   do j=2,m
c     write(17,1010) (u1n(i,j),i=1,2*n+1)
c   enddo

c   open(unit=18,file='vn01.dat')
c   do j=1,m
c     write(18,1010) (u2n(i,j),i=2,2*n)
c   enddo

c   open(unit=19,file='xse01.dat')
c   do j=1,m+1
c     write(19,1010) (xsen(i,j),i=1,2*n+1)
c   enddo

c   open(unit=20,file='yse01.dat')
c   do j=1,m+1
c     write(20,1010) (ysen(i,j),i=1,2*n+1)
c   enddo

c   end if

c
c
c   if (k.eq.1000) then
c
c The result at time t=5ps
c
c   open(unit=21,file='etn1.dat')
c   do j=1,m+1
c     write(21,1010) (etn(i,j),i=1,2*n+1)
c   enddo

c   open(unit=22,file='ltn1.dat')
c   do j=1,m+1
c     write(22,1010) (ltn(i,j),i=1,2*n+1)
c   enddo

c   open(unit=23,file='un1.dat')
c   do j=2,m
c     write(23,1010) (u1n(i,j),i=1,2*n+1)
c   enddo

c   open(unit=24,file='vn1.dat')
c   do j=1,m
c

```

```

        write(24,1010) (u2n(i,j),i=2,2*n)
        enddo
c
        open(unit=25,file='xse1.dat')
        do j=1,m+1
        write(25,1010) (xsen(i,j),i=1,2*n+1)
        enddo
c
        open(unit=26,file='yse1.dat')
        do j=1,m+1
        write(26,1010) (ysen(i,j),i=1,2*n+1)
        enddo
c
        end if
c
c the result at time t=10ps
c
c
        if (k.eq.2000) then
        open(unit=27,file='etn2.dat')
        do j=1,m+1
        write(27,1010) (etn(i,j),i=1,2*n+1)
        enddo
c
        open(unit=28,file='ltn2.dat')
        do j=1,m+1
        write(28,1010) (ltn(i,j),i=1,2*n+1)
        enddo
c
        open(unit=29,file='un2.dat')
        do j=2,m
        write(29,1010) (u1n(i,j),i=1,2*n+1)
        enddo
c
        open(unit=30,file='vn2.dat')
        do j=1,m
        write(30,1010) (u2n(i,j),i=2,2*n)
        enddo
c
        open(unit=31,file='xse2.dat')
        do j=1,m+1
        write(31,1010) (xsen(i,j),i=1,2*n+1)
        enddo
c
        open(unit=32,file='yse2.dat')
        do j=1,m+1
        write(32,1010) (ysen(i,j),i=1,2*n+1)
        enddo
c
        end if
c
c the result at time t=15ps
c
c
        if (k.eq.3000) then
        open(unit=33,file='etn3.dat')
        do j=1,m+1
        write(33,1010) (etn(i,j),i=1,2*n+1)
        enddo
c
        open(unit=34,file='ltn3.dat')
        do j=1,m+1
        write(34,1010) (ltn(i,j),i=1,2*n+1)
        enddo
c
        open(unit=35,file='un3.dat')
        do j=2,m
        write(35,1010) (u1n(i,j),i=1,2*n+1)
        enddo
c
        open(unit=36,file='vn3.dat')
        do j=1,m
        write(36,1010) (u2n(i,j),i=2,2*n)
        enddo
c
        open(unit=37,file='xse3.dat')
        do j=1,m+1
        write(37,1010) (xsen(i,j),i=1,2*n+1)
        enddo
c
        open(unit=38,file='yse3.dat')
        do j=1,m+1
        write(38,1010) (ysen(i,j),i=1,2*n+1)
        enddo
c
        end if
c
c
        1 end do
c
        open(unit=39,file='etn4.dat')
        do j=1,m+1
        write(39,1010) (etn(i,j),i=1,2*n+1)
        enddo
c
        open(unit=40,file='ltn4.dat')
        do j=1,m+1
        write(40,1010) (ltn(i,j),i=1,2*n+1)
        enddo
c
        open(unit=41,file='eltm0.dat')
        do k=1,p+1
        write(41,1020) t(k),etm(k),ltm(k)
        enddo
c
        open(unit=42,file='xse4.dat')
        do j=1,m+1
        write(42,1010) (xsen(i,j),i=1,2*n+1)
        enddo
c
        open(unit=43,file='yse4.dat')
        do j=1,m+1
        write(43,1010) (ysen(i,j),i=1,2*n+1)
        enddo
c
        open(unit=44,file='um0.dat')
        do k=1,p+1
        write(44,1020) t(k),u1m(k),u2m(k)
        enddo

```

```

open(unit=45,file='vm3.dat')
do k=1,p1
write(45,1020) t(k),v1m(k),v2m(k)
enddo
c
c open(unit=46,file='un4.dat')
do j=2,m
write(46,1010) (u1n(i,j),j=1,2*n+1)
enddo
c
c open(unit=47,file='vn4.dat')
do j=1,m
write(47,1010) (u2n(i,j),j=2,2*n)
enddo
c
c
c 1010 format(401e15.6)
1020 format(e15.6,2e15.6)
c
      end

subroutine temp(n,m,h1,h2,x,y,t,dt,lto,ltm,eto,etn,
$      xsan,ysan,xsao,ysao)
c
implicit double precision (a-h,l,o-z)
dimension x(401),y(201)
dimension
eto(401,201),etn(401,201),lto(401,201),ltm(401,201),
$ ewetn(401,201),oldet(401,201),oldlt(401,201),
$ xsan(401,201),ysan(401,201),
$ xsao(401,201),ysao(401,201)
c
integer iteration
c
c
c
c Gold lame constant
lemta1=199.0d+9
c Gold shear modulus
cmiu1=27.0d+9
c Gold thermal expansion coefficient
alphat1=14.2d-6
c Gold electron heat capacity
ce01=2.1d+4
c Gold lattic heat capacity
cl1=2.5d+6
c Gold electron - lattic coupling factor
g1=2.6d+16
c Gold electron thermal conductivity
cke01=315.0
c
c
c Chromium lame constant
lemta2=83.3d+9
c Chromium shear modulus
cmiu2=115.0d+9
c Chromium thermal expansion coefficient
alphat2=4.9d-6
c Chromium electron heat capacity
ce02=5.8d+4
c Chromium lattic heat capacity
cl2=3.3d+6
c Chromium electron - lattic coupling factor
g2=4.2d+17
c Chromium electron thermal conductivity
cke02=94.0
c
c
c Laser fluence
flu=1000.0
c Laser pulse duration
tp=0.1d-12
c Optical penetration depth
delta=15.3d-9
c Surface reflectivity
sur=0.93
c Spatial profile parameters
rs=1d-6
c
c
iteration=0
d1=g1*dt/(2.0*cl1)
d2=g2*dt/(2.0*cl2)
ee1=(3.0*lemta1+2.0*cmiu1)*alphat1/cl1
ee2=(3.0*lemta2+2.0*cmiu2)*alphat2/cl2
c
do j=1,m+1
do i=1,2*n+1
oldet(i,j)=eto(i,j)
oldlt(i,j)=lto(i,j)
end do
end do
c
tol=1e-3
detmax=tol+0.001
do while (detmax.gt.tol)
c
detmax=0.0
do j=2,m
c
c Electron temperature at gold film
c
do i=2,n
q=0.94*flu*(1.0-sur)/(tp*delta)
$      *exp(-x(i)/delta-y(j)*y(j)/(rs*rs)
$      -2.77*(t-2.0*tp)*(t-2.0*tp)/(tp*tp))
c
a=ce01*(eto(i,j)+oldet(i,j))/(2.0*300.0)
b1=cke01*(oldet(i+1,j)/oldlt(i+1,j)+oldet(i,j)/oldlt(i,j))
$ /(4.0*h1*h1)*dt
b2=cke01*(oldet(i,j)/oldlt(i,j)+oldet(i-1,j)/oldlt(i-1,j))
$ /(4.0*h1*h1)*dt
b3=cke01*(oldet(i,j+1)/oldlt(i,j+1)+oldet(i,j)/oldlt(i,j))
$ /(4.0*h2*h2)*dt
b4=cke01*(oldet(i,j)/oldlt(i,j)+oldet(i,j-1)/oldlt(i,j-1))
$ /(2.0*h2*h2)*dt
c
c1=cke01*(eto(i+1,j)/lto(i+1,j)+eto(i,j)/oldlt(i,j))

```

```

$ /(4.0*h1*h1)*dt
c2=cke01*(eto(i,j)/lto(i,j)+eto(i-1,j)/lto(i-1,j))
$ /(4.0*h1*h1)*dt
c3=cke01*(eto(i,j+1)/lto(i,j+1)+eto(i,j)/lto(i,j))
$ /(4.0*h2*h2)*dt
c4=cke01*(eto(i,j)/lto(i,j)+eto(i,j-1)/lto(i,j-1))
$ /(2.0*h2*h2)*dt
c
ewtn(i,j)=(b1*oldet(i+1,j)+b2*oldet(i-1,j)
$ +b3*oldet(i,j+1)+b4*oldet(i,j-1)
$ +g1*dt*dt*(eto(i,j)-lto(i,j))/(2.0*(1.0+d1))
$ +g1*dt*lto(i,j)/(2.0*(1.0+d1))
$ -g1*dt*ee1*((xsan(i,j)+ysan(i,j))-xsao(i,j)+ysao(i,j)))
$ /(2.0*(1.0+d1))
$ +c1*(eto(i+1,j)-eto(i,j))-c2*(eto(i,j)-eto(i-1,j))
$ +c3*(eto(i,j+1)-eto(i,j))-c4*(eto(i,j)-eto(i,j-1))
$ -g1*dt*(eto(i,j)-lto(i,j))/2.0+q*dt+a*eto(i,j))
$ /(a+b1+b2+b3+b4+g1*dt/2.0-
g1*dt*d1/(2.0*(1.0+d1)))
c
c   write(*,*) ewtn(i,j),oldet(i,j)
c   pause
end do
c
c Electron temperature at interface i=n+1
c
b1=cke01*(oldet(n+1,j)/(oldlt(n+1,j)))
b2=cke02*(oldet(n+2,j)/(oldlt(n+2,j)))
ewtn(n+1,j)=(b1*oldet(i-
1,j)+b2*oldet(i+1,j))/(b1+b2)
c
c Electron temperature at chromium film
c
do i=n+2,2*n
q=0.94*flu*(1.0-sur)/(tp*delta)
$ *exp(-x(i)/delta-y(j)*y(j)/(rs*rs)
$ -2.77*(t-2.0*tp)*(t-2.0*tp)/(tp*tp))
c
a=ce02*(eto(i,j)+oldet(i,j))/(2.0*300.0)
b1=cke02*(oldet(i+1,j)/oldlt(i+1,j)+oldet(i,j)/oldlt(i,j))
$ /(4.0*h1*h1)*dt
b2=cke02*(oldet(i,j)/oldlt(i,j)+oldet(i-1,j)/oldlt(i-1,j))
$ /(4.0*h1*h1)*dt
b3=cke02*(oldet(i,j+1)/oldlt(i,j+1)+oldet(i,j)/oldlt(i,j))
$ /(4.0*h2*h2)*dt
b4=cke02*(oldet(i,j)/oldlt(i,j)+oldet(i,j-1)/oldlt(i,j-1))
$ /(2.0*h2*h2)*dt
c
c1=cke02*(eto(i+1,j)/lto(i+1,j)+eto(i,j)/oldlt(i,j))
$ /(4.0*h1*h1)*dt
c2=cke02*(eto(i,j)/lto(i,j)+eto(i-1,j)/lto(i-1,j))
$ /(4.0*h1*h1)*dt
c3=cke02*(eto(i,j+1)/lto(i,j+1)+eto(i,j)/lto(i,j))
$ /(4.0*h2*h2)*dt
c4=cke02*(eto(i,j)/lto(i,j)+eto(i,j-1)/lto(i,j-1))
$ /(2.0*h2*h2)*dt
c
ewtn(i,j)=(b1*oldet(i+1,j)+b2*oldet(i-1,j)
$ +b3*oldet(i,j+1)+b4*oldet(i,j-1)
$ +g2*dt*dt*(eto(i,j)-lto(i,j))/(2.0*(1.0+d2))
$ +g2*dt*lto(i,j)/(2.0*(1.0+d2))
$ -g2*dt*ee2*((xsan(i,j)+ysan(i,j))-xsao(i,j)+ysao(i,j)))
$ /(2.0*(1.0+d2))
$ +c1*(eto(i+1,j)-eto(i,j))-c2*(eto(i,j)-eto(i-1,j))
$ +c3*(eto(i,j+1)-eto(i,j))-c4*(eto(i,j)-eto(i,j-1))
$ -g2*dt*(eto(i,j)-lto(i,j))/2.0+q*dt+a*eto(i,j))
$ /(a+b1+b2+b3+b4+g2*dt/2.0-
g2*dt*d2/(2.0*(1.0+d2)))
c
c   write(*,*) ewtn(i,j),oldet(i,j)
c   pause
end do
end do
c
do j=2,m
do i=2,2*n
det=ewtn(i,j)-oldet(i,j)
if (abs(det).gt.detmax) detmax=abs(det)
oldet(i,j)=ewtn(i,j)
end do
end do
c
do j=1,m+1
oldet(1,j)=oldet(2,j)
oldet(2*n+1,j)=oldet(2*n,j)
end do
c
do i=1,2*n+1
oldet(i,1)=oldet(i,2)
oldet(i,m+1)=oldet(i,m)
end do
c
do j=1,m+1
do i=1,n+1
oldlt(i,j)=d1/(1.0+d1)*oldet(i,j)+d1/(1.0+d1)*(eto(i,j)-
lto(i,j))
$ +1.0/(1.0+d1)*lto(i,j)
$ -ee1/(1.0+d1)
$ *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
end do
c
do i=n+2,2*n+1
oldlt(i,j)=d2/(1.0+d2)*oldet(i,j)+d2/(1.0+d2)*(eto(i,j)-
lto(i,j))
$ +1.0/(1.0+d2)*lto(i,j)
$ -ee2/(1.0+d2)
$ *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
end do
end do
iteration=iteration+1
end do
c
write(*,*) 'iteration=',iteration
c

```

```

c   do j=1,m+1
c   write(*,*) (ewetn(i,j),i=1,2*n+1)
c   end do
c   pause
c
c   do j=1,m+1
c   do i=1,2*n+1
c     etn(i,j)=oldet(i,j)
c   end do
c   end do
c
c   do j=2,m
c   do i=2,n+1
c     ltn(i,j)=d1/(1.0+d)*etn(i,j)+d1/(1.0+d1)*(eto(i,j)-
lto(i,j))
c     $    -1.0/(1.0+d1)*lto(i,j)
c     $    -ee1/(1.0+d1)
c     $    *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
c
c   end do
c   do i=n+2,2*n
c     ltn(i,j)=d2/(1.0+d)*etn(i,j)+d2/(1.0+d2)*(eto(i,j)-
lto(i,j))
c     $    +1.0/(1.0+d2)*lto(i,j)
c     $    -ee2/(1.0+d2)
c     $    *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
c
c   end do
c   end do
c
c   do j=1,m+1
c     ltn(1,j)=ltn(2,j)
c     ltn(2*n+1,j)=ltn(2*n,j)
c   end do
c   do i=1,2*n+1
c     ltn(i,1)=ltn(i,2)
c     ltn(i,m+1)=ltn(i,m)
c   end do
c
c   return
c
c subroutine velocity(n,m,h1,h2,dt,etn,ltn,
c
c   xsen,ysen,ssen,xsao,ysao,ssao,v1o,v2o,v1n,v2n,u1o,u2o,
c   u1n,u2n)
c   implicit double precision (a-h,l,o-z)
c
c   dimension etn(401,201),ltn(401,201),
c   $ xsen(401,201),ysen(401,201),ssen(401,201),
c   $ xsao(401,201),ysao(401,201),ssao(401,201),
c   $ 
c   v1o(401,201),v2o(401,201),v1n(401,201),v2n(401,201),
c   $ 
c   u1o(401,201),u2o(401,201),u1n(401,201),u2n(401,201)
c
c
c   c Gold lame constant
c     lemta1=199.0d+9
c   c Gold shear modulus
c
c   cmiu1=27.0d+9
c   c Gold thermal expansion coefficient
c     alphat1=14.2d-6
c   c Gold density
c     lou1=1.93d+4
c   c Gold electron - blast coefficient
c     tri1=70
c
c   c Chromium lame constant
c     lemta2=83.3d+9
c   c Chromium shear modulus
c     cmiu2=115.0d+9
c   c Chromium thermal expansion coefficient
c     alphat2=4.9d-6
c   c Chromium density
c     lou2=7.19d+3
c   c chromium electron - blast coefficient
c     tri2=193.3
c
c
c   c Velocity and displacement in the thickness direction
c
c   c
c   do j=2,m
c
c   c The thin film of gold
c
c   do i=1,n
c     v1n(i,j)=((xsen(i+1,j)-xsen(i,j))/h1
c     $ +(ssen(i,j)-ssen(i-1,j))/h2
c     $ +tri1*(etn(i+1,j)*etn(i+1,j)-etn(i,j)*etn(i,j))/h1)
c     $ *dt/lou1+v1o(i,j)
c
c   u1n(i,j)=v1n(i,j)*dt+u1o(i,j)
c   end do
c
c   c The thin film of chromium
c
c   do i=n+2,2*n+1
c     v1n(i,j)=((xsen(i,j)-xsen(i-1,j))/h1
c     $ +(ssen(i-1,j)-ssen(i-1,j-1))/h2
c     $ +tri2*(etn(i,j)*etn(i,j)-etn(i-1,j)*etn(i-1,j))/h1)
c     $ *dt/lou2+v1o(i,j)
c
c   u1n(i,j)=v1n(i,j)*dt+u1o(i,j)
c   end do
c
c   end do
c
c   v1n(n,2)=((xsen(n+1,2)-xsen(n,2))/h1
c   $ +ssen(n,2)/h2
c   $ +tri1*(etn(n+1,2)*etn(n+1,2)-etn(n,2)*etn(n,2))/h1)
c   $ *dt/lou1+v1o(n,2)
c   u1n(n,2)=v1n(n,2)*dt+u1o(n,2)
c
c   v1n(n,m)=((xsen(n+1,m)-xsen(n,m))/h1
c   $ -ssen(n,m-1)/h2
c   $ +tri1*(etn(n+1,m)*etn(n+1,m)-
etn(n,m)*etn(n,m))/h1)
c   $ *dt/lou1+v1o(n,m)
c   u1n(n,m)=v1n(n,m)*dt+u1o(n,m)
c

```

```

v1n(n+2,2)=((xsen(n+2,2)-xsen(n+1,2))/h1
$ +ssen(n+1,2)/h2
$ +tri2*(etn(n+2,2)*etn(n+2,2)-
etn(n+1,2)*etn(n+1,2))/h1)
$ *dt/lou2+v1o(n+2,2)
u1n(n+2,2)=v1n(n+2,2)*dt+u1o(n+2,2)

c
v1n(n+2,m)=((xsen(n+2,m)-xsen(n+1,m))/h1
$ -ssen(n+1,m-1)/h2
$ +tri2*(etn(n+2,m)*etn(n+2,m)-
etn(n+1,m)*etn(n+1,m))/h1)
$ *dt/lou2+v1o(n+2,m)
u1n(n+2,m)=v1n(n+2,m)*dt+u1o(n+2,m)

c
v1n(n,1)=((xsen(n+1,2)-xsen(n,2))/h1
$ +2.0*ssen(n,1)/h2
$ +tri1*(etn(n+1,1)*etn(n+1,1)-etn(n,1)*etn(n,1))/h1)
$ *dt/lou1+v1o(n,1)
u1n(n,1)=v1n(n,1)*dt+u1o(n,1)

c
v1n(n,m+1)=((xsen(n+1,m)-xsen(n,m))/h1
$ -2.0*ssen(n,m)/h2
$ +tri1*(etn(n+1,m+1)*etn(n+1,m+1)-
etn(n,m+1)*etn(n,m+1))/h1)
$ *dt/lou1+v1o(n,m+1)
u1n(n,m+1)=v1n(n,m+1)*dt+u1o(n,m+1)

c
v1n(n+2,1)=((xsen(n+2,2)-xsen(n+1,2))/h1
$ +2.0*ssen(n+1,1)/h2
$ +tri2*(etn(n+2,1)*etn(n+2,1)-
etn(n+1,1)*etn(n+1,1))/h1)
$ *dt/lou2+v1o(n+2,1)
u1n(n+2,1)=v1n(n+2,1)*dt+u1o(n+2,1)

c
v1n(n+2,m+1)=((xsen(n+2,m)-xsen(n+1,m))/h1
$ -2.0*ssen(n+1,m)/h2
$ +tri2*(etn(n+2,m+1)*etn(n+2,m+1)-
etn(n+1,m+1)*etn(n+1,m+1))/h1)
$ *dt/lou2+v1o(n+2,m+1)
u1n(n+2,m+1)=v1n(n+2,m+1)*dt+u1o(n+2,m+1)

c
c Velocity and displacement in the length direction
c
do j=1,m
a1=cmiu1*dt/h2
a2=cmiu1*dt/h1
a3=cmiu1*ssao(i,j)
b1=cmiu2*dt/h2
b2=cmiu2*dt/h1
b3=cmiu2*ssao(i,j)

v2n(n+1,j)=(a2*v2n(n,j)+b2*v2n(n+2,j)+b1*(v1n(n+1,j-
1)-v1n(n+1,j)))
$ +b3-a1*(v1n(n+1,j-1)-v1n(n+1,j))-a3)/(a2+b2)
c
u2n(n+1,j)=v2n(n+1,j)*dt+u2o(n+1,j)
c
end do

c Velocity in thickness direction
c
do j=2,m
a1=(lemta1+2.0*cmiu1)*dt*2.0/h1
a2=(lemta1+2.0*cmiu1)*xsao(n+1,j)
a3=lemta1*dt/h2
a4=lemta1*ysao(n+1,j)
a5=(3.0*lemta1+2.0*cmiu1)*alphat1
b1=(lemta2+2.0*cmiu2)*dt*2.0/h1
b2=(lemta2+2.0*cmiu2)*xsao(n+2,j)
b3=lemta2*dt/h2
b4=lemta2*ysao(n+2,j)
b5=(3.0*lemta2+2.0*cmiu2)*alphat2
v1n(n+1,j)=(a1*v1n(n,j)+b1*v1n(n+2,j)+b2
$ +b3*(v2n(n+1,j)-v2n(n+1,j-1))+b4-b5*(ltn(n+2,j)-
300.0))
$ -a2-a3*(v2n(n+1,j)-v2n(n+1,j-1))-a4+a5*(ltn(n+1,j)-300.0))
$ /(a1+b1)
c

```

```

c
u1n(n+1,j)=v1n(n+1,j)*dt+u1o(n+1,j)
end do
return
end

A.3 Source Code for Double-Layered
Thin Film with Imperfectly
Interfacial Thermal
Contact

c All the units are SI
c Program main
implicit double precision (a-h,l,o-z)
dimension t(4001),t1(4001),x(401),y(201)
dimension
eto(401,201),etn(401,201),lto(401,201),ltn(401,201),
$ etm(4001),ltm(4001), u1m(4001),u2m(4001),
v1m(4001),v2m(4001),
$ xsao(401,201),ysao(401,201),ssao(401,201),
$ xsao(401,201),ysao(401,201),ssao(401,201),
$ xsan(401,201),ysan(401,201),ssan(401,201),
$ xseo(401,201),yseo(401,201),sse(401,201),
$ xsen(401,201),ysen(401,201),ssen(401,201),
$ 
v1o(401,201),v2o(401,201),v1n(401,201),v2n(401,201),
$
u1o(401,201),u2o(401,201),u1n(401,201),u2n(401,201)
c $
uixt(401,2001),xsext(401,2001),u2xt(401,2001),ysext(4
01,2001),
c $ u1xt1(401,2001),xsext1(401,2001),
c $ u2xt1(401,2001),ysext1(401,2001)
c
integer p, counter
c
c
c Gold lame constant
lemta1=199.0d+9
c Gold shear modulus
cmiu1=27.0d+9
c Gold thermal expansion coefficient
alphat1=14.2d-6
c Gold density
c lou1=1.93d+4
c
c Chromium lame constant
lemta2=83.3d+9
c Chromium shear modulus
cmiu2=115.0d+9
c Chromium thermal expansion coefficient
alphat2=4.9d-6
c Chromium density
c lou2=7.19d+3
c
lx=1.0D-7
ly=1.0D-6
n=40
m=20

h1=lx/n
h2=ly/m
p=400
dt=0.005d-12
counter=0
t(1)=0
x(1)=0
y(1)=0

c initial condition
c
k=1
do j=1,m+1
do i=1,2*n+1
eto(i,j)=300.0
lto(i,j)=300.0
xsao(i,j)=0.0
ysao(i,j)=0.0
ssao(i,j)=0.0
xsao(i,j)=0.0
ysao(i,j)=0.0
ssao(i,j)=0.0
xseo(i,j)=0.0
yseo(i,j)=0.0
sse(1,j)=0.0
v1o(i,j)=0.0
v2o(i,j)=0.0
u1o(i,j)=0.0
u2o(i,j)=0.0
end do
end do
etm(k)=300.0
ltm(k)=300.0

c
do j=2,m+1
y(j)=y(j-1)+h2
end do
do i=2,2*n+1
x(i)=x(i-1)+h1
end do

c
write(*,*) 'start'
c
c
c
do 1 k=2,p+1
c
c
c
do j=1,m+1
do i=1,2*n+1
xsan(i,j)=xsao(i,j)
ysan(i,j)=ysao(i,j)
enddo
enddo
c
c
do j=1,m
do i=1,2*n
ssan(i,j)=ssao(i,j)
end do
end do
c
c
```

```

c
c   tol=1d-14
c   detuvmax=tol+1d-5
c   do while (detuvmax.gt.tol)
c   detuvmax=0.0
c
c     t(k)=t(k-1)+dt
c     t1(k)=t(k-1)+dt/2.0
c
c   Call the subroutine to compute temperature
c
c     call temp(n,m,h1,h2,x,y,t1(k),dt,lto,ltm,etn,
c               $      xsan,ysan,xsao,ysao)
c
c     do j=1,m+1
c       do i=1,2*n+1
c         xsan(i,j)=xsao(i,j)
c         ysan(i,j)=ysao(i,j)
c       enddo
c     enddo
c
c     do j=1,m
c       do i=1,2*n
c         ssan(i,j)=ssao(i,j)
c       end do
c     end do
c
c     tol=1d-14
c     detuvmax=tol+1d-5
c     do while (detuvmax.gt.tol)
c     detuvmax=0.0
c
c
c   Compute stress
c
c
c     do j=1,m+1
c       xsen(1,j)=0.0
c       xsen(2*n+1,j)=0.0
c     end do
c
c     do i=1,2*n+1
c       ysen(i,1)=0.0
c       ysen(i,m+1)=0.0
c     end do
c
c     do j=2,m
c
c   The thin film of gold
c
c     do i=2,n+1
c
c       xsen(i,j)=(lemta1+2.0*cmiu1)*xsan(i,j)+lemta1*ysan(i,j)
c       $ -(3.0*lemta1+2.0*cmiu1)*alphat1*(ltm(i,j)-300.0)
c
c       ysen(i,j)=lemta1*xsan(i,j)+(lemta1+2.0*cmiu1)*ysan(i,j)
c       $ -(3.0*lemta1+2.0*cmiu1)*alphat1*(ltm(i,j)-300.0)
c
c     end do
c
c
c   The thin film of chromium
c
c     do i=n+2,2*n
c
c       xsen(i,j)=(lemta2+2.0*cmiu2)*xsan(i,j)+lemta2*ysan(i,j)
c       $ -(3.0*lemta2+2.0*cmiu2)*alphat2*(ltm(i,j)-300.0)
c
c       ysen(i,j)=lemta2*xsan(i,j)+(lemta2+2.0*cmiu2)*ysan(i,j)
c       $ -(3.0*lemta2+2.0*cmiu2)*alphat2*(ltm(i,j)-300.0)
c
c     end do
c
c     do j=1,m
c       ssen(1,j)=0.0
c       ssen(2*n,j)=0.0
c     end do
c
c   Gold film
c     do i=1,n-1
c       ssen(i,1)=0.0
c       ssen(i,m)=0.0
c     end do
c
c   Chromium film
c     do i=n+2,2*n
c       ssen(i,1)=0.0
c       ssen(i,m)=0.0
c     end do
c
c     do j=2,m-1
c
c   The thin film of gold
c
c     do i=2,n
c       ssen(i,j)=cmiu1*ssan(i,j)
c     end do
c
c   The thin film of chromium
c
c     do i=n+1,2*n-1
c       ssen(i,j)=cmiu2*ssan(i,j)
c     end do
c
c     end do
c
c     ssen(n,1)=cmiu1*ssan(n,1)
c     ssen(n,m)=cmiu1*ssan(n,m)
c     ssen(n+1,1)=cmiu2*ssan(n+1,1)
c     ssen(n+1,m)=cmiu2*ssan(n+1,m)
c
c
c   Calculate velocity
c
c
c     call velocity(n,m,h1,h2,dt,etn,ltm,
c                 $      xsen,ysen,ssen,xsao,ysao,ssao,v1o,v2o,v1n,v2n,u1o,u2o,
c                 u1n,u2n)
c
c

```

```

c Calculate strain
c
c
do j=2,m
c
c The thin film of gold
c
do i=2,n
xsan(i,j)=((v1n(i,j)-v1n(i-1,j))/h1)
$ *dt+xsao(i,j)
c
ysan(i,j)=((v2n(i,j)-v2n(i,j-1))/h2)
$ *dt+ysao(i,j)
end do
c
c At interface
c
xsan(n+1,j)=((v1n(n+1,j)-v1n(n,j))*2.0/h1)
$ *dt+xsao(n+1,j)
xsan(n+2,j)=((v1n(n+3,j)-v1n(n+2,j))*2.0/h1)
$ *dt+xsao(n+2,j)
c
ysan(n+1,j)=((v2n(n+1,j)-v2n(n+1,j-1))/h2)
$ *dt+ysao(n+1,j)
ysan(n+2,j)=((v2n(n+2,j)-v2n(n+2,j-1))/h2)
$ *dt+ysao(n+2,j)
c
c The thin film of chromium
c
do i=n+3,2*n
xsan(i,j)=((v1n(i+1,j)-v1n(i,j))/h1)
$ *dt+xsao(i,j)
c
ysan(i,j)=((v2n(i,j)-v2n(i,j-1))/h2)
$ *dt+ysao(i,j)
end do
c
end do
c
c
c Shear strain
c
do j=2,m-1
c
c The thin film of gold
c
do i=2,n
ssan(i,j)=((v1n(i,j+1)-v1n(i,j))/h2
$ +(v2n(i+1,j)-v2n(i,j))/h1)
$ *dt+ssao(i,j)
end do
c
c The thin film of chromium
c
do i=n+1,2*n-2
ssan(i,j)=((v1n(i+2,j+1)-v1n(i+2,j))/h2
$ +(v2n(i+2,j)-v2n(i+1,j))/h1)
$ *dt+ssao(i,j)
end do
c
end do
c

```

ssan(n,1)=((v1n(n,2)-v1n(n,1))/h2
\$ +(v2n(n+1,1)-v2n(n,1))/h1)
\$ *dt+ssao(n,1)
ssan(n,m)=((v1n(n,m+1)-v1n(n,m))/h2
\$ +(v2n(n+1,m)-v2n(n,m))/h1)
\$ *dt+ssao(n,m)
ssan(n+1,1)=((v1n(n+3,2)-v1n(n+3,1))/h2
\$ +(v2n(n+3,1)-v2n(n+2,1))/h1)
\$ *dt+ssao(n+1,1)
ssan(n+1,m)=((v1n(n+3,m+1)-v1n(n+3,m))/h2
\$ +(v2n(n+3,m)-v2n(n+2,m))/h1)
\$ *dt+ssao(n+1,m)

c Completion of calculation of strain
c
do j=1,m+1
do i=1,2*n+1
det1=xsan(i,j)-xsao(i,j)
det2=ysan(i,j)-ysao(i,j)
det3=ssan(i,j)-ssao(i,j)
det=max(abs(det1),abs(det2),abs(det3))
if(abs(det).gt.detuvmax) detuvmax=abs(det)
end do
end do
c
do j=1,m+1
do i=1,2*n+1
xsao(i,j)=xsan(i,j)
ysao(i,j)=ysan(i,j)
ssao(i,j)=ssan(i,j)
end do
end do
c
write(*,*) 'detuvmax=', detuvmax
c
c End do with detmax
c
end do
c-----

do j=1,m+1
do i=1,2*n+1
etn(i,j)=etn(i,j)
ltn(i,j)=ltn(i,j)
xsao(i,j)=xsan(i,j)
ysao(i,j)=ysan(i,j)
ssao(i,j)=ssan(i,j)
xseo(i,j)=xsen(i,j)
yseo(i,j)=ysen(i,j)
sseo(i,j)=ssen(i,j)
v1o(i,j)=v1n(i,j)
v2o(i,j)=v2n(i,j)
u1o(i,j)=u1n(i,j)
u2o(i,j)=u2n(i,j)
end do
end do
c
etm(k)=etn(1,1)
ltm(k)=ltn(1,1)
u1m(k)=u1n(1,2)

```

u2m(k)=u2n(2,1)
v1m(k)=v1n(1,2)
v2m(k)=v2n(2,1)
c
c   do i=1,2*n+1
c     u1xt(i,k)=u1n(i,2)
c     xsext(i,k)=xsen(i,2)
c     u2xt(i,k)=u2n(i,2)
c     ysext(i,k)=ysen(i,2)
c   end do
c
c   do i=1,m+1
c     u1xt1(i,k)=u1n(2,i)
c     xsext1(i,k)=xsen(2,i)
c     u2xt1(i,k)=u2n(2,i)
c     ysext1(i,k)=ysen(2,i)
c   end do
c
c   counter=counter+1
c   write(*,*) counter
c
c Output intermediate result
c
c   if (k.eq.50) then
c
c The result at time t=0.25ps
c
c   open(unit=9,file='etn01.dat')
c   do j=1,m+1
c     write(9,1010) (etn(i,j),i=1,2*n+1)
c   enddo
c
c   open(unit=10,file='ltn01.dat')
c   do j=1,m+1
c     write(10,1010) (ltn(i,j),i=1,2*n+1)
c   enddo
c   end if
c
c   if (k.eq.100) then
c
c The result at time t=0.5ps
c
c   open(unit=11,file='etn02.dat')
c   do j=1,m+1
c     write(11,1010) (etn(i,j),i=1,2*n+1)
c   enddo
c
c   open(unit=12,file='ltn02.dat')
c   do j=1,m+1
c     write(12,1010) (ltn(i,j),i=1,2*n+1)
c   enddo
c   end if
c
c   if (k.eq.200) then
c
c The result at time t=1ps
c
c   open(unit=13,file='etn03.dat')
c   do j=1,m+1
c     write(13,1010) (etn(i,j),i=1,2*n+1)
c   enddo
c
c   open(unit=14,file='ltn03.dat')
c   do j=1,m+1
c     write(14,1010) (ltn(i,j),i=1,2*n+1)
c   enddo
c   end if
c
c   if (k.eq.400) then
c
c The result at time t=2ps
c
c   open(unit=15,file='etn04.dat')
c   do j=1,m+1
c     write(15,1010) (etn(i,j),i=1,2*n+1)
c   enddo
c
c   open(unit=16,file='ltn04.dat')
c   do j=1,m+1
c     write(16,1010) (ltn(i,j),i=1,2*n+1)
c   enddo
c
c   open(unit=17,file='un01.dat')
c   do j=2,m
c     write(17,1010) (u1n(i,j),i=1,2*n+1)
c   enddo
c
c   open(unit=18,file='vn01.dat')
c   do j=1,m
c     write(18,1010) (u2n(i,j),i=2,2*n)
c   enddo
c
c   open(unit=19,file='xse01.dat')
c   do j=1,m+1
c     write(19,1010) (xsen(i,j),i=1,2*n+1)
c   enddo
c
c   open(unit=20,file='yse01.dat')
c   do j=1,m+1
c     write(20,1010) (ysen(i,j),i=1,2*n+1)
c   enddo
c
c   end if
c
c   if (k.eq.1000) then
c
c The result at time t=5ps
c
c   open(unit=21,file='etn1.dat')
c   do j=1,m+1
c     write(21,1010) (etn(i,j),i=1,2*n+1)
c   enddo
c
c   open(unit=22,file='ltn1.dat')

```

```

do j=1,m+1
write(22,1010) (ltn(i,j),i=1,2*n+1)
enddo
c
open(unit=23,file='un1.dat')
do j=2,m
write(23,1010) (u1n(i,j),i=1,2*n+1)
enddo
c
open(unit=24,file='vn1.dat')
do j=1,m
write(24,1010) (u2n(i,j),i=2,2*n)
enddo
c
open(unit=25,file='xse1.dat')
do j=1,m+1
write(25,1010) (xsen(i,j),i=1,2*n+1)
enddo
c
open(unit=26,file='yse1.dat')
do j=1,m+1
write(26,1010) (ysen(i,j),i=1,2*n+1)
enddo
c
end if
c
c
c the result at time t=10ps
c
c
if (k.eq.2000) then
open(unit=27,file='etn2.dat')
do j=1,m+1
write(27,1010) (etn(i,j),i=1,2*n+1)
enddo
c
open(unit=28,file='ltn2.dat')
do j=1,m+1
write(28,1010) (ltn(i,j),i=1,2*n+1)
enddo
c
open(unit=29,file='un2.dat')
do j=2,m
write(29,1010) (u1n(i,j),i=1,2*n+1)
enddo
c
open(unit=30,file='vn2.dat')
do j=1,m
write(30,1010) (u2n(i,j),i=2,2*n)
enddo
c
open(unit=31,file='xse2.dat')
do j=1,m+1
write(31,1010) (xsen(i,j),i=1,2*n+1)
enddo
c
open(unit=32,file='yse2.dat')
do j=1,m+1
write(32,1010) (ysen(i,j),i=1,2*n+1)
enddo
c
end if
c
c the result at time t=15ps
c
c
if (k.eq.3000) then
open(unit=33,file='etn3.dat')
do j=1,m+1
write(33,1010) (etn(i,j),i=1,2*n+1)
enddo
c
open(unit=34,file='ltn3.dat')
do j=1,m+1
write(34,1010) (ltn(i,j),i=1,2*n+1)
enddo
c
open(unit=35,file='un3.dat')
do j=2,m
write(35,1010) (u1n(i,j),i=1,2*n+1)
enddo
c
open(unit=36,file='vn3.dat')
do j=1,m
write(36,1010) (u2n(i,j),i=2,2*n)
enddo
c
open(unit=37,file='xse3.dat')
do j=1,m+1
write(37,1010) (xsen(i,j),i=1,2*n+1)
enddo
c
open(unit=38,file='yse3.dat')
do j=1,m+1
write(38,1010) (ysen(i,j),i=1,2*n+1)
enddo
c
end if
c
c
1 end do
c
open(unit=39,file='etn4.dat')
do j=1,m+1
write(39,1010) (etn(i,j),i=1,2*n+1)
enddo
c
open(unit=40,file='ltn4.dat')
do j=1,m+1
write(40,1010) (ltn(i,j),i=1,2*n+1)
enddo
c
open(unit=41,file='eltm0.dat')
do k=1,p+1
write(41,1020) t(k),etm(k),ltm(k)
enddo
c
open(unit=42,file='xse4.dat')
do j=1,m+1
write(42,1010) (xsen(i,j),i=1,2*n+1)
enddo

```

```

c
open(unit=43,file='yse4.dat')
do j=1,m+1
write(43,1010) (ysen(i,j),i=1,2*n+1)
enddo
c
open(unit=44,file='um0.dat')
do k=1,p+1
write(44,1020) t(k),u1m(k),u2m(k)
enddo
c
open(unit=45,file='vm3.dat')
do k=1,p+1
write(45,1020) t(k),v1m(k),v2m(k)
enddo
c
open(unit=46,file='un4.dat')
do j=2,m
write(46,1010) (u1n(i,j),i=1,2*n+1)
enddo
c
open(unit=47,file='vn4.dat')
do j=1,m
write(47,1010) (u2n(i,j),i=2,2*n)
enddo
c
c
c
1010    format(401e15.6)
1020    format(e15.6,2e15.6)
c
      end

      subroutine temp(n,m,h1,h2,x,y,t,dt,lto,ltm,eto,etn,
$           xsan,ysan,xsao,ysac)
c
implicit double precision (a-h,l,o-z)
dimension x(401),y(201)
dimension
eto(401,201),etn(401,201),lto(401,201),ltm(401,201),
$ ewtn(401,201),oldet(401,201),oldlt(401,201),
$ xsan(401,201),ysan(401,201),
$ xsao(401,201),ysao(401,201)
c
integer iteration
c
c
c Gold lame constant
lemta1=199.0d+9
c Gold shear modulus
cmiu1=27.0d+9
c Gold thermal expansion coefficient
alphat1=14.2d-6
c Gold electron heat capacity
ce01=2.1d+4
c Gold lattic heat capacity
cl1=2.5d+6
c Gold electron - lattic coupling factor
g1=2.6d+16
c Gold electron thermal conductivity
cke01=315.0
c
c
c Chromium lame constant
lemta2=83.3d+9
c Chromium shear modulus
cmiu2=115.0d+9
c Chromium thermal expansion coefficient
alphat2=4.9d-6
c Chromium electron heat capacity
ce02=5.8d+4
c Chromium lattic heat capacity
cl2=3.3d+6
c Chromium electron - lattic coupling factor
g2=4.2d+17
c Chromium electron thermal conductivity
cke02=94.0
c
c
c
c Laser fluence
flu=2000.0
c Laser pulse duration
tp=0.1d-12
c Optical penetration depth
delta=15.3d-9
c Surface reflectivity
sur=0.93
c Spatial profile parameters
rs=1d-6
c Stefan-Boltzmann constant
sigma=5.669d-8
c
iteration=0
d1=g1*dt/(2.0*cl1)
d2=g2*dt/(2.0*cl2)
ee1=(3.0*lemta1+2.0*cmiu1)*alphat1/cl1
ee2=(3.0*lemta2+2.0*cmiu2)*alphat2/cl2
c
do j=1,m+1
do i=1,2*n+1
oldet(i,j)=eto(i,j)
oldlt(i,j)=lto(i,j)
end do
end do
c
tol=1e-3
detmax=tol+0.001
do while (detmax.gt.tol)
c
detmax=0.0
do j=2,m
c
c Electron temperature at gold film
c
do i=2,n
q=0.94*flu*(1.0-sur)/(tp*delta)
$     *exp(-x(i)/delta-y(j)*y(j)/(rs*rs)
$     -2.77*(t-2.0*tp)*(t-2.0*tp)/(tp*tp))
c
a=ce01*(eto(i,j)+oldet(i,j))/(2.0*300.0)
b1=cke01*(oldet(i+1,j)/oldlt(i+1,j)+oldet(i,j)/oldlt(i,j))

```

```

c   $ /(4.0*h1*h1)*dt
c   b1=353.0*((oldet(i+1,j)/6.42d+4)**2+0.16)**1.25
c   $
c   *((oldet(i+1,j)/6.42d+4)**2+0.44)*(oldet(i+1,j)/6.42d+4)
c   $ /(((oldet(i+1,j)/6.42d+4)**2+0.092)**0.5
c   $
c   *((oldet(i+1,j)/6.42d+4)**2+0.16*oldlt(i+1,j)/6.42d+4))
c   $ +((oldet(i,j)/6.42d+4)**2+0.16)**1.25
c   $
c   *((oldet(i,j)/6.42d+4)**2+0.44)*(oldet(i,j)/6.42d+4)
c   $ /(((oldet(i,j)/6.42d+4)**2+0.092)**0.5
c   $
c   *((oldet(i,j)/6.42d+4)**2+0.16*oldlt(i,j)/6.42d+4)))
c   $ /(4.0*h1*h1)*dt

b2=cke01*(oldet(i,j)/oldlt(i,j)+oldet(i-1,j)/oldlt(i-1,j))
$ /(4.0*h1*h1)*dt
c   b2=353.0*((oldet(i,j)/6.42d+4)**2+0.16)**1.25
c   $
c   *((oldet(i,j)/6.42d+4)**2+0.44)*(oldet(i,j)/6.42d+4)
c   $ /(((oldet(i,j)/6.42d+4)**2+0.092)**0.5
c   $
c   *((oldet(i,j)/6.42d+4)**2+0.16*oldlt(i,j)/6.42d+4))
c   $ +((oldet(i-1,j)/6.42d+4)**2+0.16)**1.25
c   $ *((oldet(i-1,j)/6.42d+4)**2+0.44)*(oldet(i-
1,j)/6.42d+4)
c   $ /(((oldet(i-1,j)/6.42d+4)**2+0.092)**0.5
c   $ *((oldet(i-1,j)/6.42d+4)**2+0.16*oldlt(i-
1,j)/6.42d+4)))
c   $ /(4.0*h1*h1)*dt

b3=cke01*(oldet(i,j+1)/oldlt(i,j+1)+oldet(i,j)/oldlt(i,j))
$ /(4.0*h2*h2)*dt
c   b3=353.0*((oldet(i,j+1)/6.42d+4)**2+0.16)**1.25
c   $
c   *((oldet(i,j+1)/6.42d+4)**2+0.44)*(oldet(i,j+1)/6.42d+4)
c   $ /(((oldet(i,j+1)/6.42d+4)**2+0.092)**0.5
c   $
c   *((oldet(i,j+1)/6.42d+4)**2+0.16*oldlt(i,j+1)/6.42d+4))
c   $ +((oldet(i,j)/6.42d+4)**2+0.16)**1.25
c   $
c   *((oldet(i,j)/6.42d+4)**2+0.44)*(oldet(i,j)/6.42d+4)
c   $ /(((oldet(i,j)/6.42d+4)**2+0.092)**0.5
c   $
c   *((oldet(i,j)/6.42d+4)**2+0.16*oldlt(i,j)/6.42d+4)))
c   $ /(4.0*h2*h2)*dt

b4=cke01*(oldet(i,j)/oldlt(i,j)+oldet(i-1,j)/oldlt(i-1,j))
$ /(2.0*h2*h2)*dt
c   b4=353.0*((oldet(i,j)/6.42d+4)**2+0.16)**1.25
c   $
c   *((oldet(i,j)/6.42d+4)**2+0.44)*(oldet(i,j)/6.42d+4)
c   $ /(((oldet(i,j)/6.42d+4)**2+0.092)**0.5
c   $
c   *((oldet(i,j)/6.42d+4)**2+0.16*oldlt(i,j)/6.42d+4))
c   $ +((oldet(i-1,j)/6.42d+4)**2+0.16)**1.25
c   $ *((oldet(i-1,j)/6.42d+4)**2+0.44)*(oldet(i,j-
1)/6.42d+4)
c   $ /(((oldet(i,j-1)/6.42d+4)**2+0.092)**0.5
c   $ *((oldet(i,j-1)/6.42d+4)**2+0.16*oldlt(i,j-
1)/6.42d+4)))
c   $ /(4.0*h2*h2)*dt

c   $ /(4.0*h2*h2)*dt
c   c1=cke01*(eto(i+1,j)/lto(i+1,j)+eto(i,j)/oldlt(i,j))
$ /(4.0*h1*h1)*dt
c2=cke01*(eto(i,j)/lto(i,j)+eto(i-1,j)/lto(i-1,j))
$ /(4.0*h1*h1)*dt
c3=cke01*(eto(i,j+1)/lto(i,j+1)+eto(i,j)/lto(i,j))
$ /(4.0*h2*h2)*dt
c4=cke01*(eto(i,j)/lto(i,j)+eto(i,j-1)/lto(i,j-1))
$ /(2.0*h2*h2)*dt
c   ewtn(i,j)=(b1*oldet(i+1,j)+b2*oldet(i-1,j)
$ +b3*oldet(i,j+1)+b4*oldet(i,j-1)
$ +g1*d1*dt*(eto(i,j)-lto(i,j))/(2.0*(1.0+d1))
$ +g1*dt*ltoto(i,j)/(2.0*(1.0+d1))
$ -g1*dt*ee1*((xsan(i,j)+ysan(i,j))-
(xsao(i,j)+ysao(i,j)))
$ /(2.0*(1.0+d1))
$ +c1*(eto(i+1,j)-eto(i,j))-c2*(eto(i,j)-eto(i-1,j))
$ +c3*(eto(i,j+1)-eto(i,j))-c4*(eto(i,j)-eto(i,j-1))
$ -g1*dt*(eto(i,j)-lto(i,j))/2.0+q*dt+a*eto(i,j))
$ /(a+b1+b2+b3+b4+g1*dt/2.0-
g1*dt*d1/(2.0*(1.0+d1)))
c   write(*,*) ewtn(i,j),oldet(i,j)
c   pause
end do
c   Electron temperature at interface i=n+1
c   b1=cke01*(oldet(n+1,j)/(oldlt(n+1,j)))
b2=cke02*(oldet(n+2,j)/(oldlt(n+2,j)))
ewtn(n+2,j)=oldet(n+3,j)-b1/b2*(oldet(n+1,j)-
oldet(n,j))
ewtn(n+1,j)=oldet(n,j)-sigma*h1/b1*
$ (oldet(n+1,j)**4-oldet(n+2,j)**4)
c   Electron temperature at chromium film
c   do i=n+3,2*n
q=0.94*flu*(1.0-surf)/(tp*delta)
$ *exp(-x(i)/delta-y(j)*y(j)/(rs*rs)
$ -2.77*(t-2.0*tp)*(t-2.0*tp)/(tp*tp))
c   a=ce02*(eto(i,j)+oldet(i,j))/(2.0*300.0)

b1=cke02*(oldet(i+1,j)/oldlt(i+1,j)+oldet(i,j)/oldlt(i,j))
$ /(4.0*h1*h1)*dt
b2=cke02*(oldet(i,j)/oldlt(i,j)+oldet(i-1,j)/oldlt(i-1,j))
$ /(4.0*h1*h1)*dt
b3=cke02*(oldet(i,j+1)/oldlt(i,j+1)+oldet(i,j)/oldlt(i,j))
$ /(4.0*h2*h2)*dt
b4=cke02*(oldet(i,j)/oldlt(i,j)+oldet(i,j-1)/oldlt(i,j-1))
$ /(2.0*h2*h2)*dt
c   c1=cke02*(eto(i+1,j)/lto(i+1,j)+eto(i,j)/oldlt(i,j))
$ /(4.0*h1*h1)*dt
c2=cke02*(eto(i,j)/lto(i,j)+eto(i-1,j)/lto(i-1,j))
$ /(4.0*h1*h1)*dt
c3=cke02*(eto(i,j+1)/lto(i,j+1)+eto(i,j)/lto(i,j))

```

```

$ /(4.0*h2*h2)*dt
c4=cke02*(eto(i,j)/lto(i,j)+eto(i,j-1)/lto(i,j-1))
$ /(2.0*h2*h2)*dt
c
ewetn(i,j)=(b1*oldet(i+1,j)+b2*oldet(i-1,j)
$ +b3*oldet(i,j+1)+b4*oldet(i,j-1)
$ +g2*d2*dt*(eto(i,j)-lto(i,j))/(2.0*(1.0+d2))
$ +g2*dt*lto(i,j)/(2.0*(1.0+d2))
$ -g2*dt*ee2*((xsan(i,j)+ysan(i,j))- (xsao(i,j)+ysao(i,j)))
$ /(2.0*(1.0+d2))
$ +c1*(eto(i+1,j)-eto(i,j))-c2*(eto(i,j)-eto(i-1,j))
$ +c3*(eto(i,j+1)-eto(i,j))-c4*(eto(i,j)-eto(i,j-1))
$ -g2*dt*(eto(i,j)-lto(i,j))/2.0+q*dt+a*eto(i,j))
$ /(a+b1+b2+b3+b4+g2*dt/2.0-
g2*dt*d2/(2.0*(1.0+d2)))
c
c   write(*,*) ewetn(i,j),oldet(i,j)
c   pause
      end do
      end do
c
do j=2,m
do i=2,2*n
det=ewetn(i,j)-oldet(i,j)
if (abs(det).gt.detmax) detmax=abs(det)
oldet(i,j)=ewetn(i,j)
end do
end do
c
do j=1,m+1
oldet(1,j)=oldet(2,j)
oldet(2*n+1,j)=oldet(2*n,j)
end do
c
do i=1,2*n+1
oldet(i,1)=oldet(1,2)
oldet(i,m+1)=oldet(i,m)
end do
c
do j=1,m+1
do i=1,n+1
oldlt(i,j)=d1/(1.0+d1)*oldet(i,j)+d1/(1.0+d1)*(eto(i,j)-
lto(i,j))
$ +1.0/(1.0+d1)*lto(i,j)
$ -ee1/(1.0+d1)
$ *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
end do
c
do i=n+2,2*n+1
oldlt(i,j)=d2/(1.0+d2)*oldet(i,j)+d2/(1.0+d2)*(eto(i,j)-
lto(i,j))
$ +1.0/(1.0+d2)*lto(i,j)
$ -ee2/(1.0+d2)
$ *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
end do
end do
c
iteration=iteration+1
c
end do
c
write(*,*) 'iteration=',iteration
c
c   do j=1,m+1
c   write(*,*) (ewetn(i,j),i=1,2*n+1)
c   end do
c   pause
c
do j=1,m+1
do i=1,2*n+1
etn(i,j)=oldet(i,j)
end do
end do
c
do j=2,m
do i=2,n+1
ltn(i,j)=d1/(1.0+d)*etn(i,j)+d1/(1.0+d1)*(eto(i,j)-
lto(i,j))
$ +1.0/(1.0+d1)*lto(i,j)
$ -ee1/(1.0+d1)
$ *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
end do
do i=n+2,2*n
ltn(i,j)=d2/(1.0+d)*etn(i,j)+d2/(1.0+d2)*(eto(i,j)-
lto(i,j))
$ +1.0/(1.0+d2)*lto(i,j)
$ -ee2/(1.0+d2)
$ *((xsan(i,j)+ysan(i,j))-(xsao(i,j)+ysao(i,j)))
end do
c
do j=1,m+1
ltn(1,j)=ltn(2,j)
ltn(2*n+1,j)=ltn(2*n,j)
end do
do i=1,2*n+1
ltn(i,1)=ltn(i,2)
ltn(i,m+1)=ltn(i,m)
end do
c
return
end

subroutine velocity(n,m,h1,h2,dt,etn,ltn,
$ xsen,ysen,ssen,xsao,ysao,ssao,v1o,v2o,v1n,v2n,u1o,u2o,
u1n,u2n)
implicit double precision (a-h,l,o-z)
c
dimension etn(401,201),ltn(401,201),
$ xsen(401,201),ysen(401,201),ssen(401,201),
$ xsao(401,201),ysao(401,201),ssao(401,201),
$ v1o(401,201),v2o(401,201),v1n(401,201),v2n(401,201),
$ u1o(401,201),u2o(401,201),u1n(401,201),u2n(401,201)

```

```

c
c
c
c Gold lame constant
lemta1=199.0d+9
c Gold shear modulus
cmiu1=27.0d+9
c Gold thermal expansion coefficient
alphat1=14.2d-6
c Gold density
lou1=1.93d+4
c Gold electron - blast coefficient
tri1=70
c Gold modulus of elasiticiy
ee1=77.97e+9
c
c Chromium lame constant
lemta2=83.3d+9
c Chromium shear modulus
cmiu2=115.0d+9
c Chromium thermal expansion coefficient
alphat2=4.9d-6
c Chromium density
lou2=7.19d+3
c chromium electron - blast coefficient
tri2=193.3
c Gold modulus of elasiticiy
ee2=279.45e+9
c
c
cc=ee1*c.miu2/(ee2*cmiu1)
c
c Velocity and displacement in the thickness direction
c
c
do j=2,m
c
c The thin film of gold
c
do j=1,n
v1n(i,j)=((xsen(i+1,j)-xsen(i,j))/h1
$ +(ssen(i,j)-ssen(i,j-1))/h2
$ +tri1*(etn(i+1,j)*etn(i+1,j)-etn(i,j)*etn(i,j))/h1
$ *dt/lou1+v1o(i,j)
c
u1n(i,j)=v1n(i,j)*dt+u1o(i,j)
end do
c
c The thin film of chromium
c
do i=n+3,2*n+1
v1n(i,j)=((xsen(i,j)-xsen(i-1,j))/h1
$ +(ssen(i-1,j)-ssen(i-1,j-1))/h2
$ +tri2*(etn(i,j)*etn(i,j)-etn(i-1,j)*etn(i-1,j))/h1
$ *dt/lou2+v1o(i,j)
c
u1n(i,j)=v1n(i,j)*dt+u1o(i,j)
end do
c
end do
c
v1n(n,2)=((xsen(n+1,2)-xsen(n,2))/h1
$ +ssen(n,2)/h2
$ +tri1*(etn(n+1,2)*etn(n+1,2)-etn(n,2)*etn(n,2))/h1
$ *dt/lou1+v1o(n,2)
u1n(n,2)=v1n(n,2)*dt+u1o(n,2)
c
v1n(n,m)=((xsen(n+1,m)-xsen(n,m))/h1
$ -ssen(n,m-1)/h2
$ +tri1*(etn(n+1,m)*etn(n+1,m)-
etn(n,m)*etn(n,m))/h1
$ *dt/lou1+v1o(n,m)
u1n(n,m)=v1n(n,m)*dt+u1o(n,m)
c
v1n(n+3,2)=((xsen(n+3,2)-xsen(n+2,2))/h1
$ +ssen(n+1,2)/h2
$ +tri2*(etn(n+3,2)*etn(n+3,2)-
etn(n+2,2)*etn(n+2,2))/h1
$ *dt/lou2+v1o(n+3,2)
u1n(n+3,2)=v1n(n+3,2)*dt+u1o(n+3,2)
c
v1n(n+3,m)=((xsen(n+3,m)-xsen(n+2,m))/h1
$ -ssen(n+1,m-1)/h2
$ +tri2*(etn(n+3,m)*etn(n+3,m)-
etn(n+2,m)*etn(n+2,m))/h1
$ *dt/lou2+v1o(n+3,m)
u1n(n+3,m)=v1n(n+3,m)*dt+u1o(n+3,m)
c
v1n(n,1)=((xsen(n+1,1)-xsen(n,1))/h1
$ +2.0*ssen(n,1)/h2
$ +tri1*(etn(n+1,1)*etn(n+1,1)-etn(n,1)*etn(n,1))/h1
$ *dt/lou1+v1o(n,1)
u1n(n,1)=v1n(n,1)*dt+u1o(n,1)
c
v1n(n,m+1)=((xsen(n+1,m)-xsen(n,m))/h1
$ -2.0*ssen(n+1,m)/h2
$ +tri1*(etn(n+1,m+1)*etn(n+1,m+1)-
etn(n,m+1)*etn(n,m+1))/h1
$ *dt/lou1+v1o(n,m+1)
u1n(n,m+1)=v1n(n,m+1)*dt+u1o(n,m+1)
c
v1n(n+3,1)=((xsen(n+3,1)-xsen(n+2,1))/h1
$ +2.0*ssen(n+1,1)/h2
$ +tri2*(etn(n+3,1)*etn(n+3,1)-
etn(n+2,1)*etn(n+2,1))/h1
$ *dt/lou2+v1o(n+3,1)
u1n(n+3,1)=v1n(n+3,1)*dt+u1o(n+3,1)
c
v1n(n+3,m+1)=((xsen(n+3,m)-xsen(n+3,m))/h1
$ -2.0*ssen(n+1,m)/h2
$ +tri2*(etn(n+3,m+1)*etn(n+3,m+1)-
etn(n+2,m+1)*etn(n+2,m+1))/h1
$ *dt/lou2+v1o(n+3,m+1)
u1n(n+3,m+1)=v1n(n+3,m+1)*dt+u1o(n+3,m+1)
c
c
c Velocity and displacement in the length direction
c
c
do j=1,m
c
c The thin film of gold
c

```

```

do i=2,n
v2n(i,j)=((ssen(i,j)-ssen(i-1,j))/h1
$ +(ysen(i,j+1)-ysen(i,j))/h2
$ +tri1*(etn(i,j+1)*etn(i,j+1)-etn(i,j)*etn(i,j))/h2)
$ *dt/lou1+v2o(i,j)
c
u2n(i,j)=v2n(i,j)*dt+u2o(i,j)
end do
c
c The thin film of chromium
c
do i=n+3,2*n
v2n(i,j)=((ssen(i-1,j)-ssen(i-2,j))/h1
$ +(ysen(i,j+1)-ysen(i,j))/h2
$ +tri2*(etn(i,j+1)*etn(i,j+1)-etn(i,j)*etn(i,j))/h2)
$ *dt/lou2+v2o(i,j)
c
u2n(i,j)=v2n(i,j)*dt+u2o(i,j)
end do
c
end do
c
v2n(n,1)=(ysen(n,2)/h2)*dt/lou1+v2o(n,1)
u2n(n,1)=v2n(n,1)*dt+u2o(n,1)
c
v2n(n,m)=(-ysen(n,m)/h2)*dt/lou1+v2o(n,m)
u2n(n,m)=v2n(n,m)*dt+u2o(n,m)
c
v2n(n+3,1)=(ysen(n+3,2)/h2)*dt/lou2+v2o(n+3,1)
u2n(n+3,1)=v2n(n+3,1)*dt+u2o(n+3,1)
c
v2n(n+3,m)=(-ysen(n+3,m)/h2)*dt/lou2+v2o(n+3,m)
u2n(n+3,m)=v2n(n+3,m)*dt+u2o(n+3,m)
c
c
c The interface between gold and chromium
c
c Velocity in length direction
c
do j=1,m
a1=cmiu1*dt/h2
a2=cmiu1*dt/h1
a3=cmiu1*ssao(i,j)
b1=cmiu2*dt/h2
b2=cmiu2*dt/h1
b3=cmiu2*ssao(i,j)

v2n(n+1,j)=(a2*v2n(n,j)+b2*v2n(n+3,j)+b1*(v1n(n+2,j)
+1)-v1n(n+2,j))
$ +b3-a1*(v1n(n+1,j+1)-v1n(n+1,j))-a3)/(a2+b2*cmiu1/cmiu2)
v2n(n+2,j)=cmiu1/cmiu2*v2n(n+1,j)
c
u2n(n+1,j)=v2n(n+1,j)*dt+u2o(n+1,j)
u2n(n+2,j)=v2n(n+2,j)*dt+u2o(n+2,j)
c
end do
c
c Velocity in thickness direction
c
do j=2,m
a1=(lemta1+2.0*cmiu1)*dt*2.0/h1
a2=(lemta1+2.0*cmiu1)*xsao(n+1,j)
a3=lemta1*dt/h2
a4=lemta1*ysao(n+1,j)
a5=(3.0*lemta1+2.0*cmiu1)*alphat1
b1=cc*(lemta2+2.0*cmiu2)*dt*2.0/h1
b2=cc*(lemta2+2.0*cmiu2)*xsao(n+2,j)
b3=cc*lemta2*dt/h2
b4=cc*lemta2*ysao(n+2,j)
b5=cc*(3.0*lemta2+2.0*cmiu2)*alphat2
v1n(n+1,j)=(a1*v1n(n,j)+b1*v1n(n+3,j)+b2
$ +b3*(v2n(n+2,j)-v2n(n+2,j-1))+b4-b5*(ltn(n+2,j)
300.0)
$ -a2-a3*(v2n(n+1,j)-v2n(n+1,j-1))-a4+a5*(ltn(n+1,j)-300.0))
$ /(a1+b1*cmiu1/cmiu2)
v1n(n+2,j)=cmiu1/cmiu2*v1n(n+1,j)
c
u1n(n+1,j)=v1n(n+1,j)*dt+u1o(n+1,j)
u1n(n+2,j)=v1n(n+2,j)*dt+u1o(n+2,j)
c
end do
c
return
end

```

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